The Coordinating Panel for Advanced Detectors: CPAD 2022

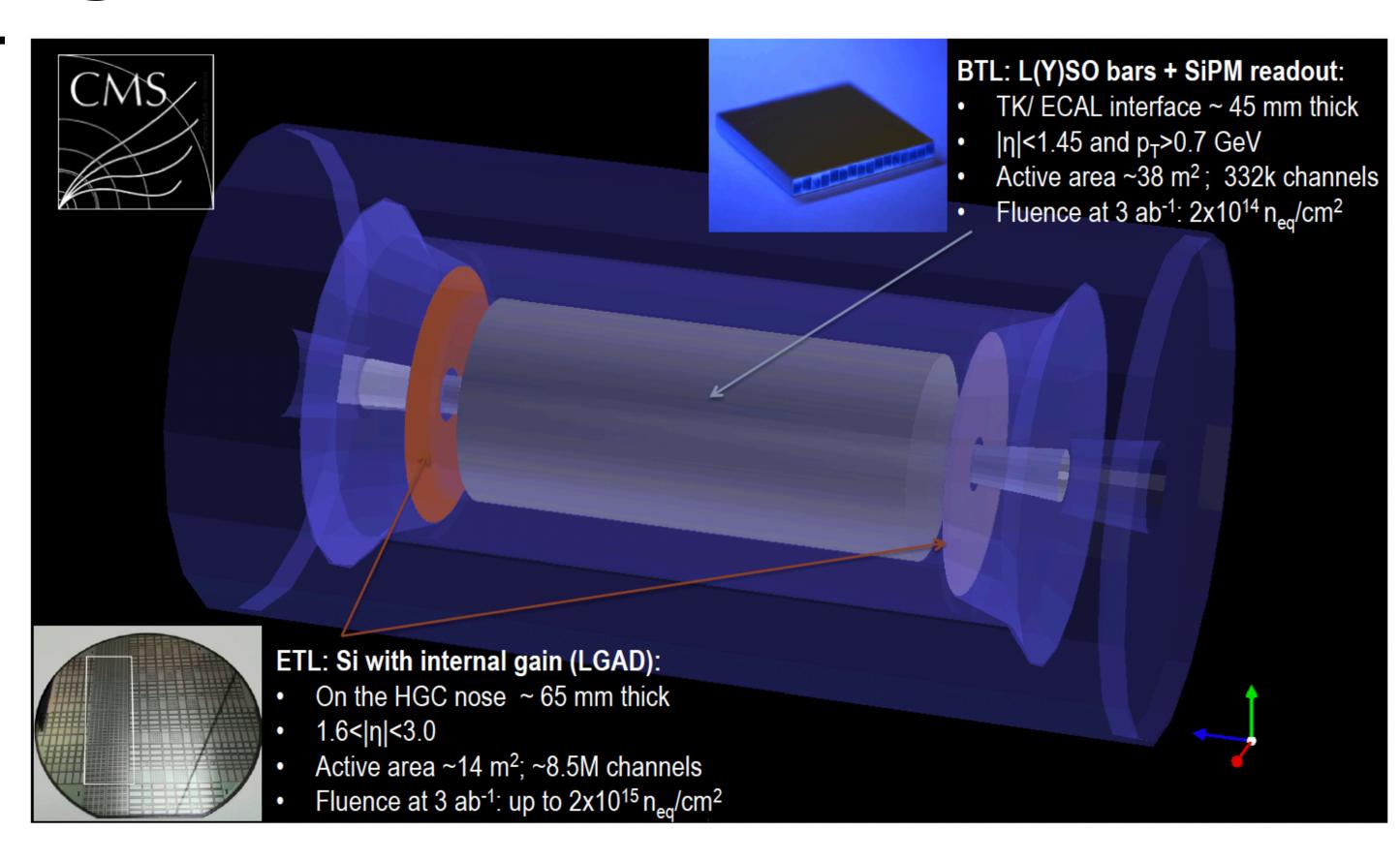
Performance of Highly Irradiated SiPMs

Coupled to LYSO:Ce Crystals for the CMS MTD Barrel
Timing Layer

Carlos E. Pérez Lara

- University of Virginia -

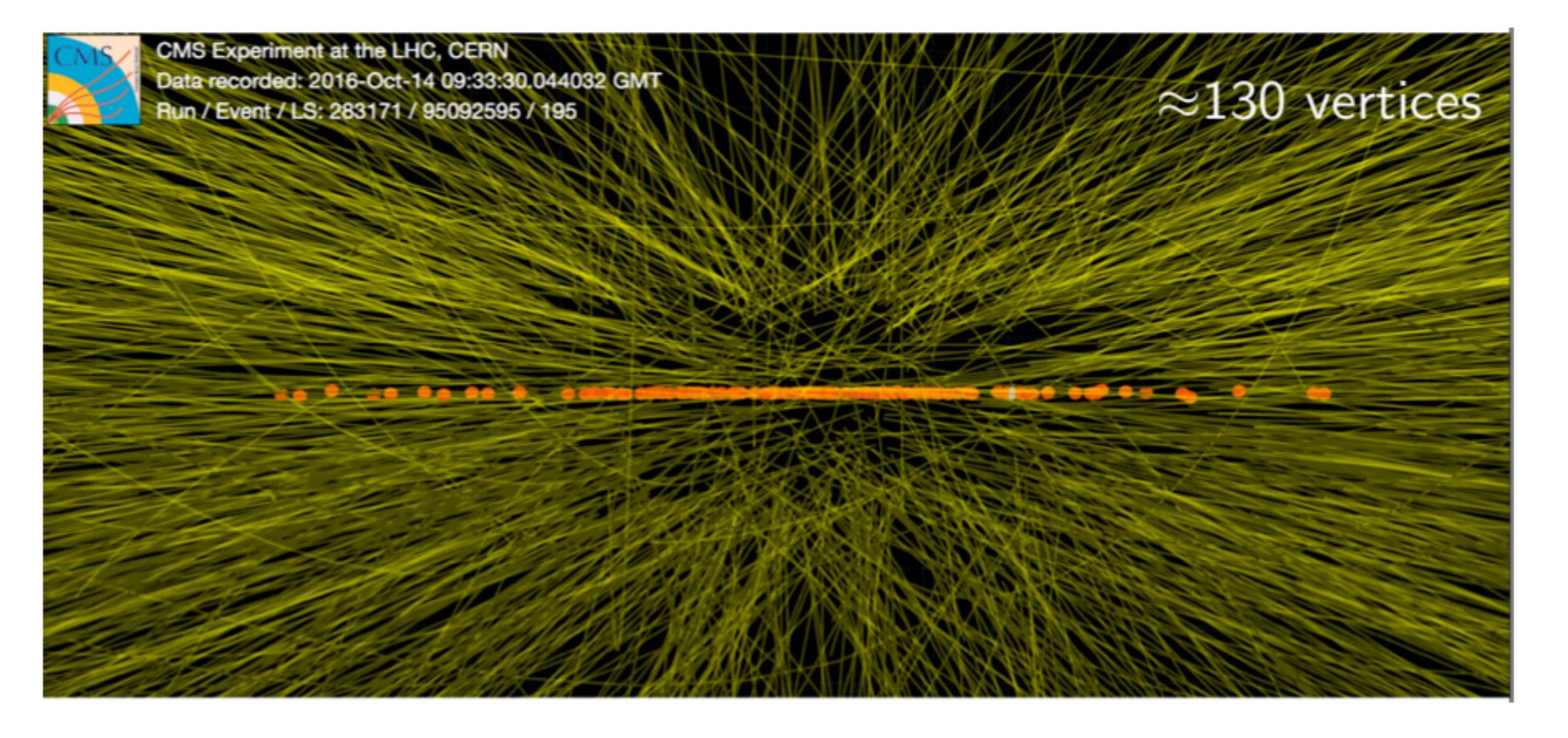
for the CMS collaboration on behalf of the MTD group



The Barrel Timing Layer Detector

CMS phase 2 upgrade program => High Luminosity LHC era

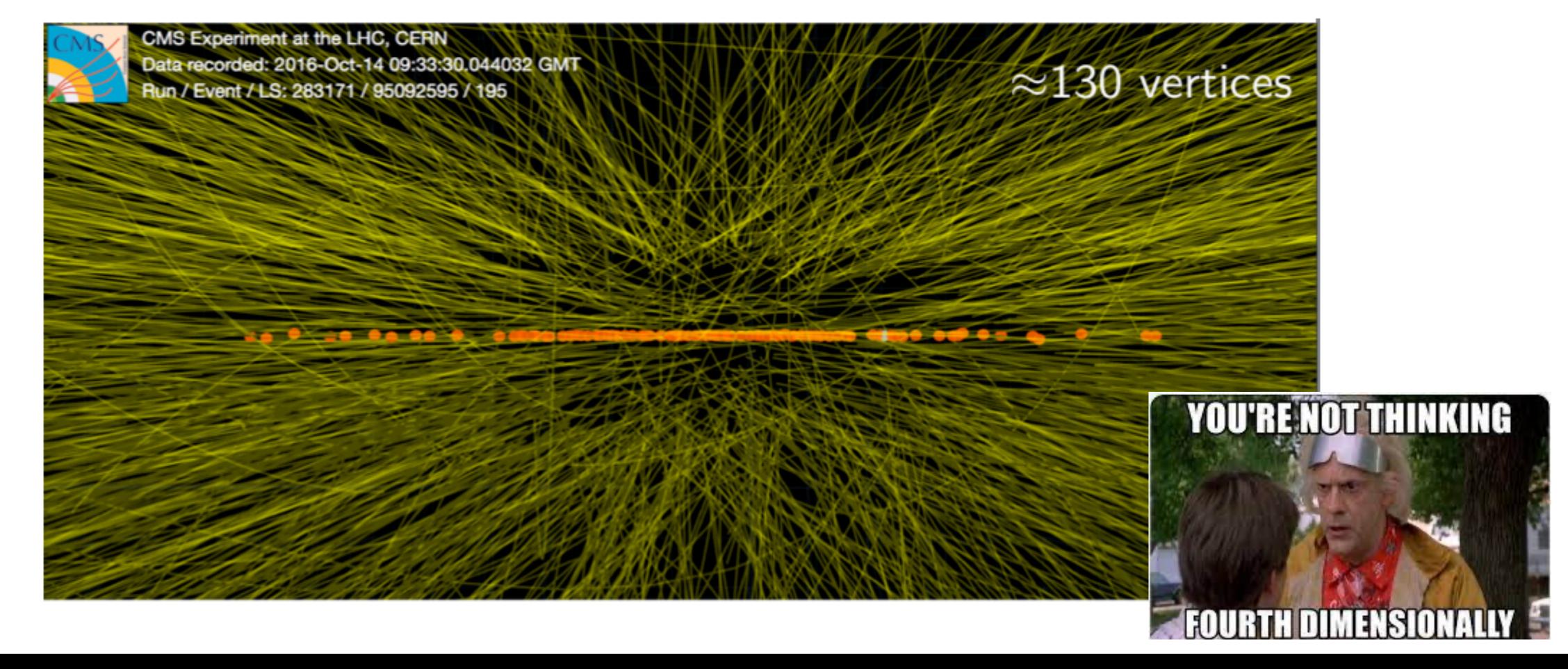
- We expect pile-up of 200 events per bunch crossing
 - Challenging to disentangle vertexes and to do tracking without upgrade



The Barrel Timing Layer Detector

CMS phase 2 upgrade program => High Luminosity LHC era

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The Barrel Timing Layer Detector

CMS phase 2 upgrade program => High Luminosity LHC era

- We expect pile-up of 200 events per bunch crossing
 - Challenging to disentangle vertexes and to do tracking without upgrade

MIP Timing Detector - Improve vertex ID and aid tracking

Timing resolution from 30-40 ps to 50-60 ps

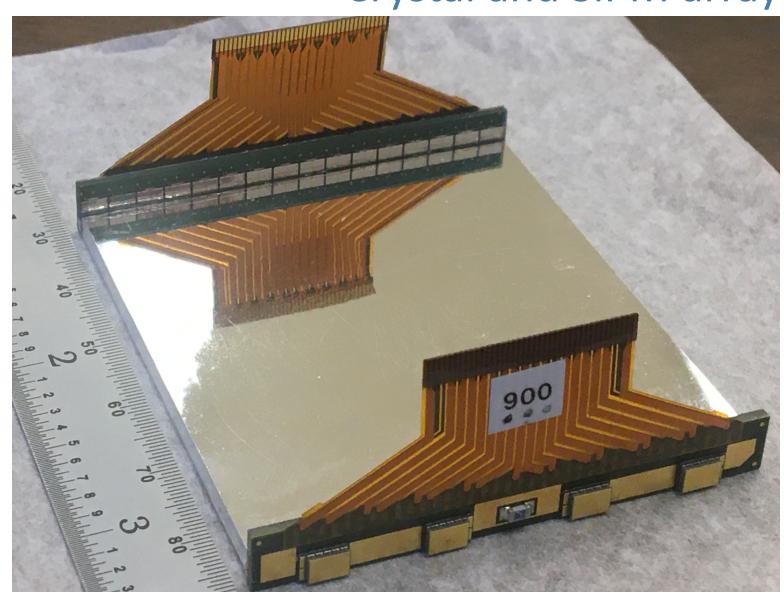
Barrel Timing Layer : LYSO+SiPM

Cylindrical coverage: 5.2 m length, 1.15 m radius

- 10368 modules (each about 5.3x5.3 cm²)
- 1 module = 16 crystals, 32 SiPMs, 8 TECs, 1 ASIC

Effects from radiation damage currently under study

Crystal and SiPM array

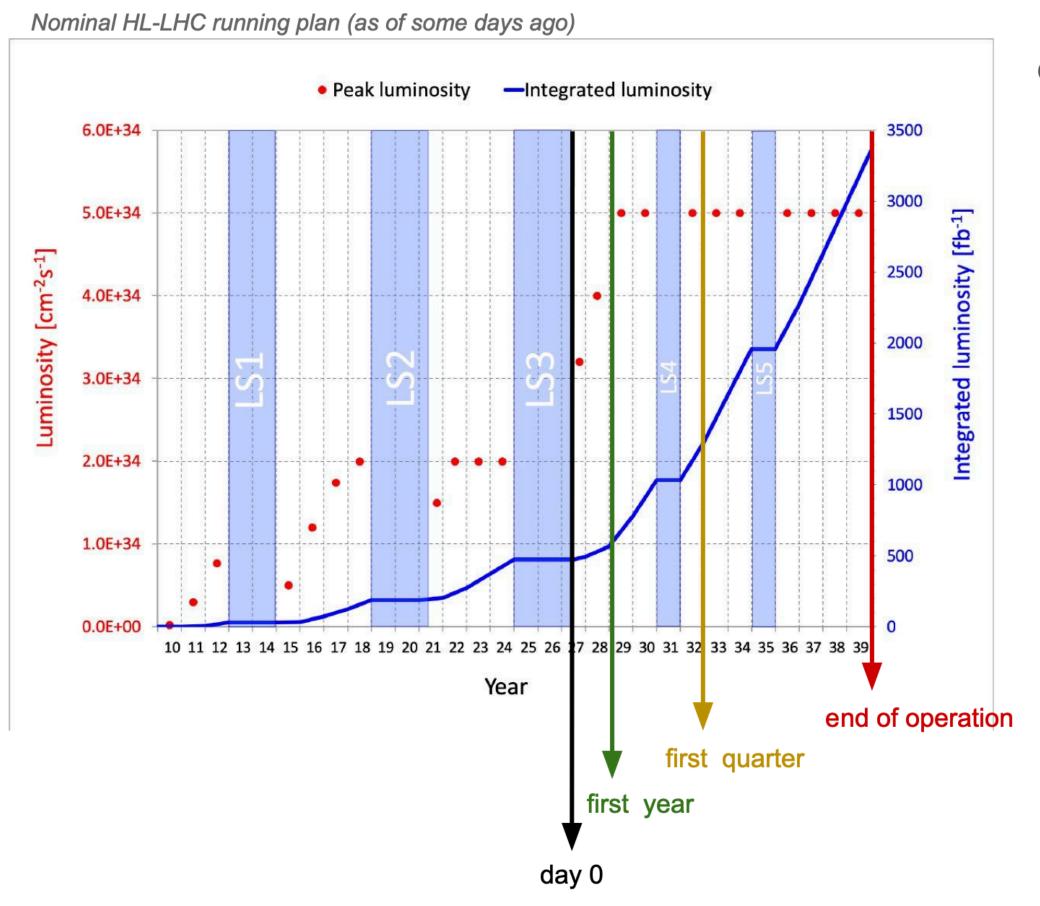


SiPM's pros:

- Insensitive to magnetic fields
- Good uniformity
- Compact size (3x3mm^2)
- Small pixel (15um)
- PDE > 20%
- Fast recovery time < 10ns
- Radiation tolerant*

Expected Radiation Damage [>10 years operation]

BTL life snapshots considered

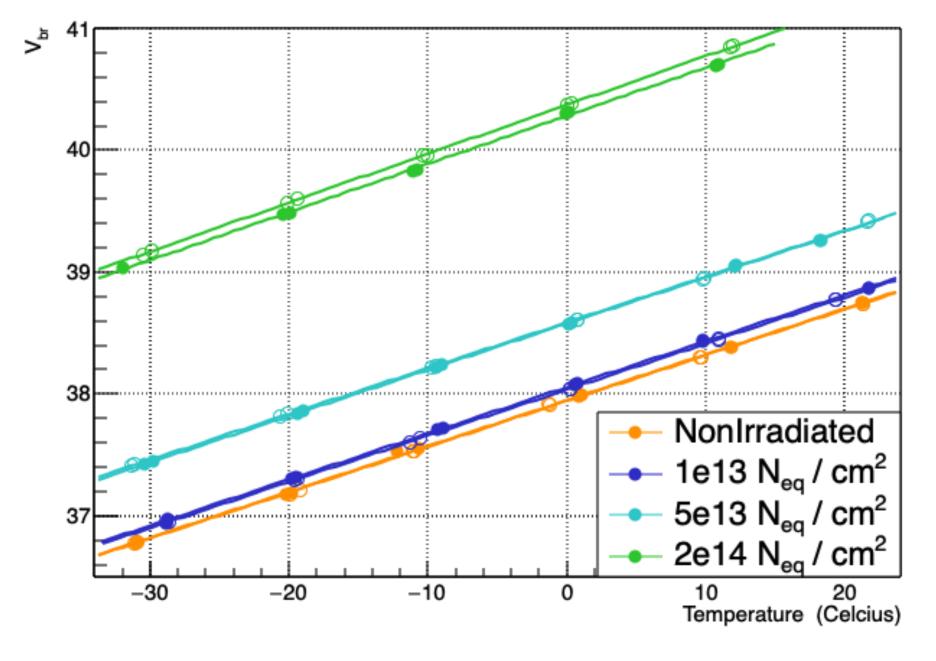


- Consider three snapshots along the BTL lifetime
 - First year (<200 fb⁻¹):
 - PU ~ 100
 - integrated fluence 1e13 1MeV neq/cm²
 - OV ~ 3.0 V
 - First quarter of operation (750 fb⁻¹):
 - PU~140
 - integrated radiation 5e13 1MeV neq/cm²
 - OV ~ 1.8 V
 - End of operation (3000 fb⁻¹):
 - PU~140
 - integrated radiation 2e14 1MeV neq/cm²
 - OV ~ 1.0 V

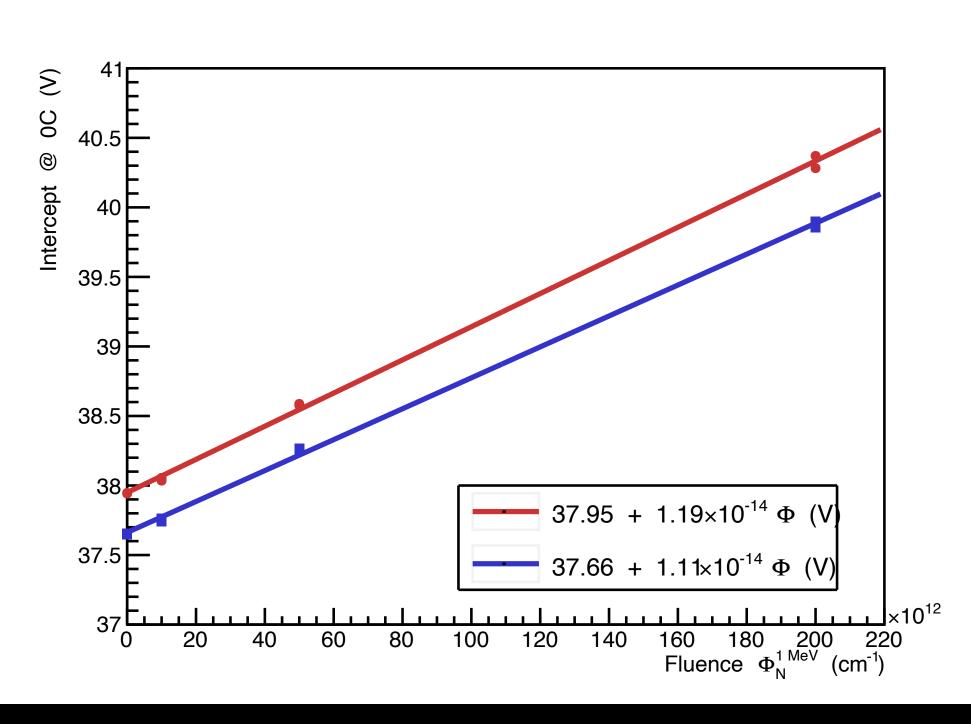
6

Breakdown Voltage (V_{br}) as function of Temperature

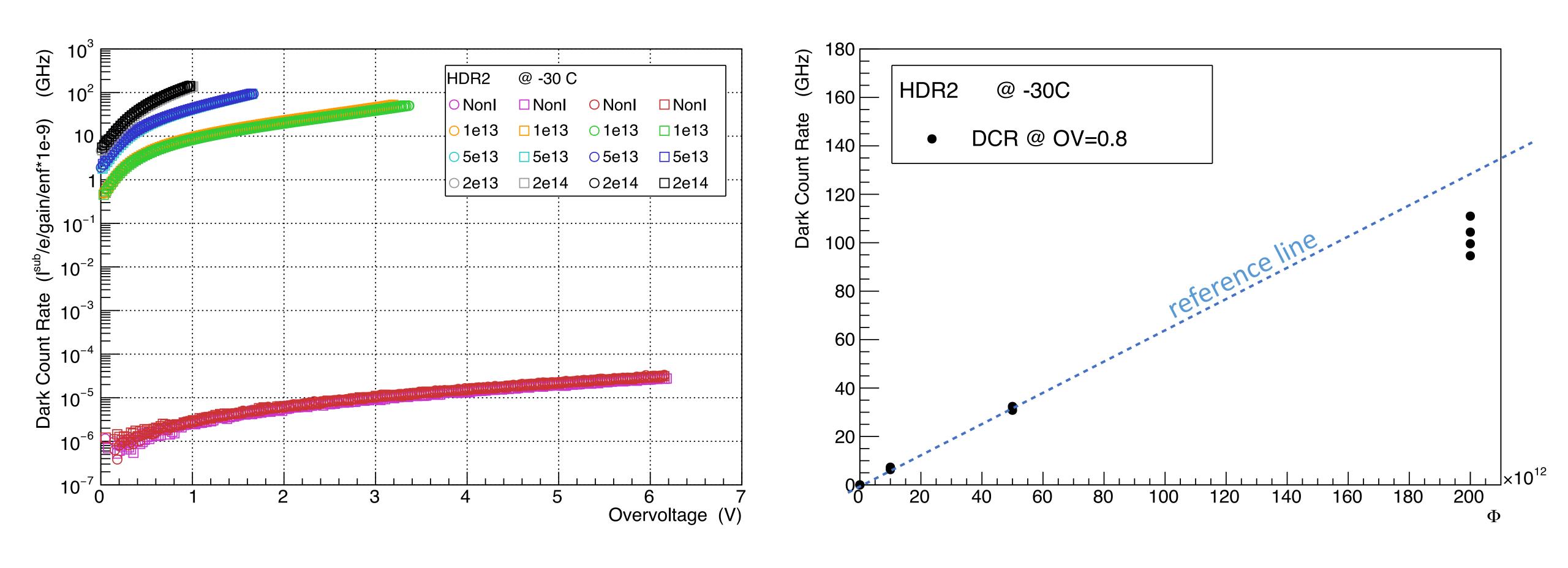
- IV curves are measured for each HDR2s at various temperatures
- V_{br} is computed from inflection point after HDR2 enters into geiger mode domain
- Linear dependence with Temp found for all HDR2s. Similar slope ~37mV/deg
- Strong linear increase of intercept with fluence found in data



Vbr as function of temperature for HDR2 with different levels of radiation damage



Dark Count Rate (DCR) as function of OverVoltage

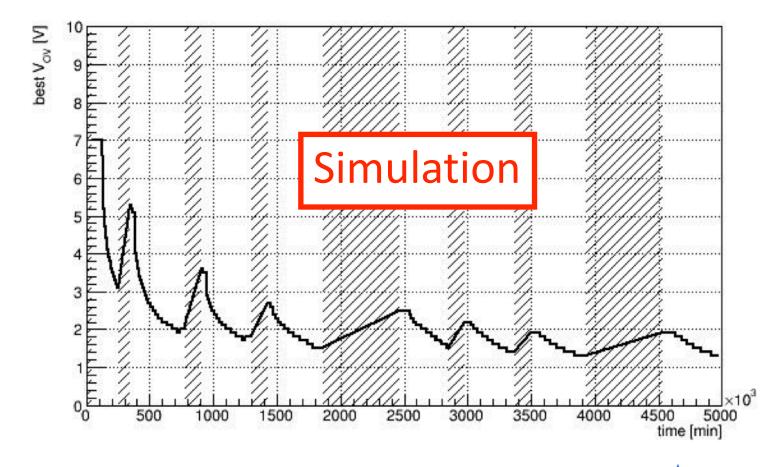


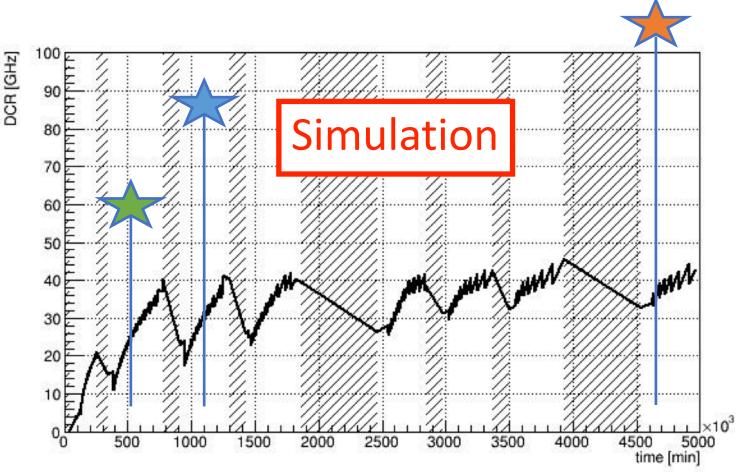
- DCR increases very rapidly with radiation damage!
- At -30C and 0.8 OV rise from 5 kHz to 100 GHz depending on radiation damage

Extrapolation of Performance for a Ten Year Scenario

Results for
$$T_{op} = -45^{\circ} \text{ C}$$
, $T_{ann} = 40^{\circ} \text{ C}$

• T_{ann} = 40° C throughout the whole duration of Technical Stops / Long Shutdowns



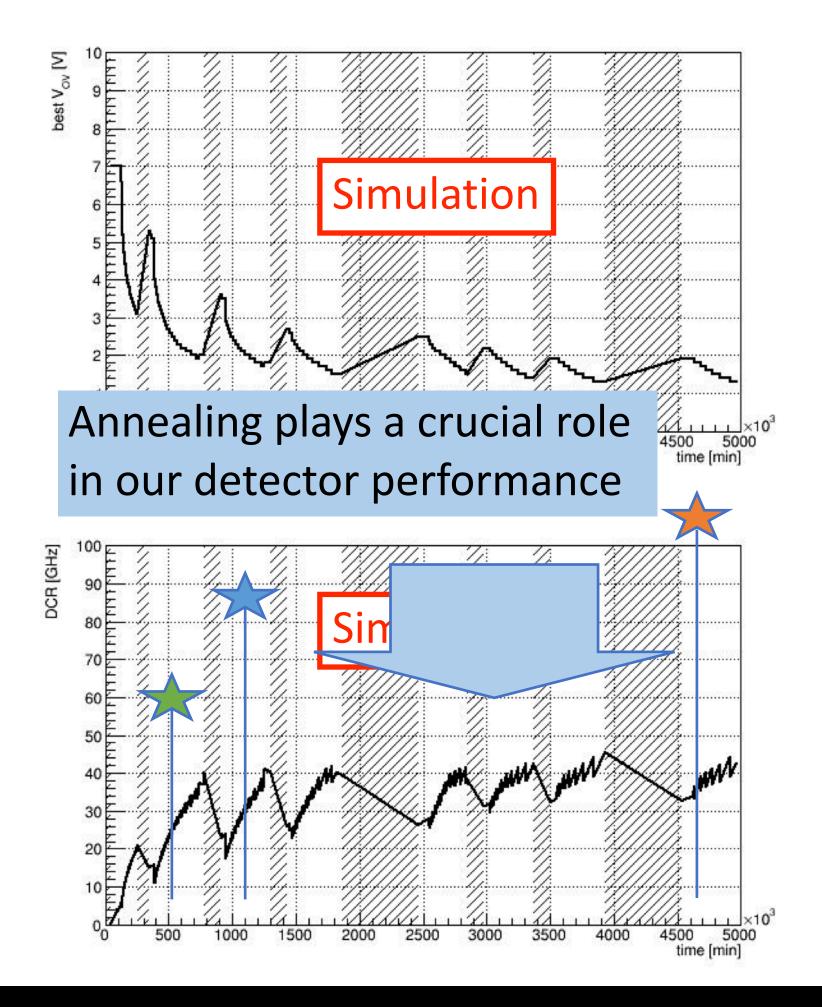


- Silicon recovers most of its properties by heat treatment: annealing
- Thermal motion reduces structural defects and stress caused by radiation
- Periods of annealing are foreseen for BTL during LHC shutdowns as depicted by the gray bands in the plots
- To obtain DCR levels at the TB operational temperature, comparable to what we expect in BTL at the end of life, we subjected four SiPMs to a high-temperature annealing procedure

Extrapolation of Performance for a Ten Year Scenario

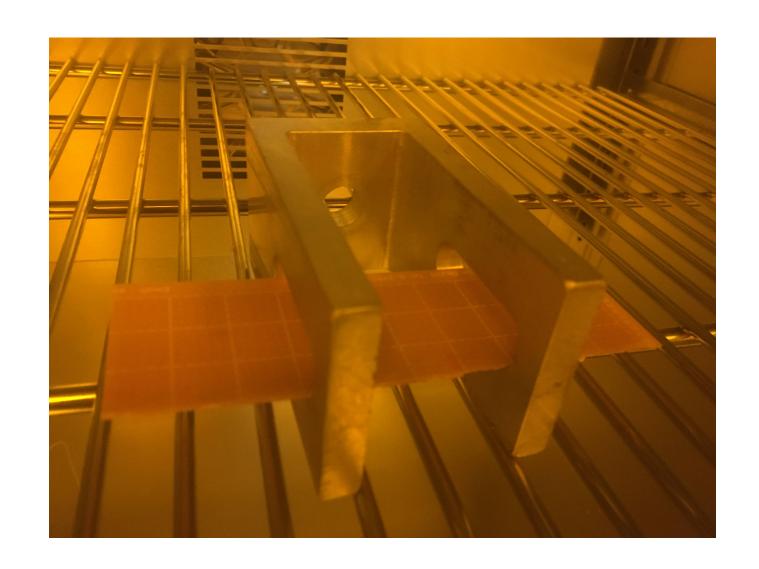
Results for
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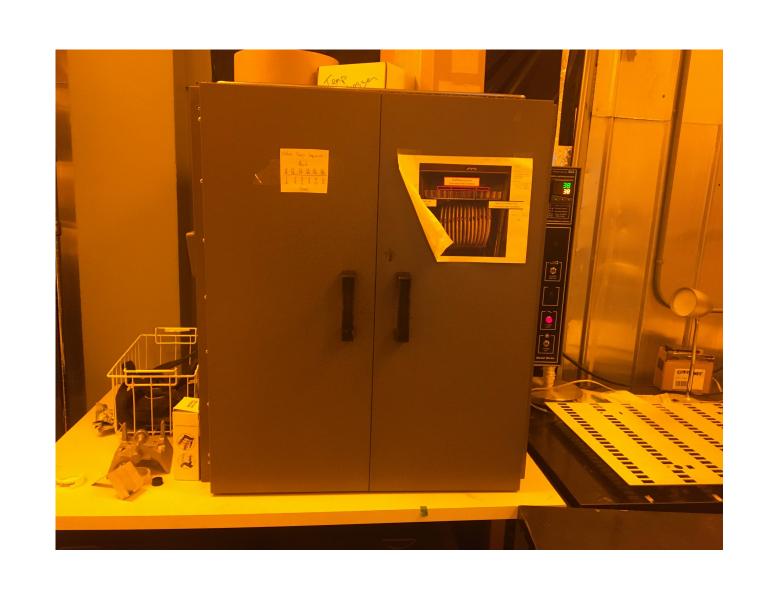


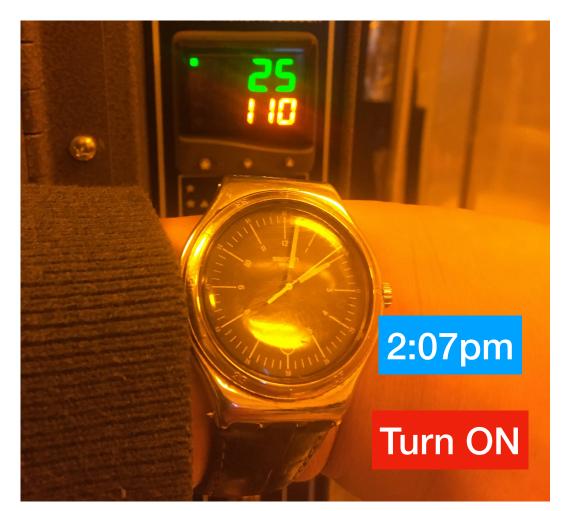
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High Temperature Annealing



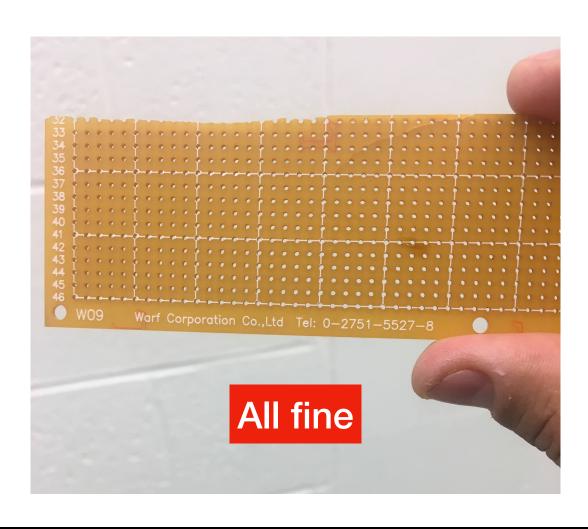
It was shown by T. TSang [2018 JINST 13 P10019] that SiPMs can withstand high temperature annealing procedure up to 250 C (also HPK although with epoxy resin)



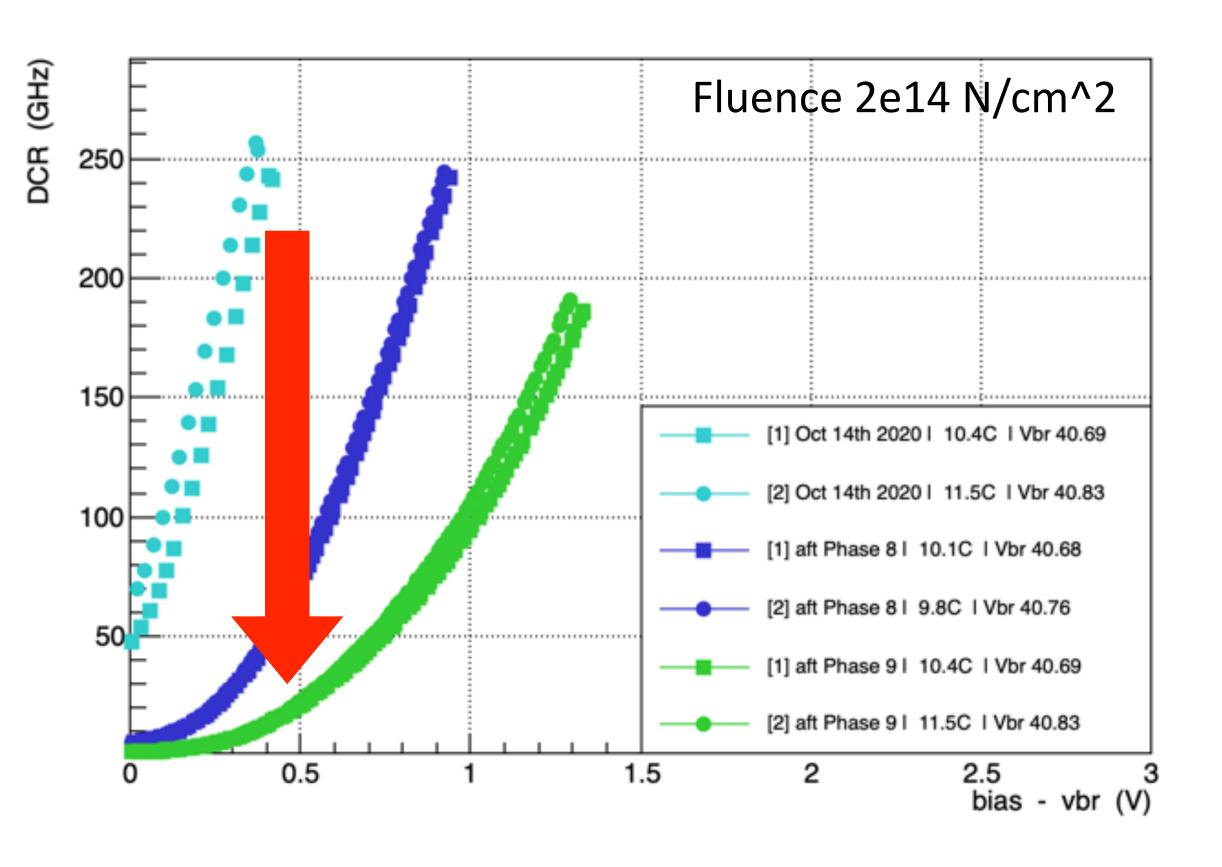


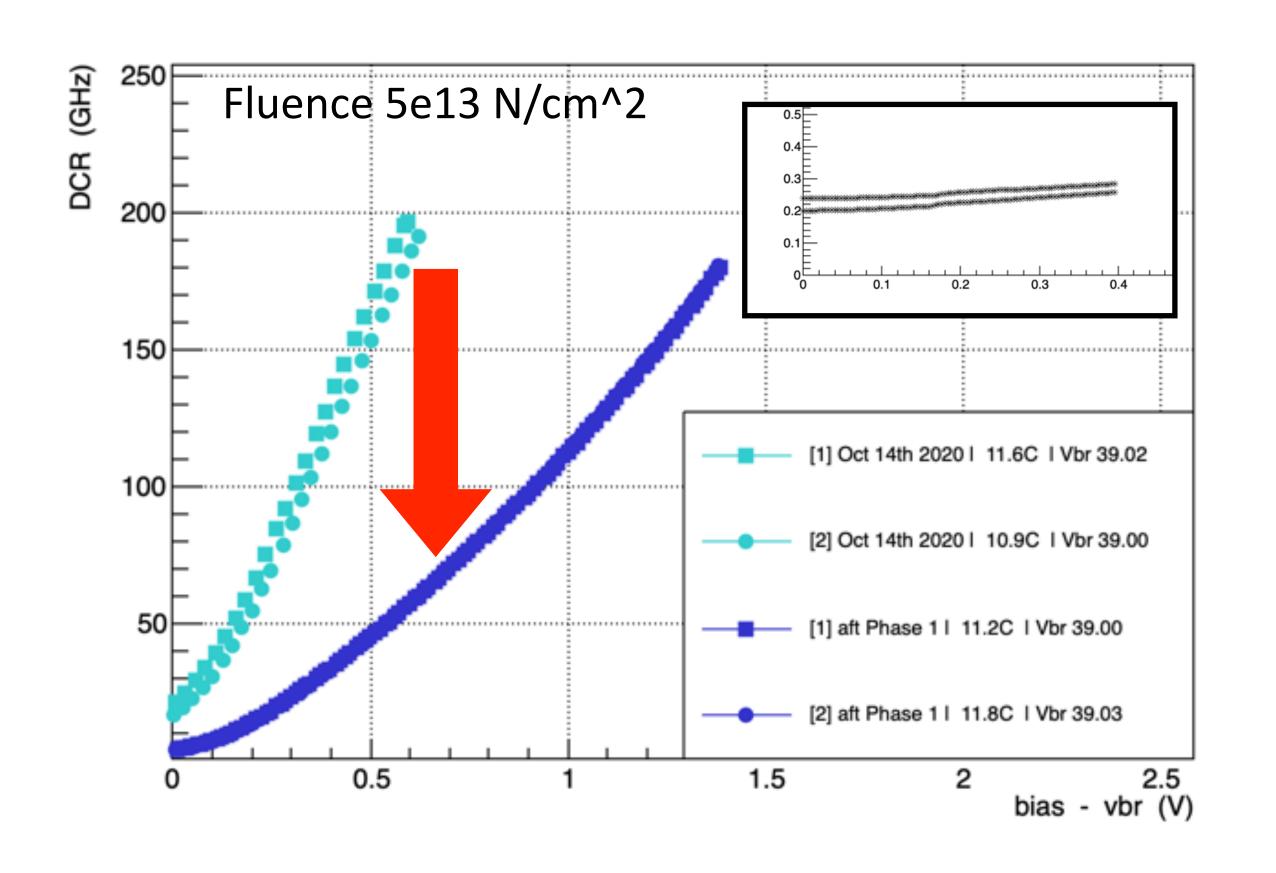






Annealing Performance in the Lab





• Phase 8: 2 hours at 110C Storing at 10 deg

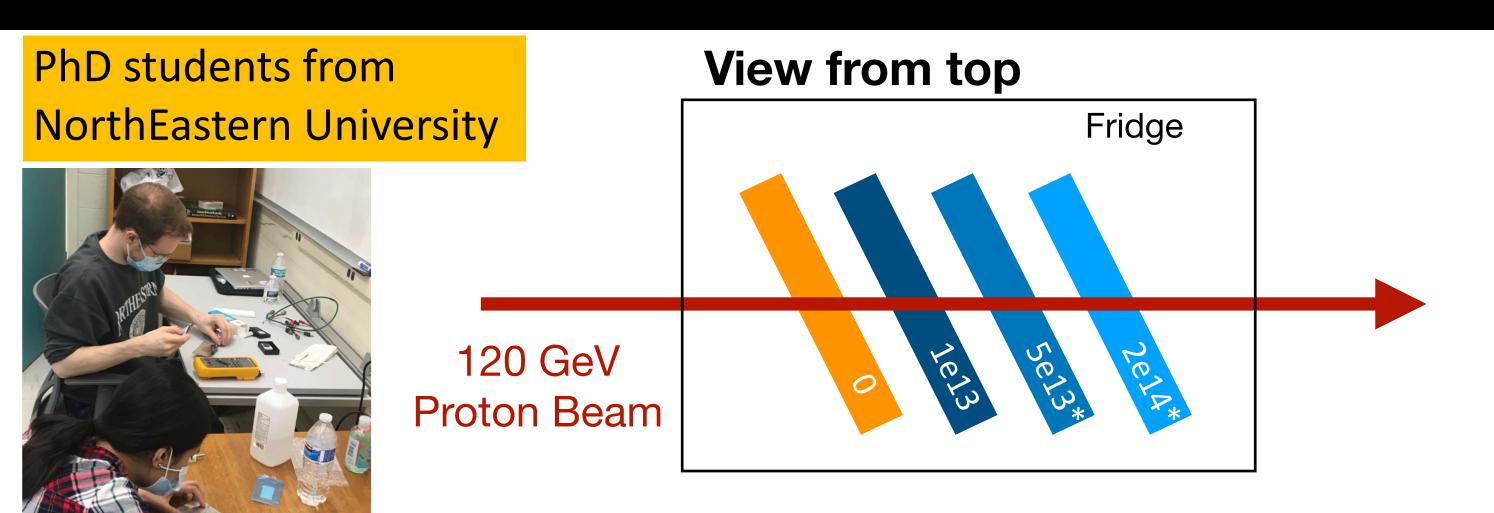
• Phase 9: 4 days at 120C

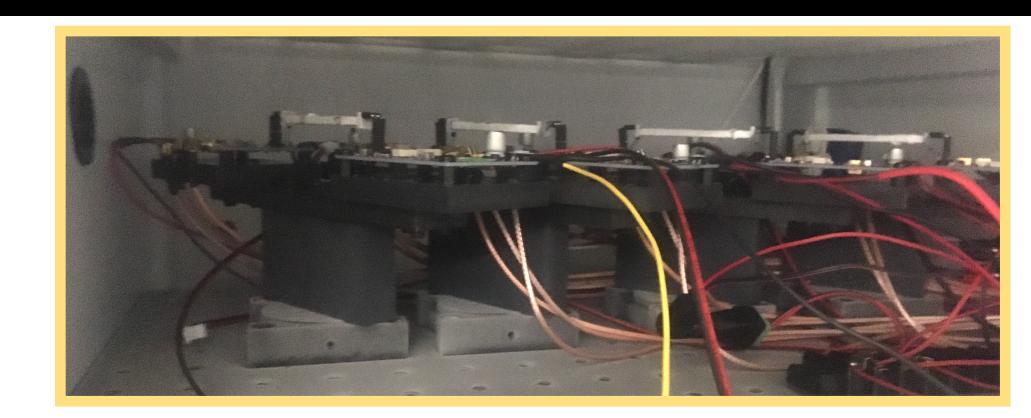
• Phase 1: 2 days at 90C Factor 5!

• Worth mentioning here: The full detector will have an active thermal layer between the SiPMs and cooling to locally anneal SiPMs only (more on this later)

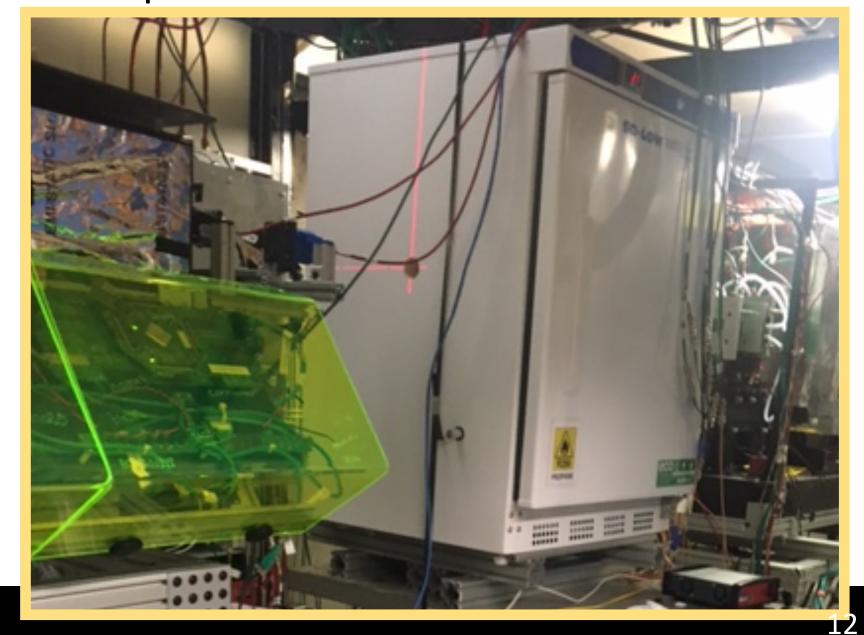
Nov, 29th 2022 | CPAD'22 | CPAD'22

May'21 Testbeam: Prototype Perf. w/Irrad SiPMs





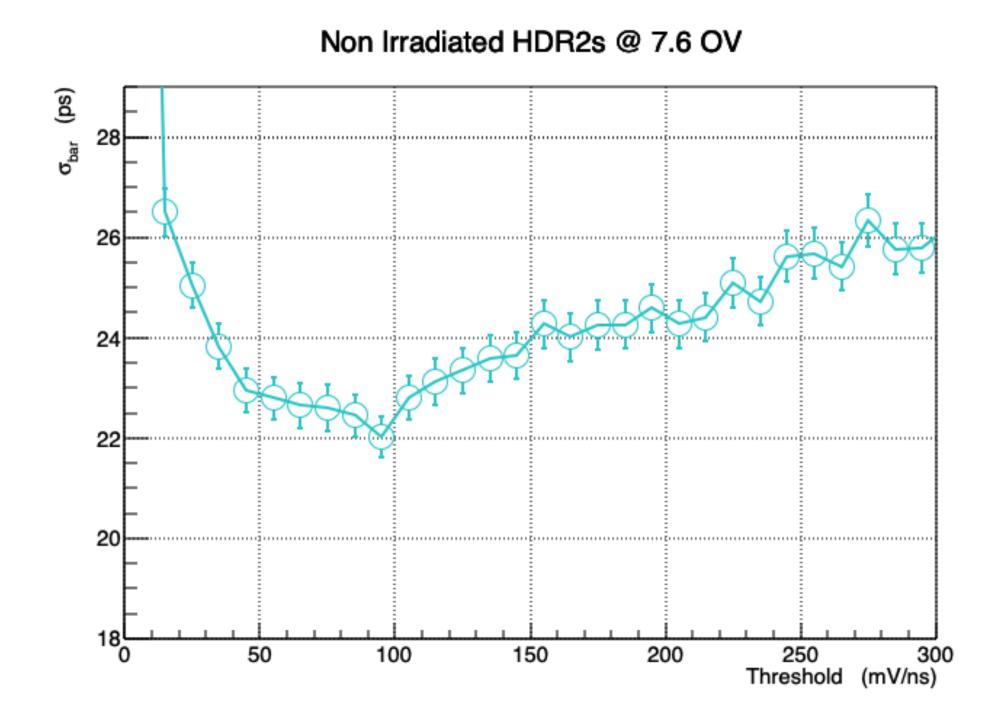
- Four BTL prototypes with different levels of radiation simultaneously exposed to a 120 GeV proton beam
 - 0, 1e13, 5e13*, 2e14* (Neq/cm²)
- Setup allowed to rotate bars wrt beam up to 52 deg
- Temperature was monitored at each HDR2 via thermistors
- HDR2 signals read via two-gain amplification board; digitized by DRS4 chip
 - Attempt to complement and diagnosed part of BTL ASIC



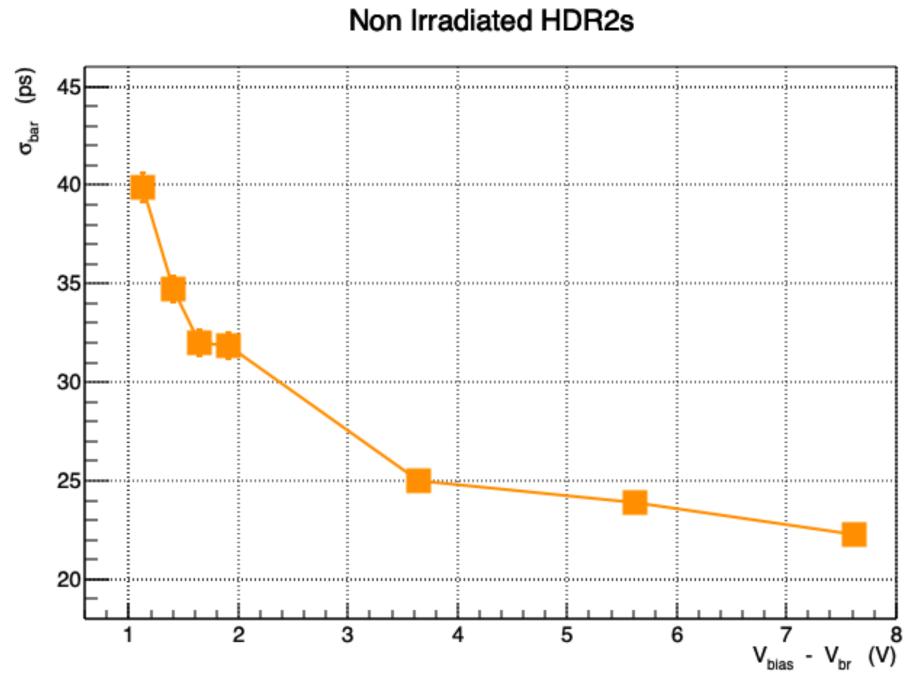
Timing Resolution for NonIrradiated Prototype

• Response to MIP was found to be within expectations [1]

- [1] Test beam characterization of sensor prototypes for there CMS Barrel MIP Timing Detector. 2021 JINST 16 P07023
- Depending on V_{op}, HDR2+LYSO are demonstrated to achieve better than 23 ps resolution
- Threshold optimization for V_{op} is essential and part of BTL's ASIC configuration
- Optimization has to be fine-tuned as radiation effects take place



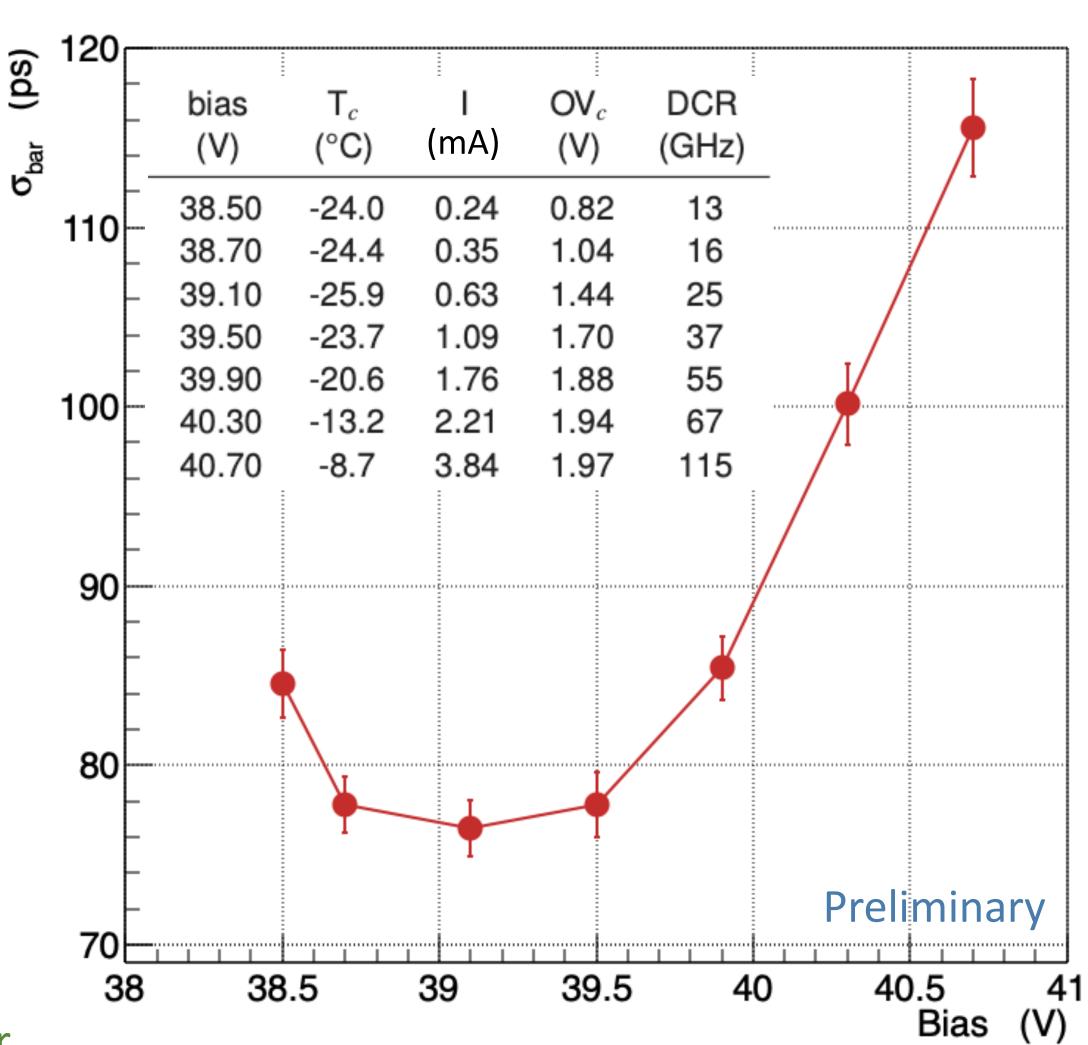
Results presented in IEEE2021 last October



Timing Resolution for Prototype with Irradiated HDR2

- Procedure to estimate OverVoltage (OV) based on deviation of MPV/PDE/GAIN was applied
- Internal temperature was computed based on V_{br}(T_c)
- DCR was scaled from I_{SiPM} using gain curves from nonirradiated HDR2
- Optimal time resolution for different V_{op} and internal temperatures are presented
- Temperatures no further down than -25C were explored, due to lack of TEC units in prototype single-bar detector
- Worth mentioning here: The full detector will be working at a temperature of -45C, after annealing we expect a DCR of 40 GHz at EndOfLife

Irradiated HDR2s



Results presented in IEEE2021 last October

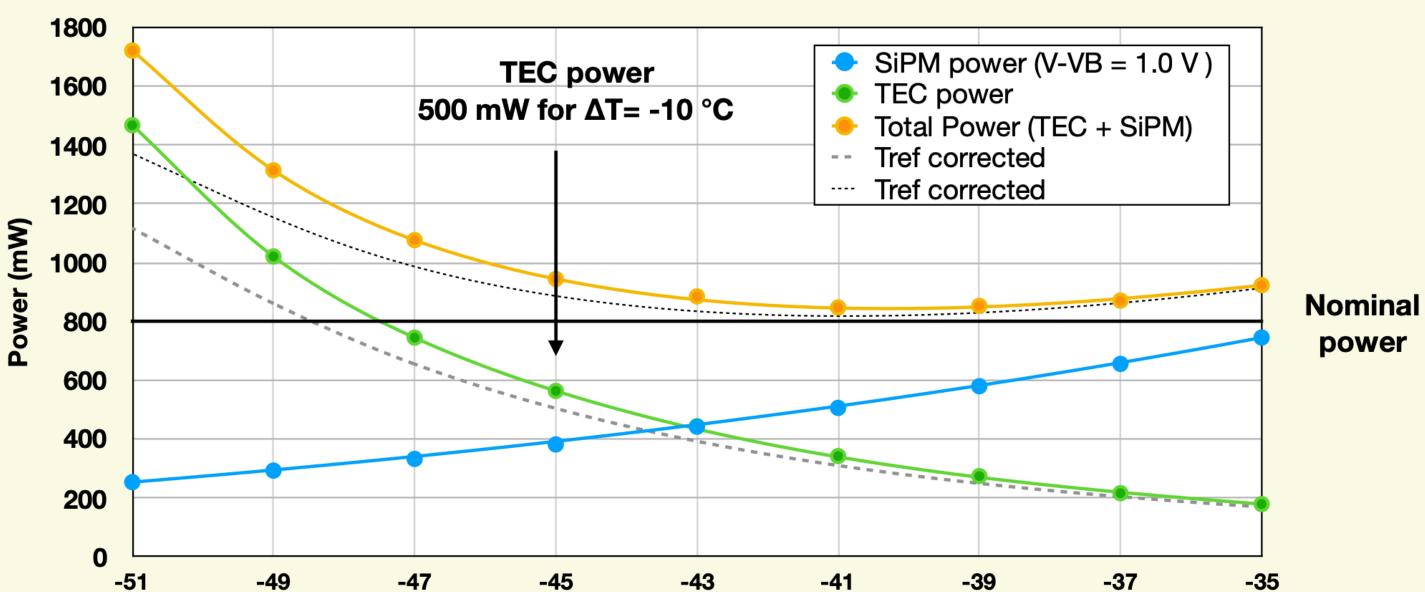
Reducing DCR by Design

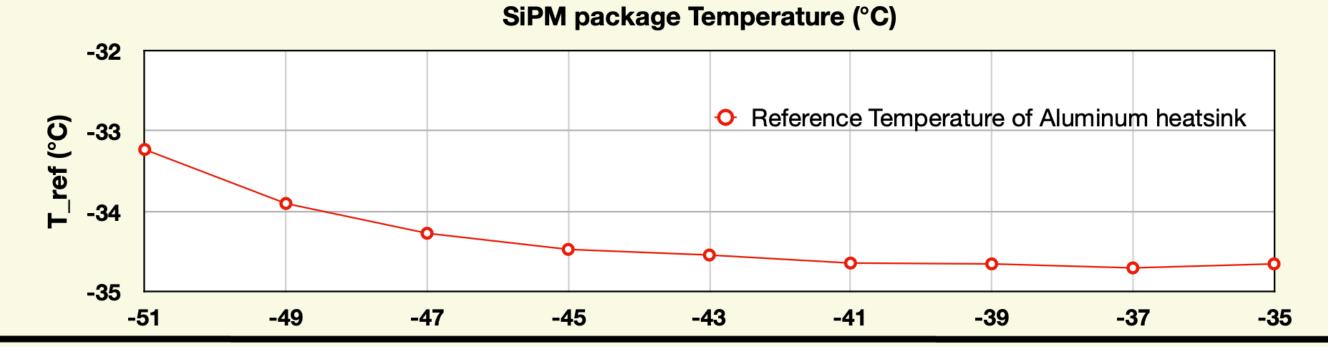


Total power consumption for full array at 1 V over voltage







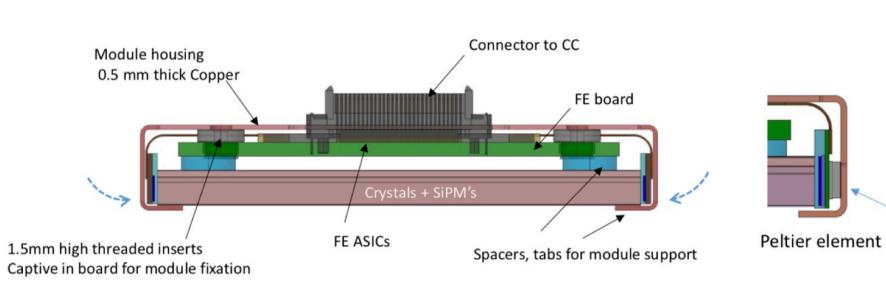


March 18, CPAD 2021 Stony Brook, NY











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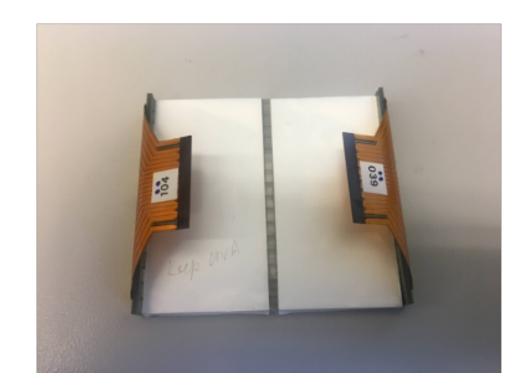
Modules Under Study

- Module 1
 - LYSO 33300060000739
 - Length 55.25 mm
 - Width 51.66 mm
 - 2-102 HPK S15408-32TC (ES1)
 - 2-98 HPK S15408-32TC (ES1)



- LYSO 33300060000738
 - Length 55.22 mm
 - Width 51.95 mm
- 2-39 HPK S15408-32TC (ES1)
- 2-104 HPK S15408-32TC (ES1)
- Module 3
 - LYSO 33300060000763
 - Length X mm
 - Width X mm
 - 2-86 HPK S15408-32TC (ES1)
 - 2-88 HPK S15408-32TC (ES1)

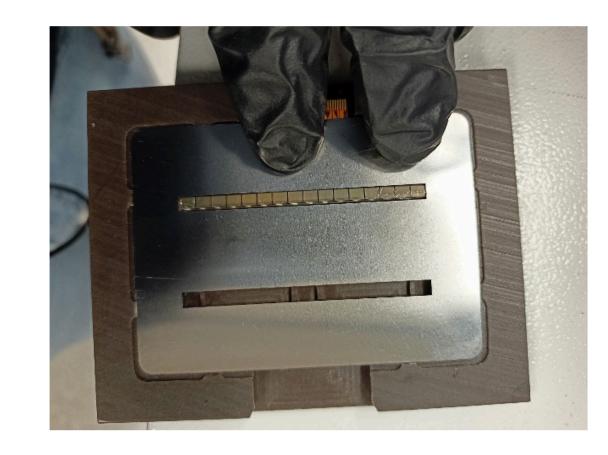


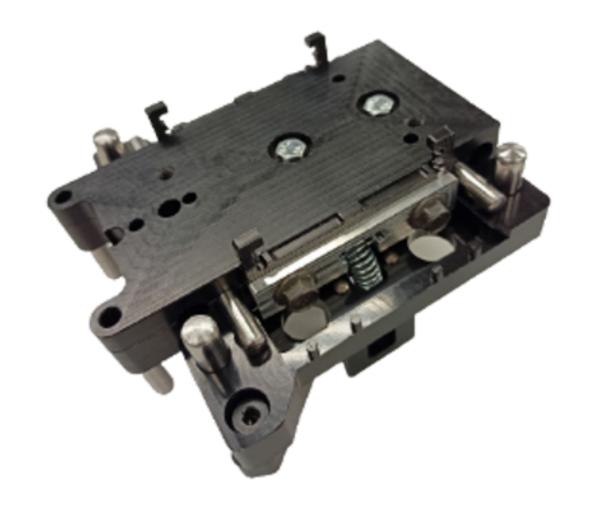


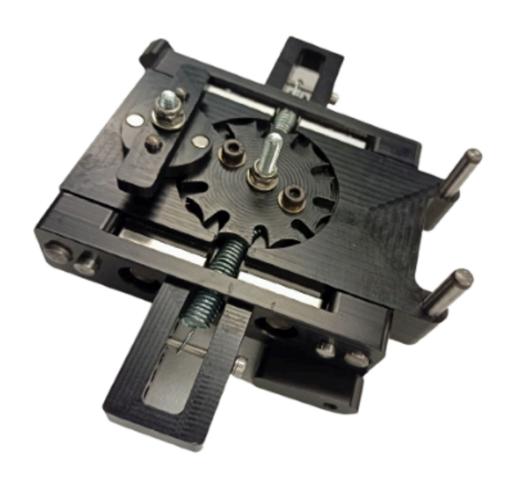


Three modules were assembled at UVA for testing

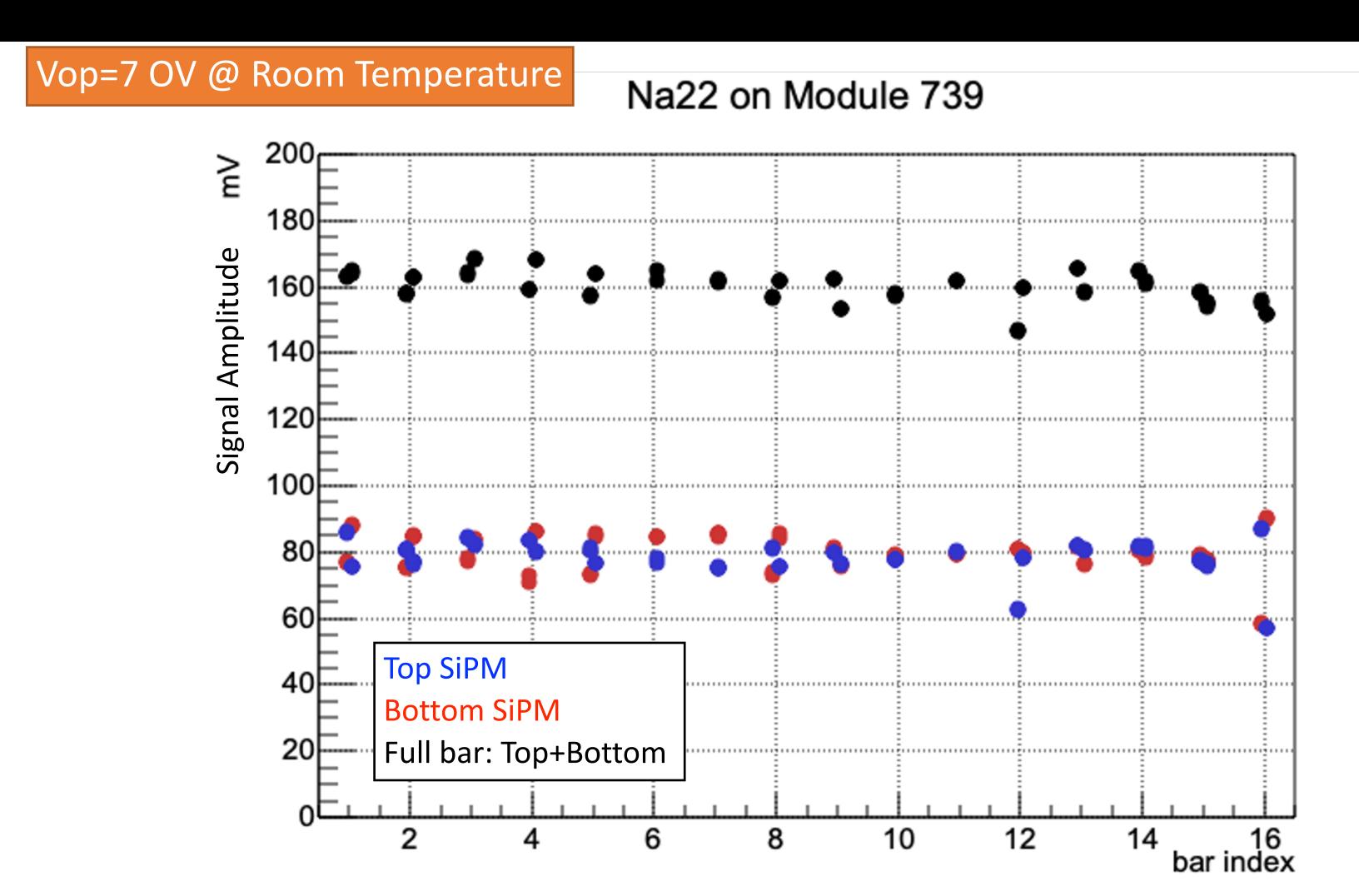




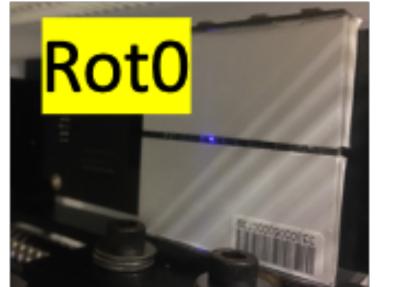




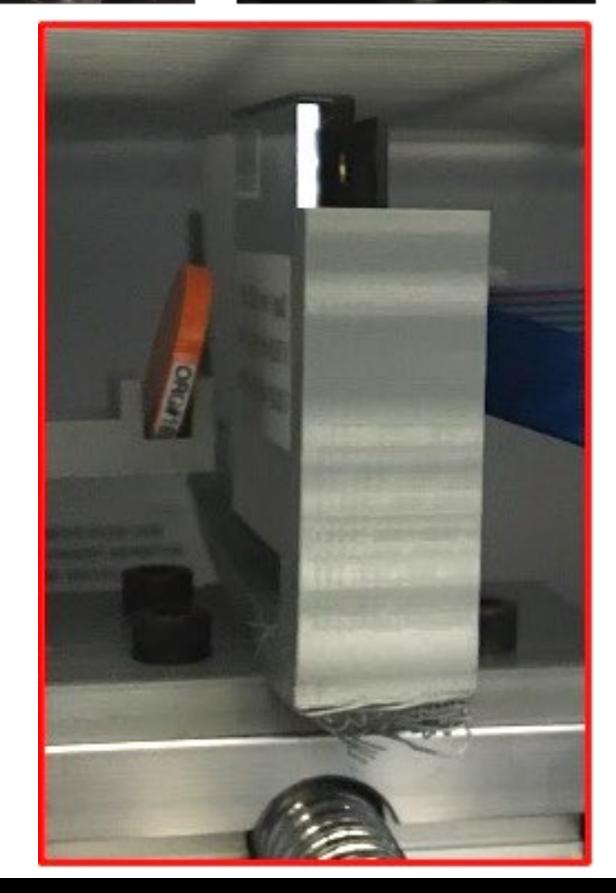
Na22 Test



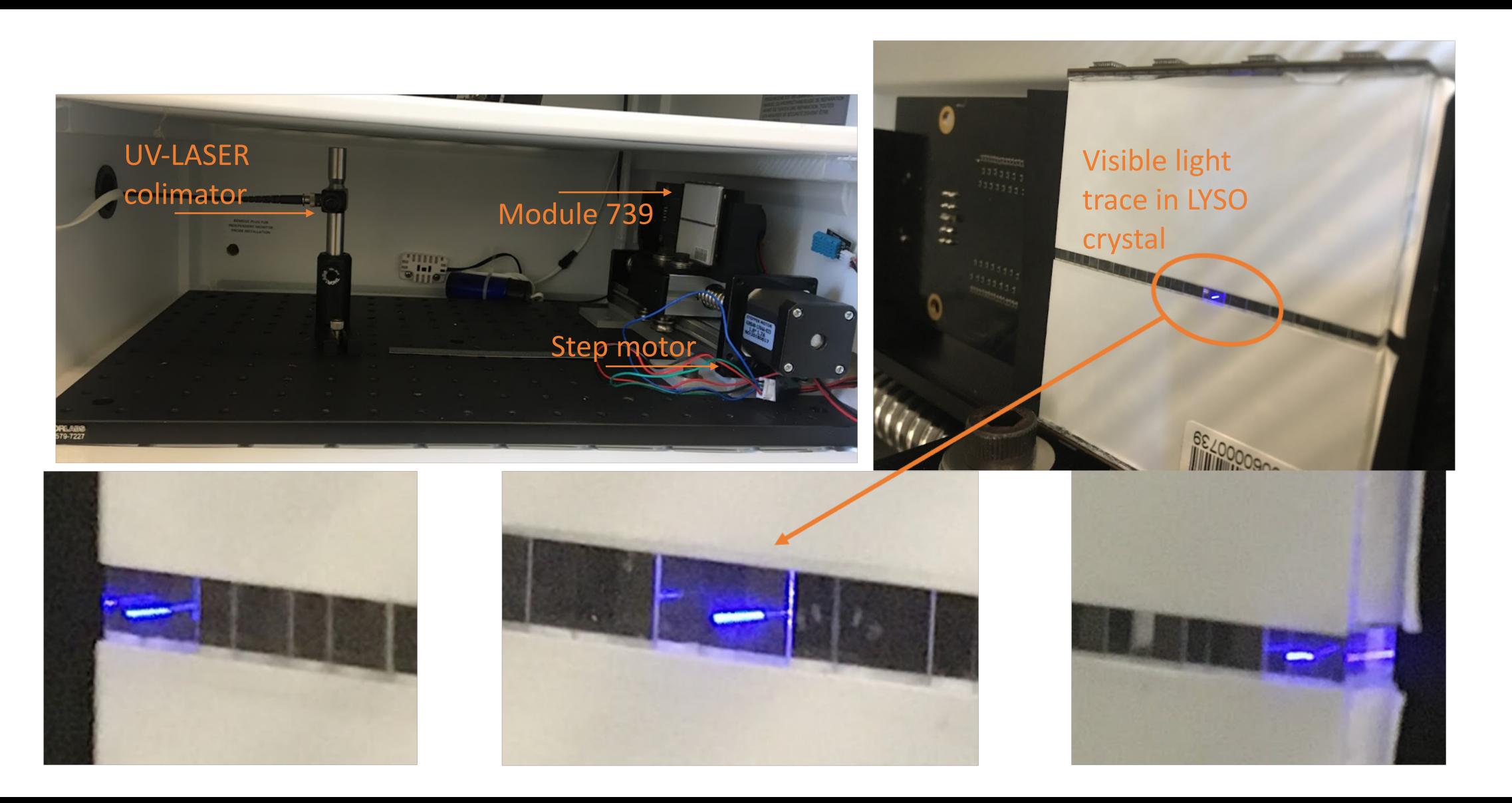
• Energy calibration of electronics while scanning across bars in prototype module also shows module homogeneity





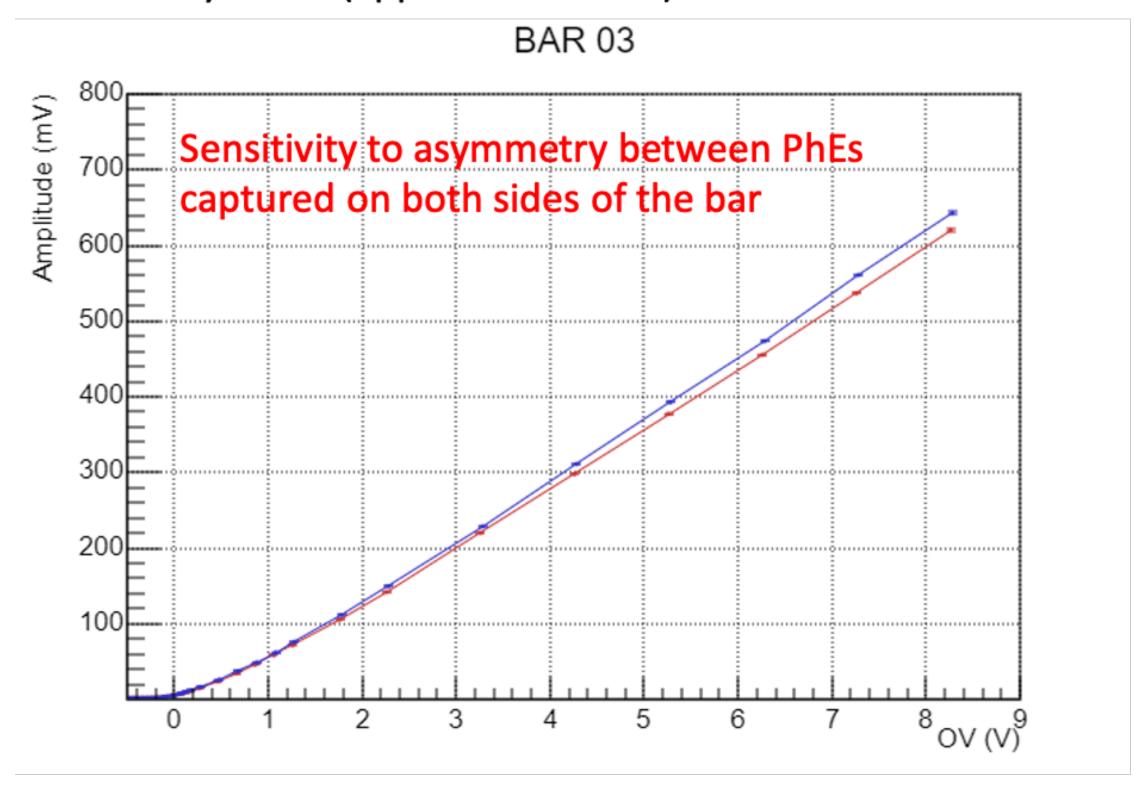


UV-Laser Scan Tests



UV Laser on Module 739

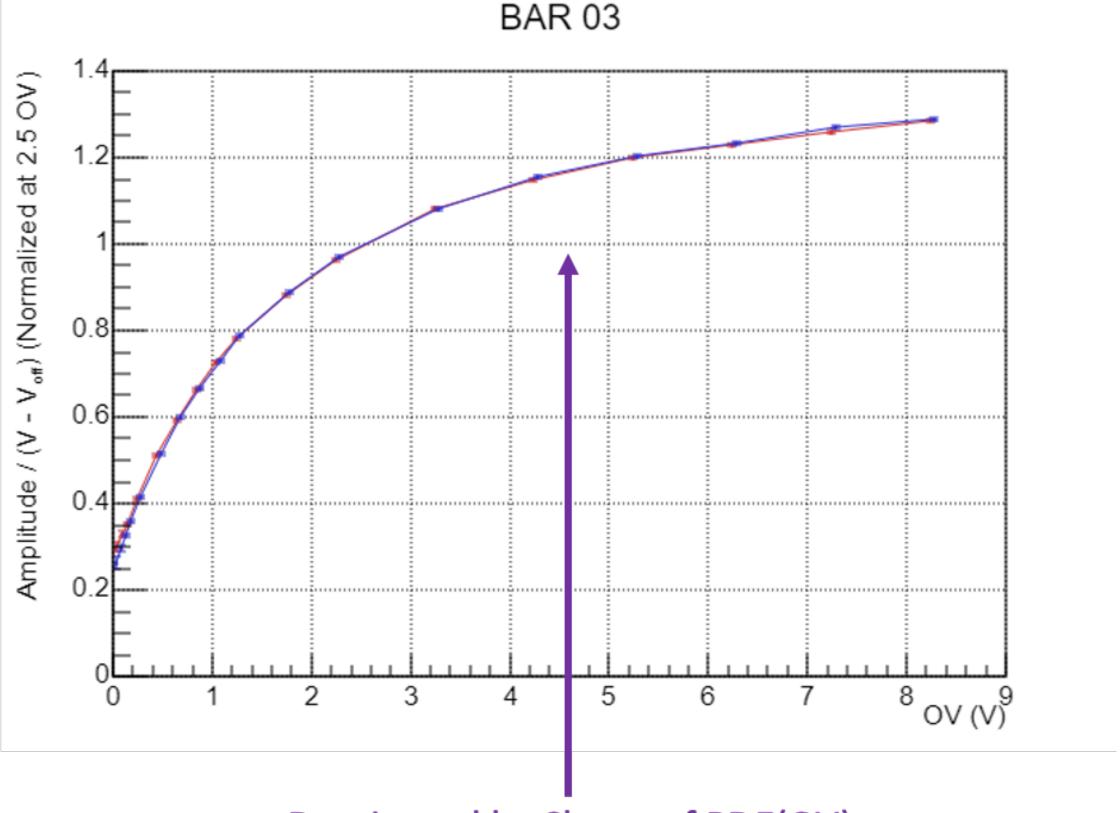
UV source centered on bar 03 T approx. +19C Intensity to 8.0 (approx. ~2.9 MeV)



Amplitude is proportional to



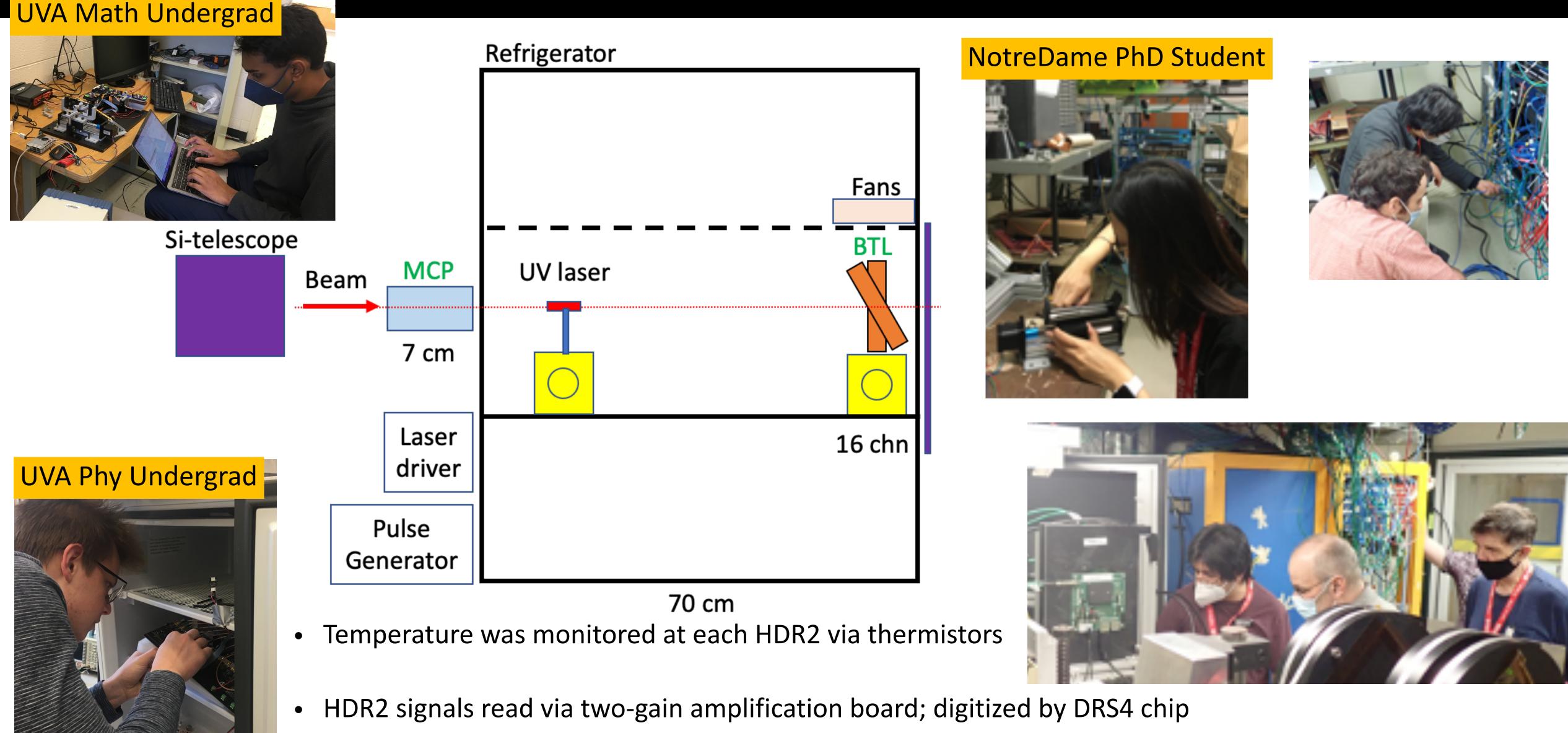




Dominated by Shape of PDE(OV)

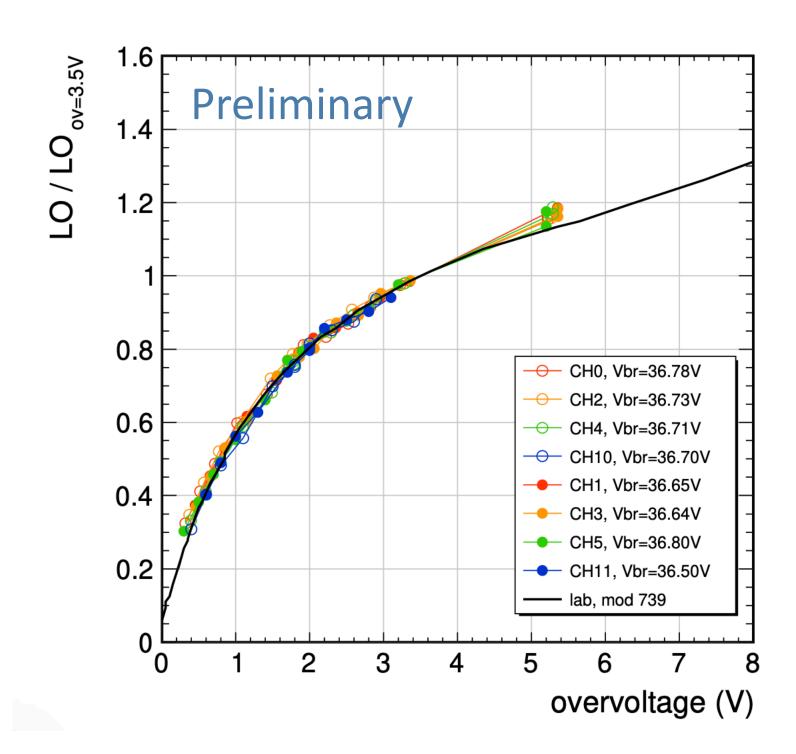
Voff approx. as Vbr - 0.4

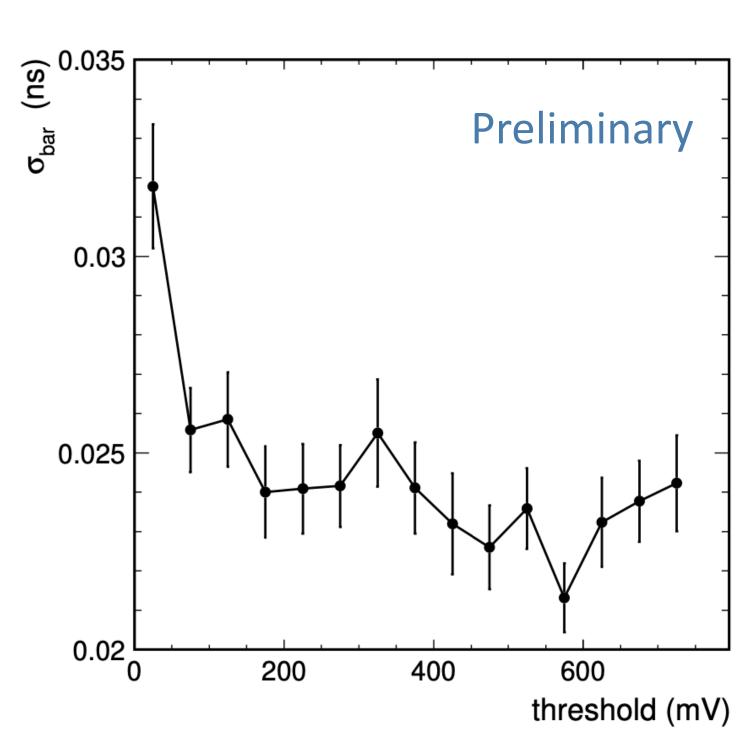
Testbeam Jun'22: Protons and Electrons on Full Module



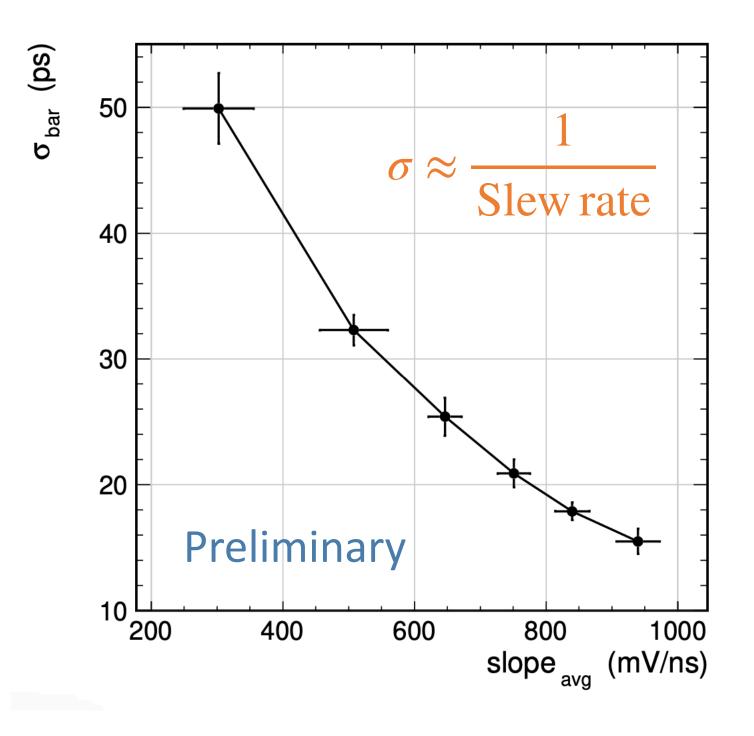
Preliminary Results (28 GeV Electrons on Full Module)

Relative Light Output (LO) measure with proton beam compared to laser measurements



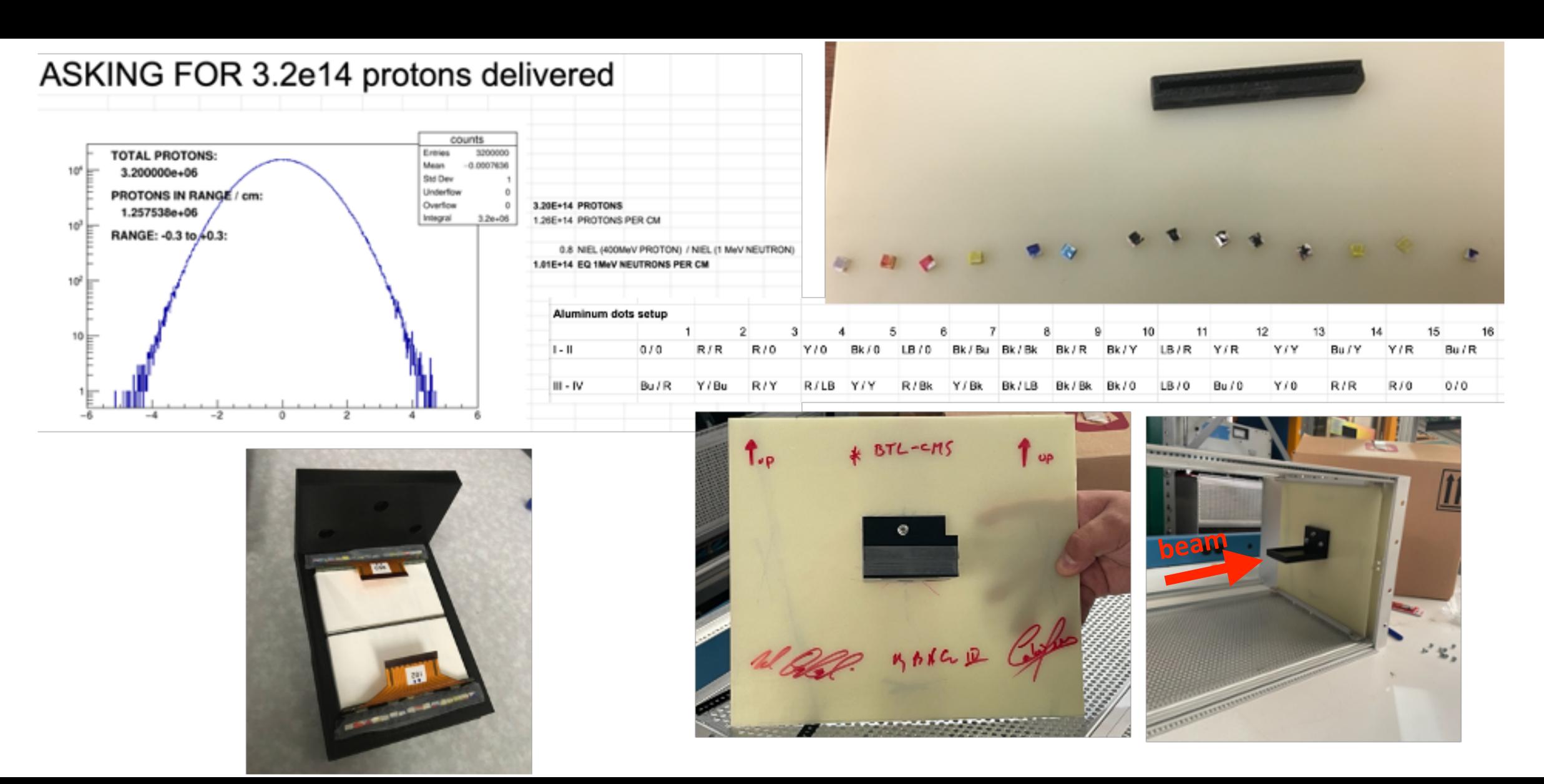


Time Resolution as a function of slew rate



Time Resolution (slew rate > 500 mV/ns) measured with protons on full module. Compatible with measurements obtained on Single-Bar-Protoype

Full Module to Fermilab ITA



Summary

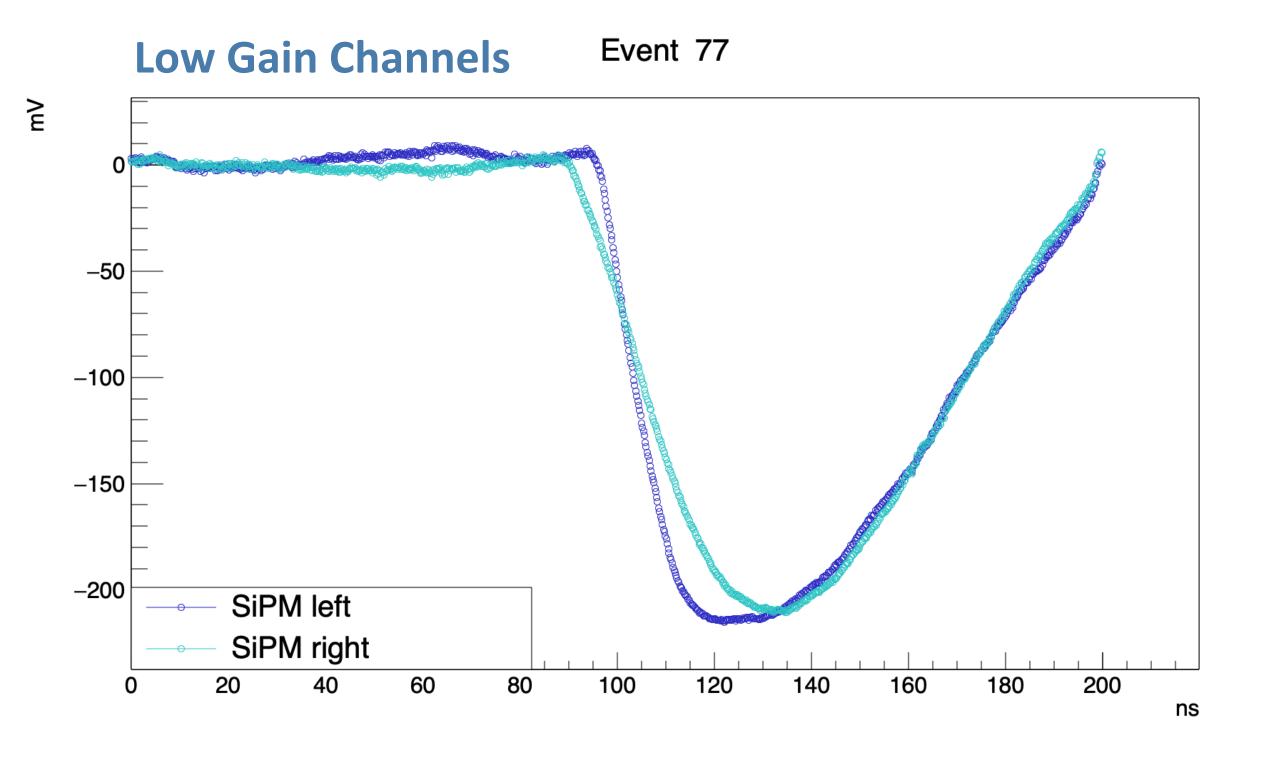
- \bullet Preliminary results for V_{br} and DCR for various temperatures and various levels of radiation damage on HDR2s were presented
- Various waveform analysis methods were studied to complement ASIC (based on TOFHIR design) configuration
- Results presented here further improve our understanding radiation damage effects on detector performance
 - Once radiation damage effects are fully understood, we will optimized our ASIC configuration to get optimal resolution at every time
- Uniformity of response of full module was assessed with Na-22, laser and protons.
- Timing response of full module measured with electrons was found to be better than 30ps
- Full module has been irradiated to check integrity of the whole assembly and test overall resolution
- We plan to test this newly irradiated module on January'23 with protons at Fermilab

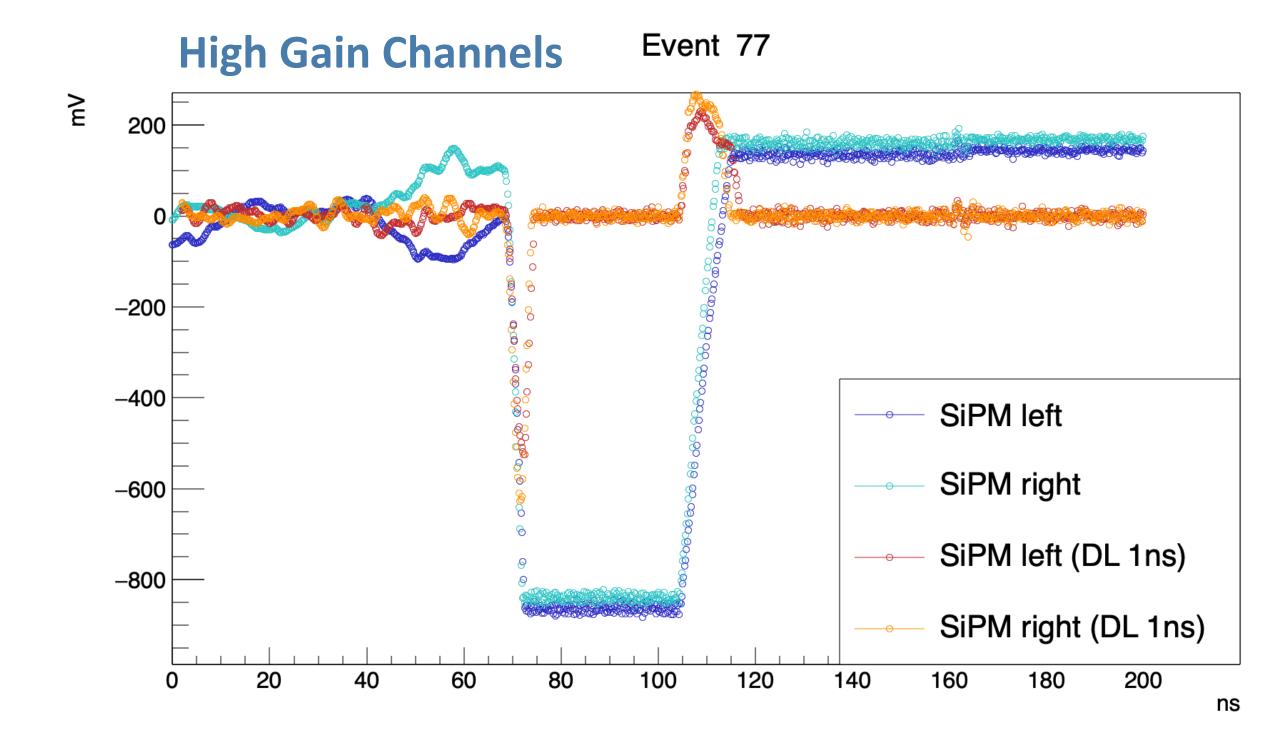
Thanks!

Backup

Event display for Irradiated HDR2s

- Data taken at 52 deg inclination with respect to the crystal's normal to surface
 (To mimic average energy deposition of 4.2 MeV which is the average expectancy in BTL detector)
- Signal digitized using CAEN DT5742 DRS4 chip 5GS/s Switched Capacitor Array

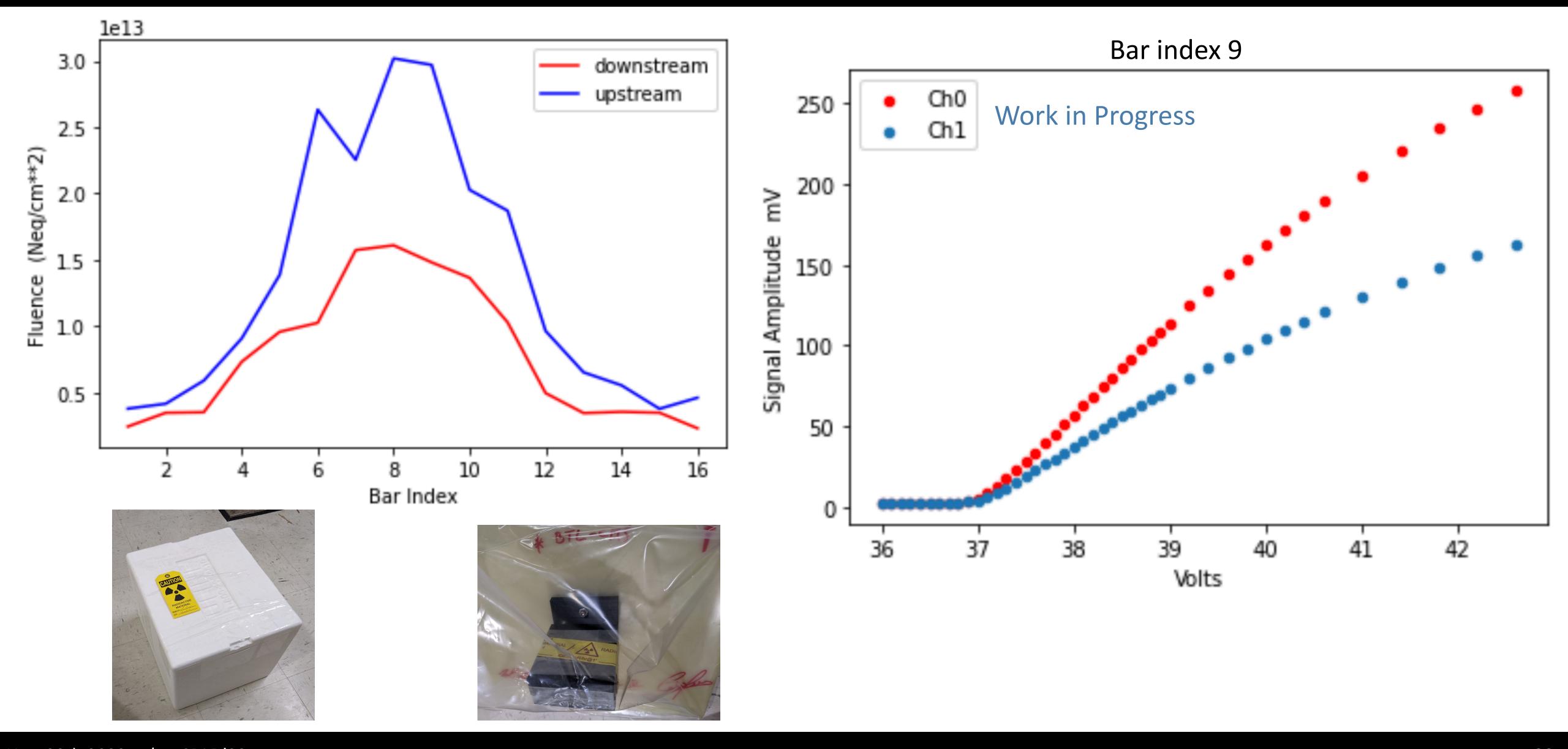


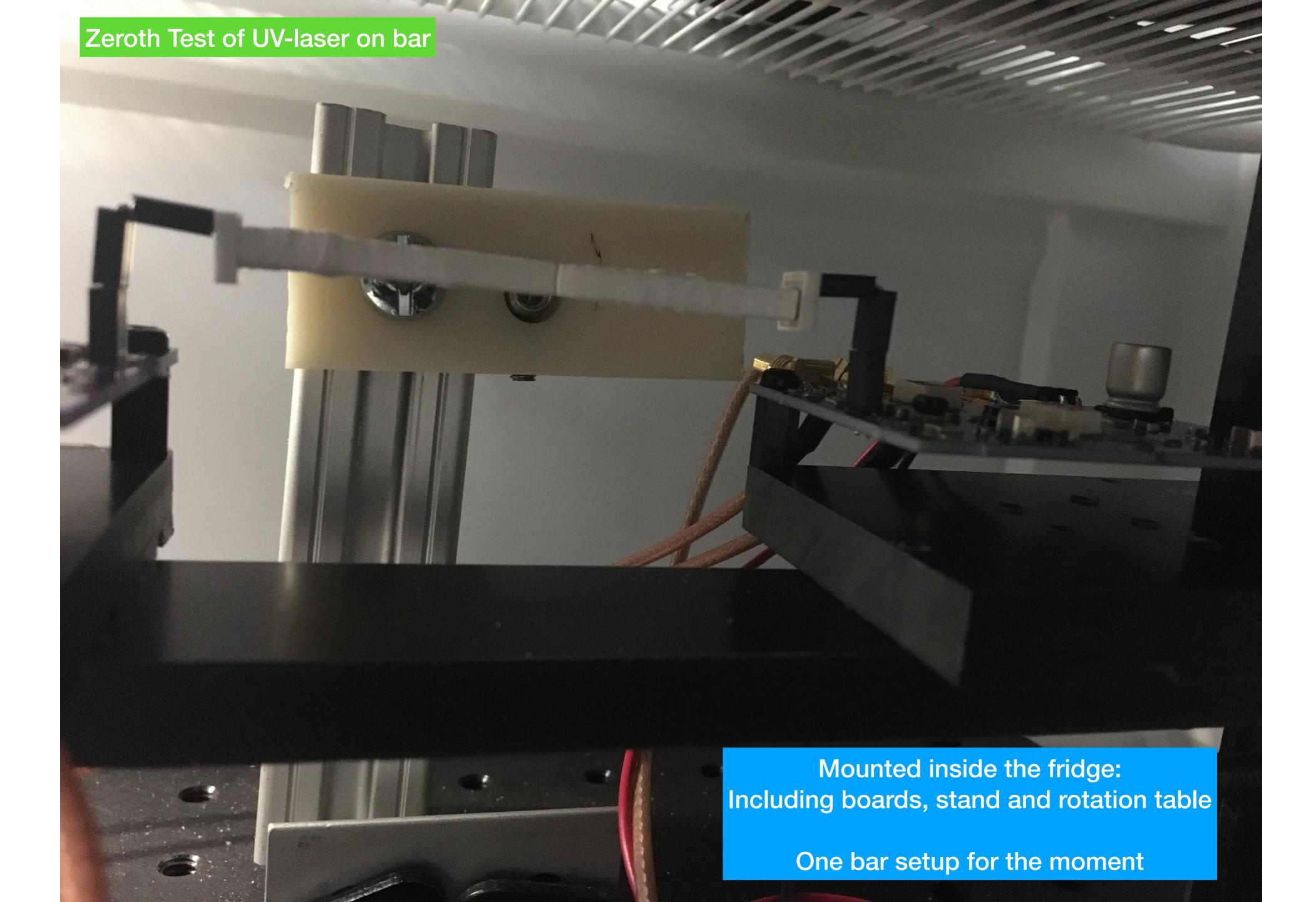


ITA Delivery of Protons to Module

83 total measurements found. Integrated protons at ITA: 17-Jun-2022-10:00:00 to 17-Jun-2022-17:06:39: 3.21e+14 ITA Proton Accumulation: 3.21e+14 100.30% of goal 32000000000000000.0. Shots so far:83 (100.30% of 3200000000000000.0) $\times 10^{12}$ ×1014 Count size range (excluding outliers): 3.9141e+12 +/- 1.1244e+11 Accumulated POT: 3.2095e+14 2022-06-17 15:42:14 Remaining POT: -9.5300e+11 2022-06-17 17:03:26 3.0 Integrated Protons Remaining beam pulse count: Between -2.3668e-01 and -2.5068e-01 Elapsed time in seconds since first beam: 4872.0 Goal Approx. time-averaged beam rate: 6.588e+10 protons per second. Per-shot E12 Approx. time-averaged shot interval 5.870e+01 s 2.5 Rough guess is 2022-06-17 17:03:11.707951 2.5 2.0 2.0 Remaining POT: -9.5300e+11 1.0 Typical pulse size [ppp]: 3.91e+12 +/- 1.12e+11 Remaining beam pulse count: 0.5 between -2.37e-01 and -2.51e-01 0.5 Estimated completion time: 2022-06-17 17:03:12 27 25:40 27 25:50 27 26:00 27 26:10 27 26:20 27 26:30 27 26:40 27 26:50 27 27:00

First Tests of Irradiated Module





The values of the theoretical "average" trigger rate, computed upon the given formulas, are reported in the following tables for $N_S = 1024$ samples.

N _G	TR Not Digitized	TR Digitized
1	6.813 kHz	6.058 kHz
2	3.409 kHz	3.030 kHz

Tab. 7.3: Theoretical "average" trigger rate values for the Optical Link

N _G	TR Not Digitized	TR Digitized
1	2.556 kHz	2.272 kHz
2	1.278 kHz	1.136 kHz

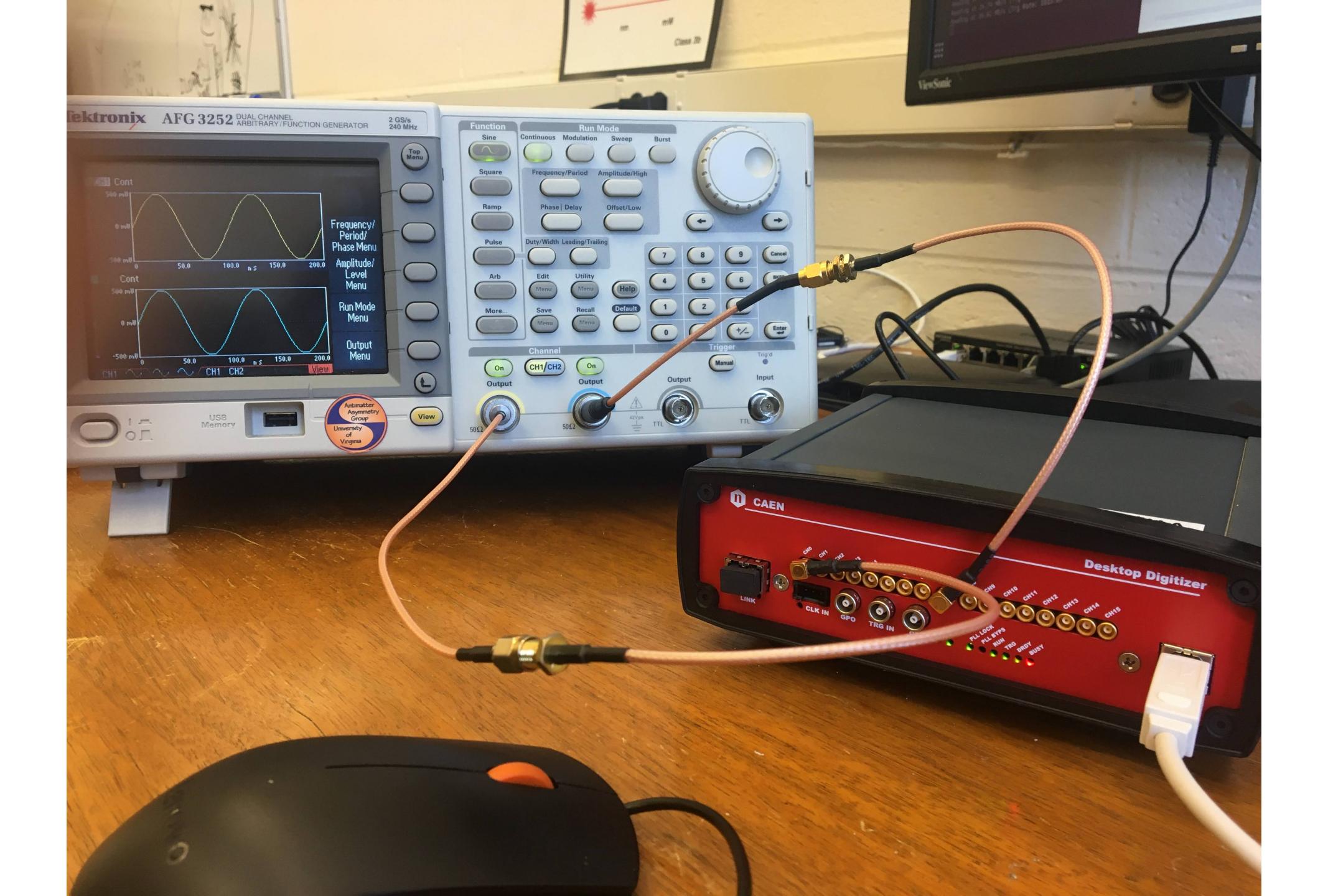
Tab. 7.4: Theoretical "average" trigger rate values for the USB Link

So theoretically for our use 16CH + TR0 digitized we will get

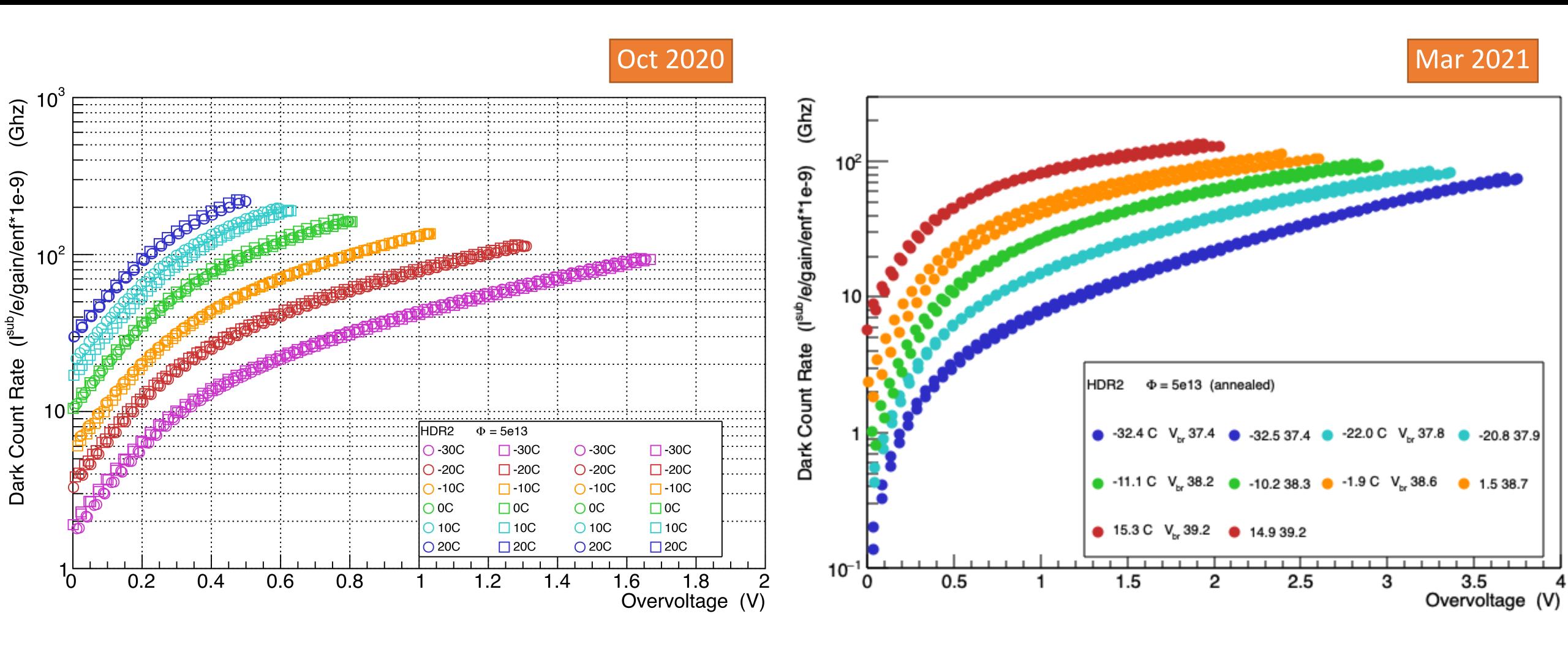
USB 1.136 kHz

PCI 3.030 kHz

50k MIPS in 13 min 4 min

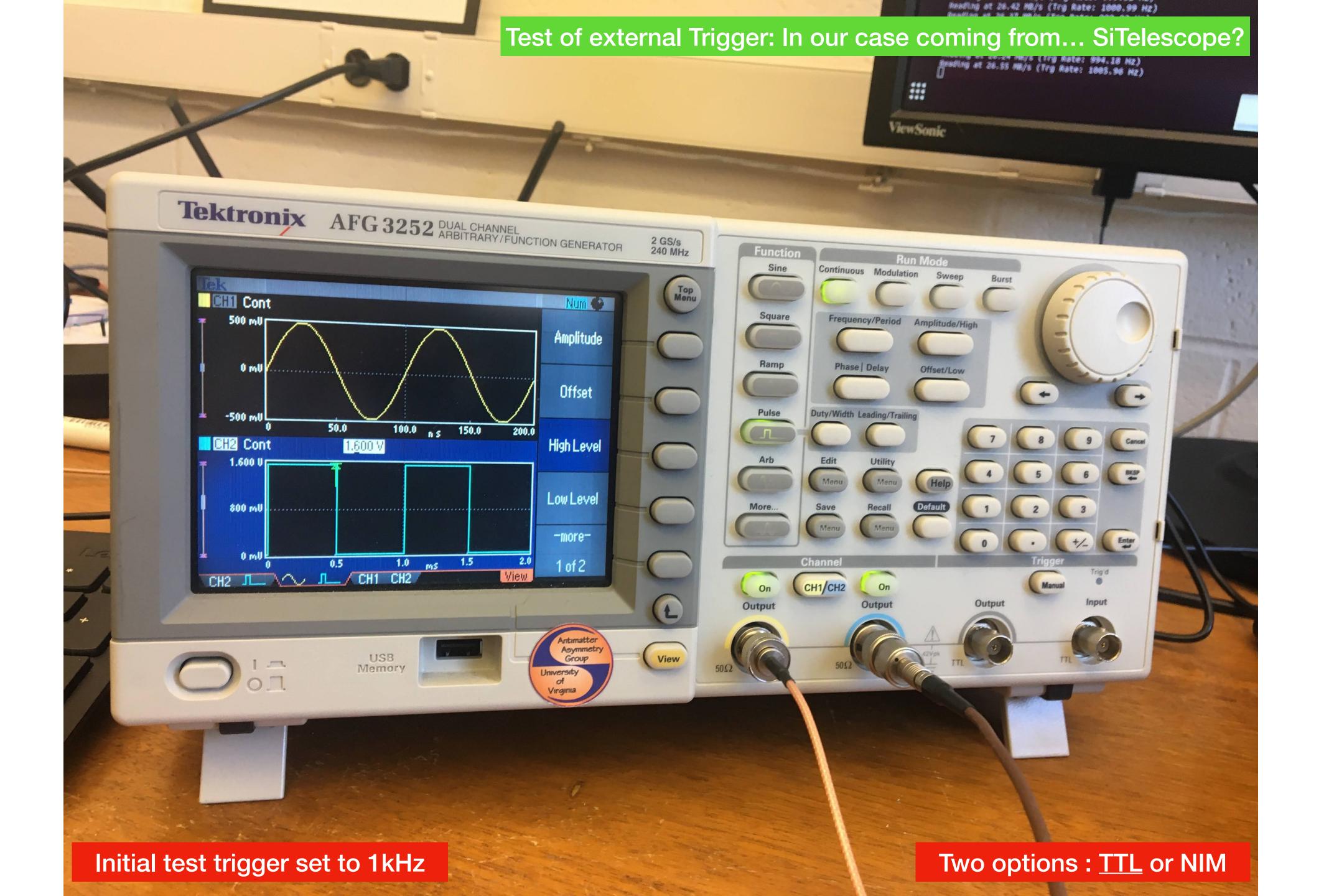


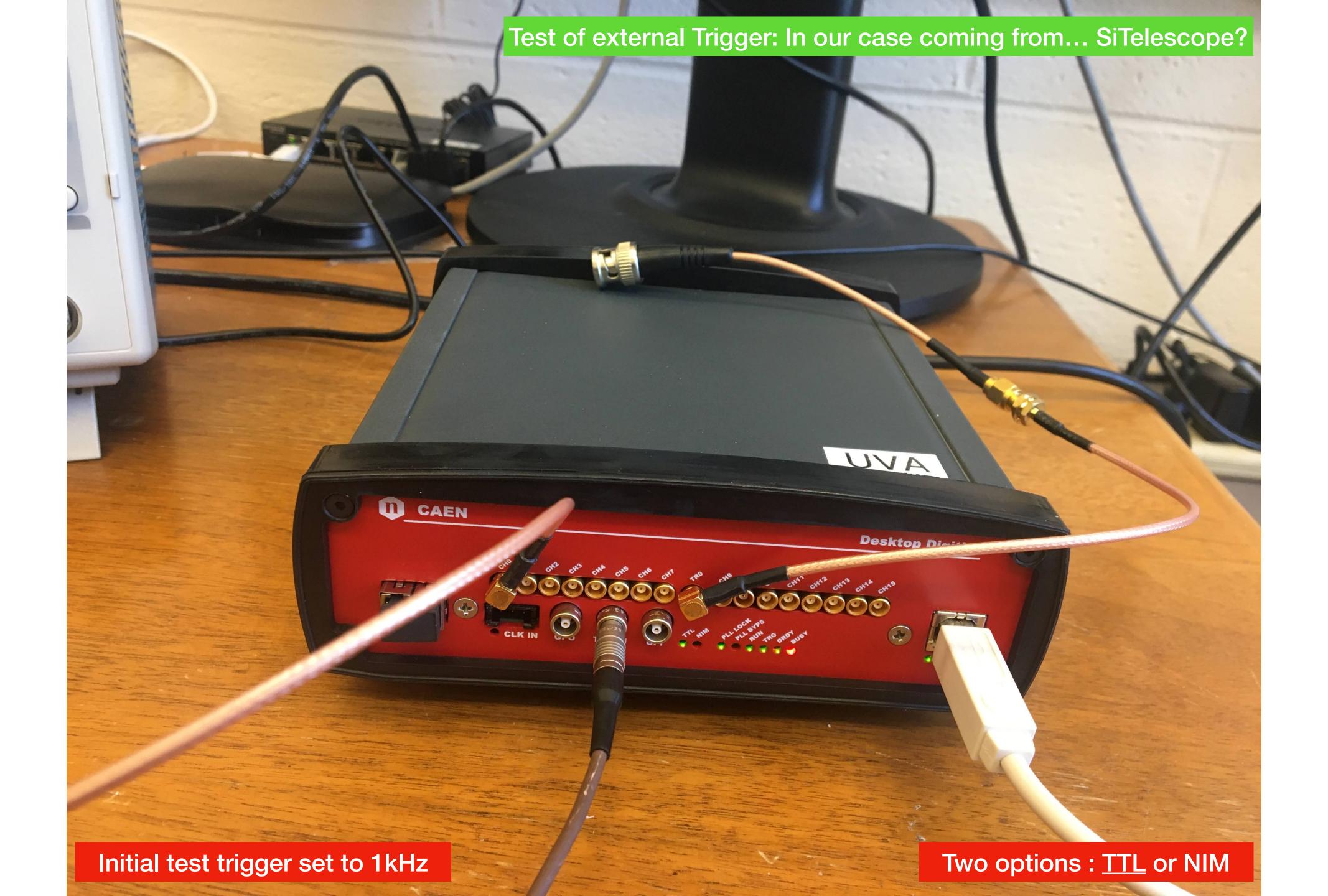
Comparison of DCR for 5e13 SiPMs before and after annealing

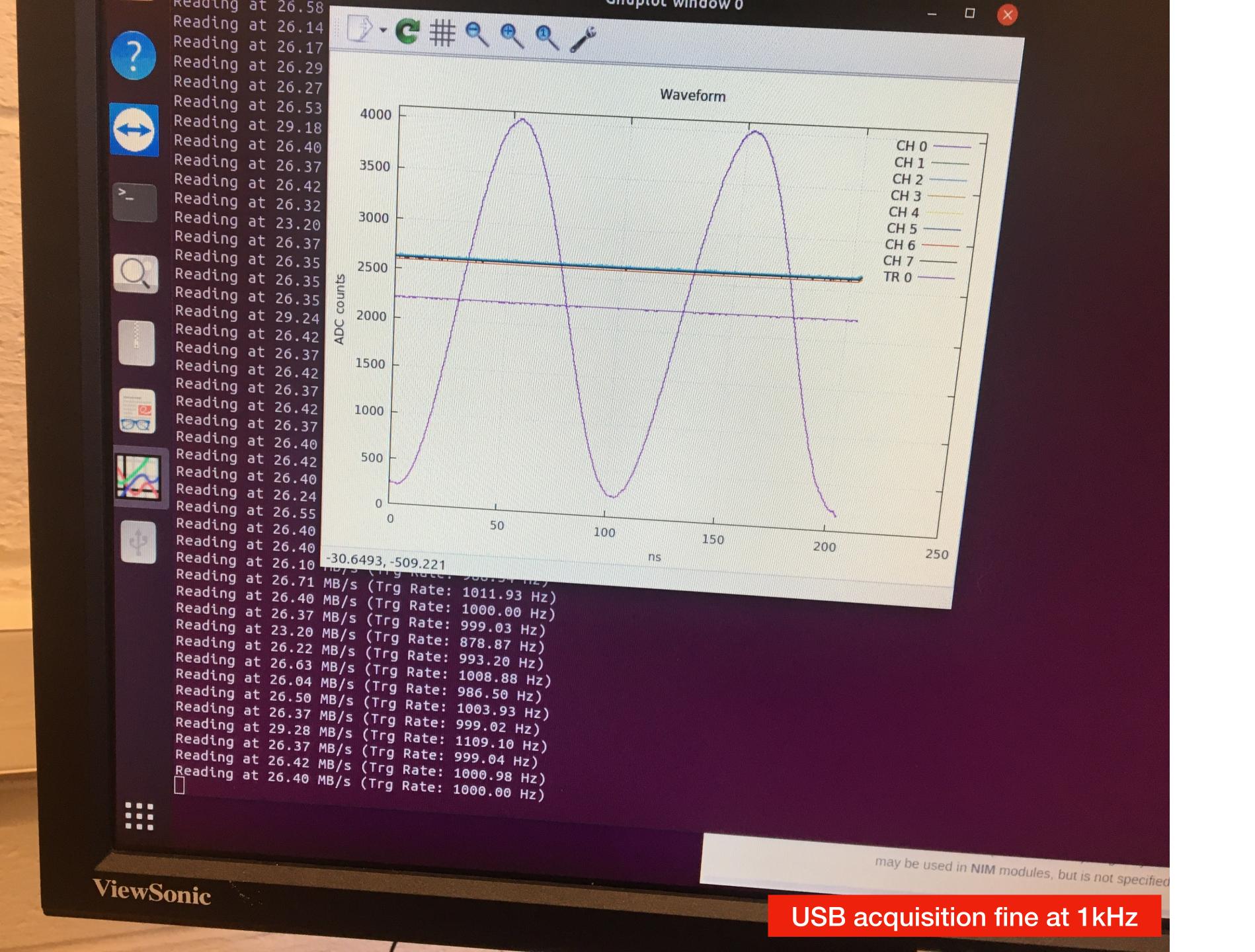


After leakage current correction, all IV curves were scaled to the same gain(OV) and enf(OV), measured by Youri/Marco in 2020

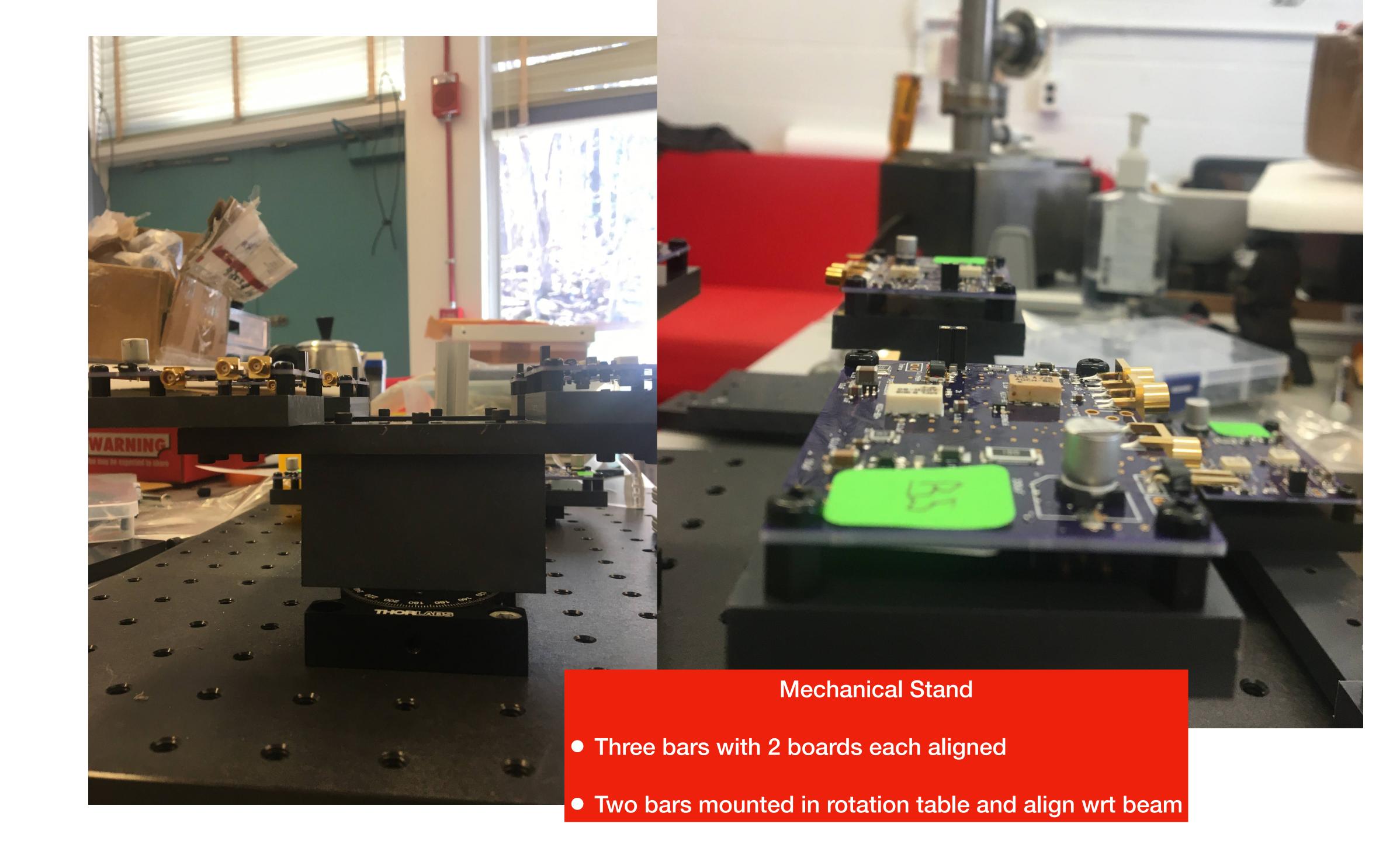
```
Reading at 26.55 MB/s (Irg Rate: 1003.90 Hz)
Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                            Using CAEN's tool wavedump
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Plot group set to 0
Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
Reading at 26.58 MB/s (Trg Rate: 1006.89 Hz)
Reading at 26.61 MB/s (Trg Rate: 1007.88 Hz)
                                                                                                                         Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
                                                                                  Gnuplot window 0
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 27.00 MB/s (Trg Rate: 1023.00 Hz)
                                                     Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                         Waveform
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
                                                       4000
                                                                                                                       CH 0
Reading at 26.98 MB/s (Trg Rate: 1021.98 Hz)
                                                                                                                       CH 1
Reading at 26.76 MB/s (Trg Rate: 1013.88 Hz)
                                                                                                                       CH 2
                                                       3500
 Reading at 26.74 MB/s (Trg Rate: 1012.87 Hz)
                                                                                                                       CH 3
 Reading at 26.84 MB/s (Trg Rate: 1016.90 Hz)
                                                                                                                      CH 4
 Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                                                      CH 5
                                                       3000
 Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
                                                                                                                      CH 6
                                                                                                                      CH 7 -
 Reading at 26.82 MB/s (Trg Rate: 1015.89 Hz)
                                                                                                                      TR 0
 Reading at 26.84 MB/s (Trg Rate: 1016.90 Hz)
                                                       2500
 Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
                                                    ADC counts
 Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
  Reading at 26.68 MB/s (Trg Rate: 1010.87 Hz)
                                                       2000
  Reading at 26.40 MB/s (Trg Rate: 1000.00 Hz)
  Reading at 23.54 MB/s (Trg Rate: 891.89 Hz)
                                                       1500
  Reading at 26.19 MB/s (Trg Rate: 992.24 Hz)
  Reading at 26.37 MB/s (Trg Rate: 999.02 Hz)
  Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
                                                       1000
  Reading at 26.92 MB/s (Trg Rate: 1019.94 Hz)
  Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
  Reading at 26.68 MB/s (Trg Rate: 1010.87 Hz)
                                                        500
  Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
  Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
  Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
  Reading at 26.76 MB/s (Trg Rate: 1013.88 Hz)
                                                                       50
                                                                                    100
  Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
                                                                                                 150
                                                                                                               200
   Reading at 26.74 MB/s (Trg Rate: 1012.87 Hz)
                                                                                                                              250
                                                                                          ns
                                                    171.155, 4572.40
                                                                                                           TR0 capable to
                                                                                                          digitize up to 2V
Sonic
```



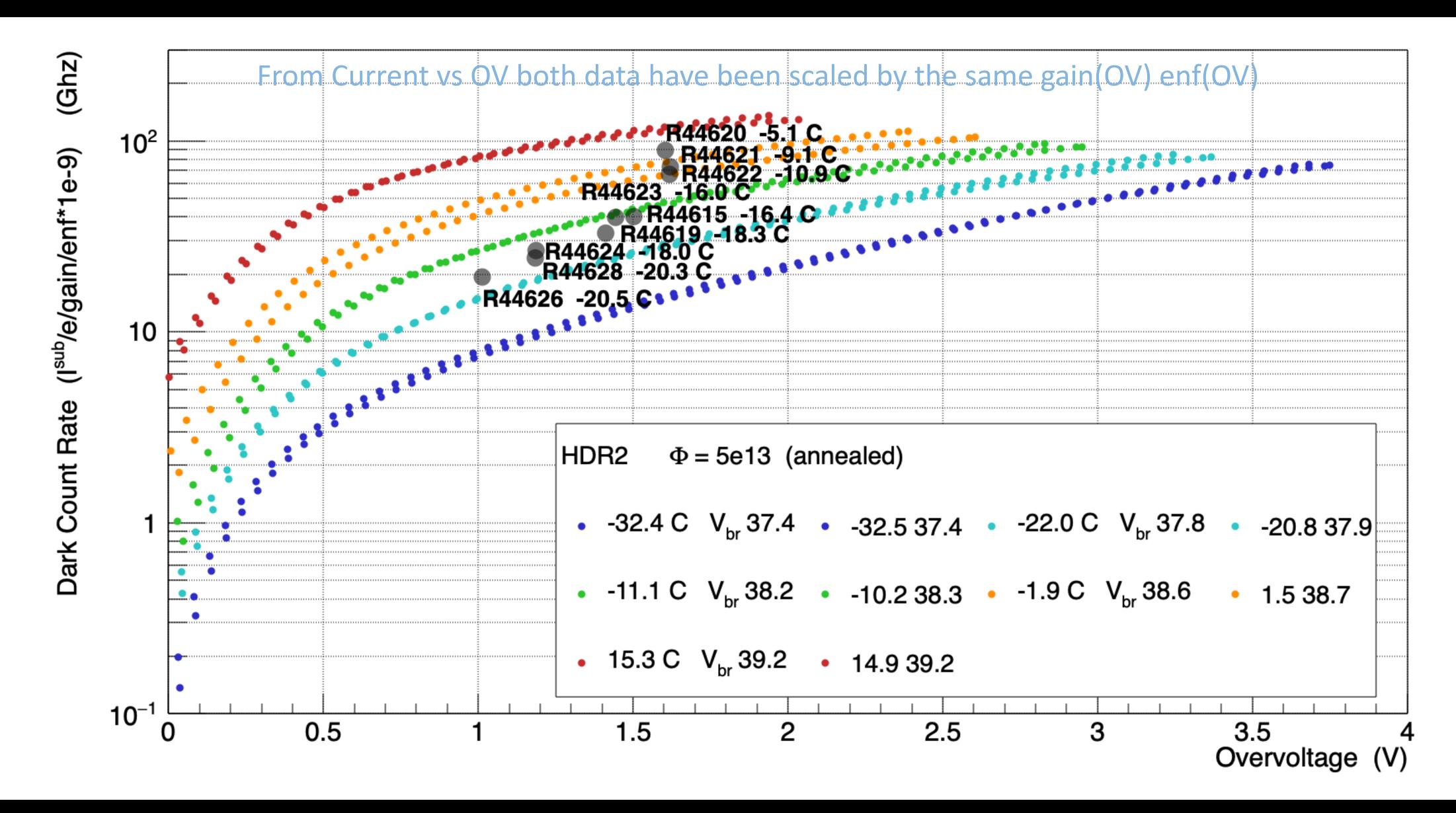




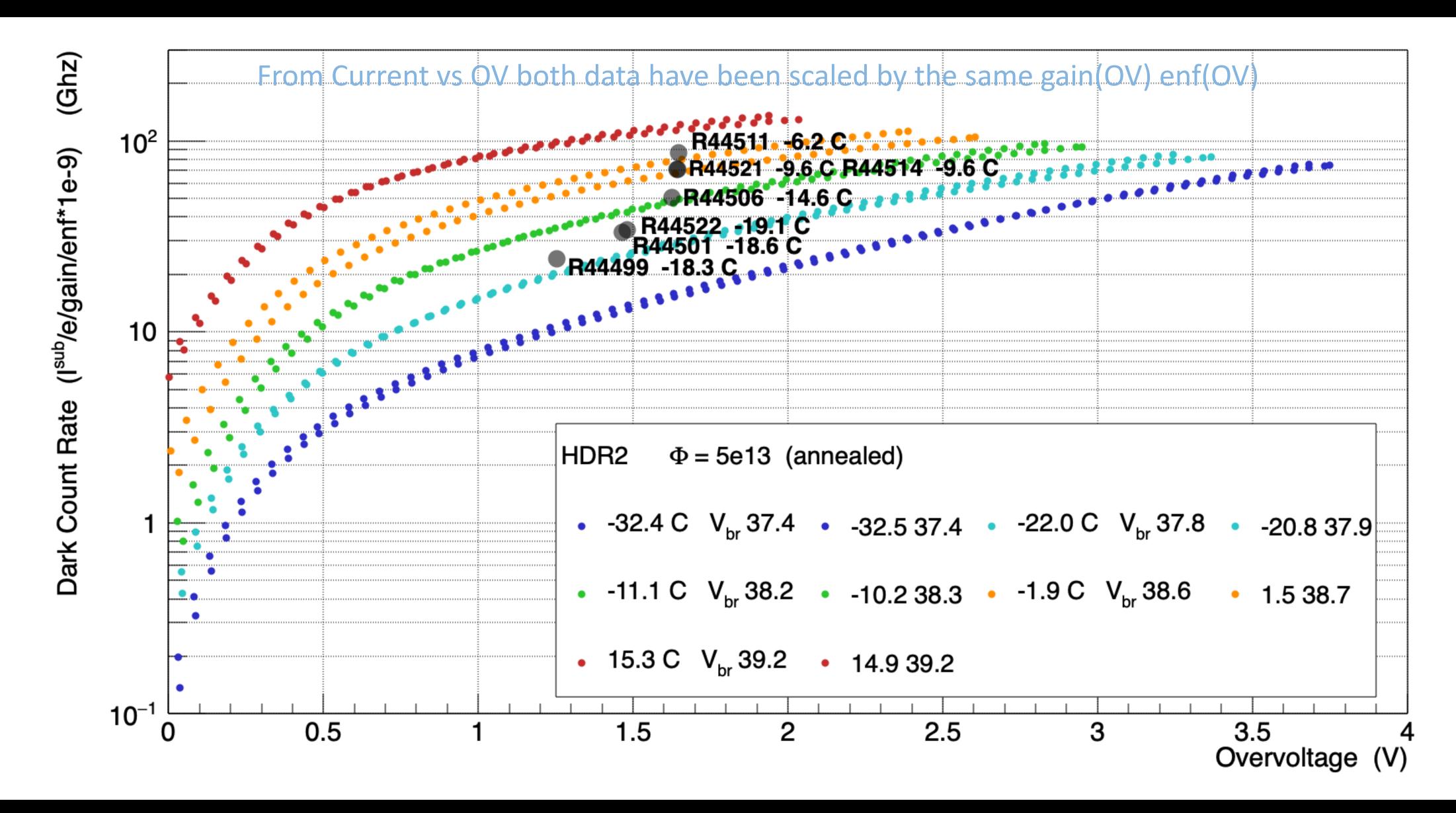
Electronic Board And Mechanical Assembly



DCR Map for bars @ 40 deg inclination.

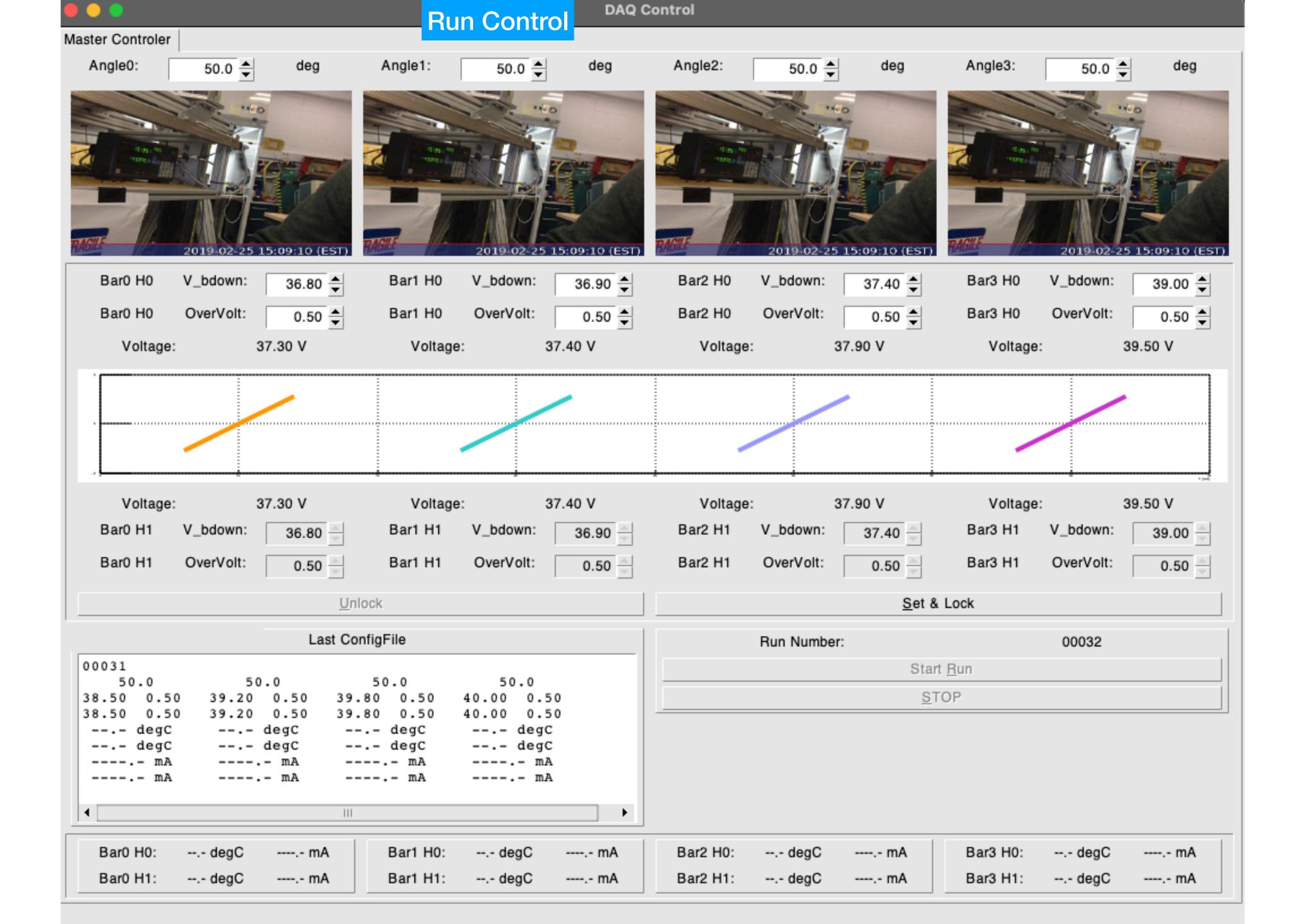


DCR Map for bars @ 0 deg inclination.





Run Control and Data Monitor

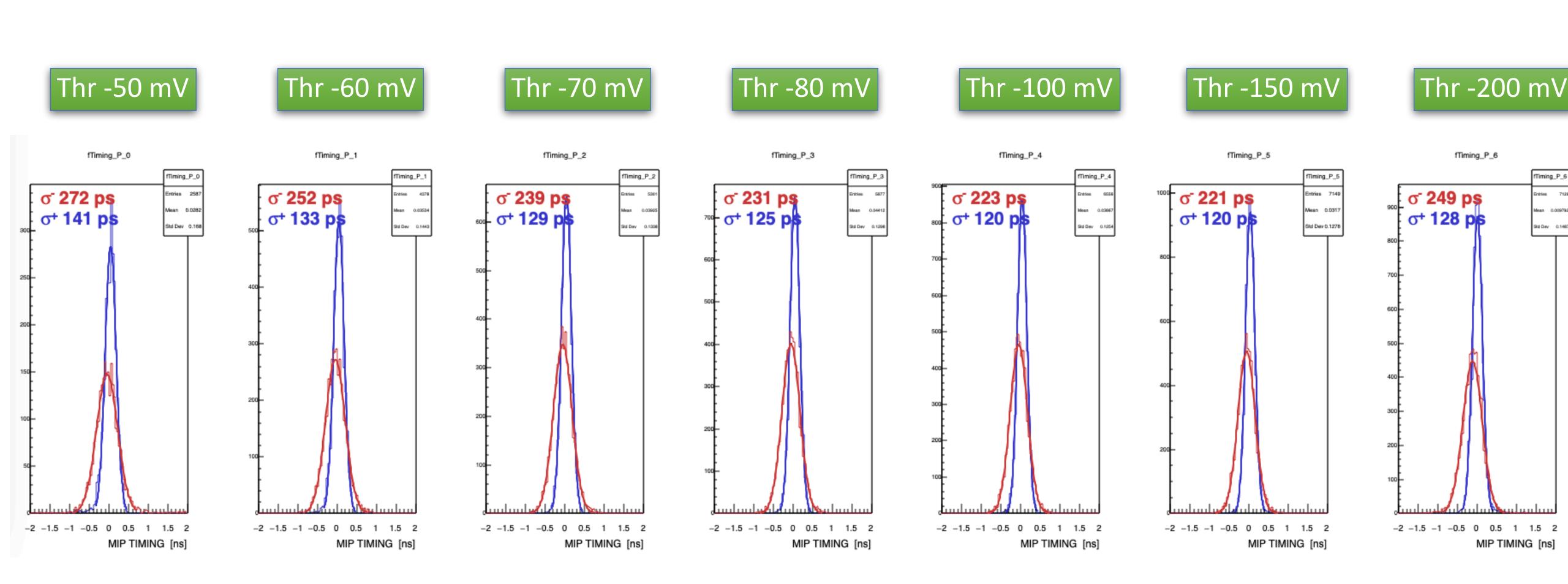


Data Quality Monitoring



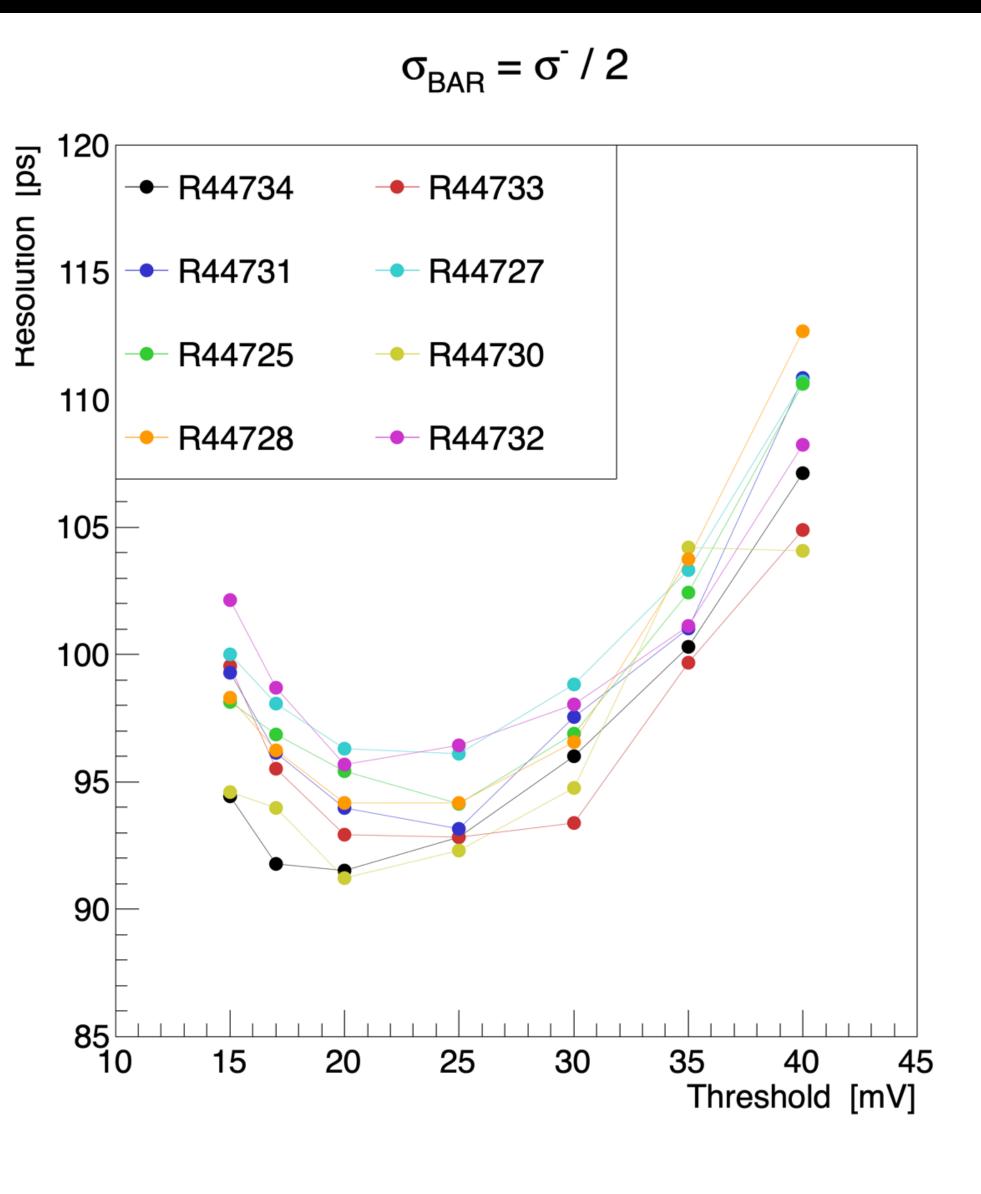
Fake MC signals

MIP Timing [ns] for different thresholds

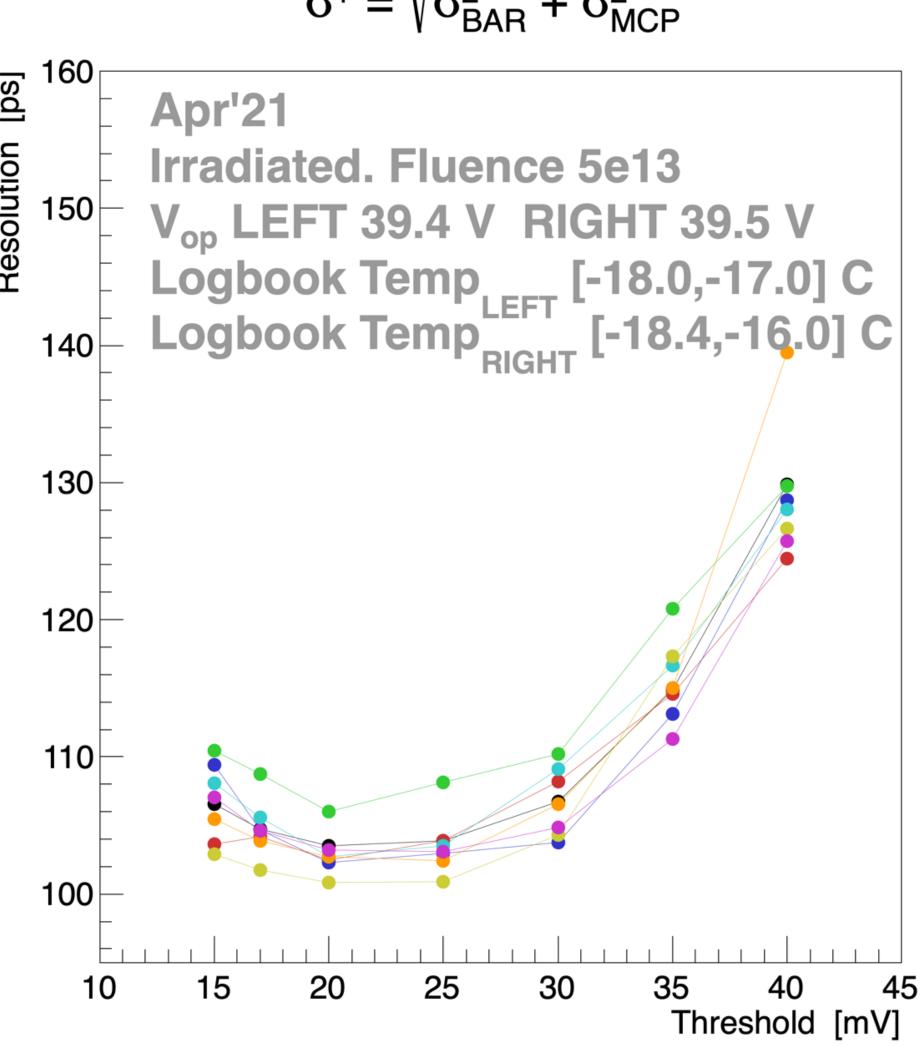


Resolutions achieved for Delay-line = 2ns

Performance of runs taken during last shift (similar conditions)



$$\sigma^{+} = \sqrt{\sigma_{\text{BAR}}^2 + \sigma_{\text{MCP}}^2}$$



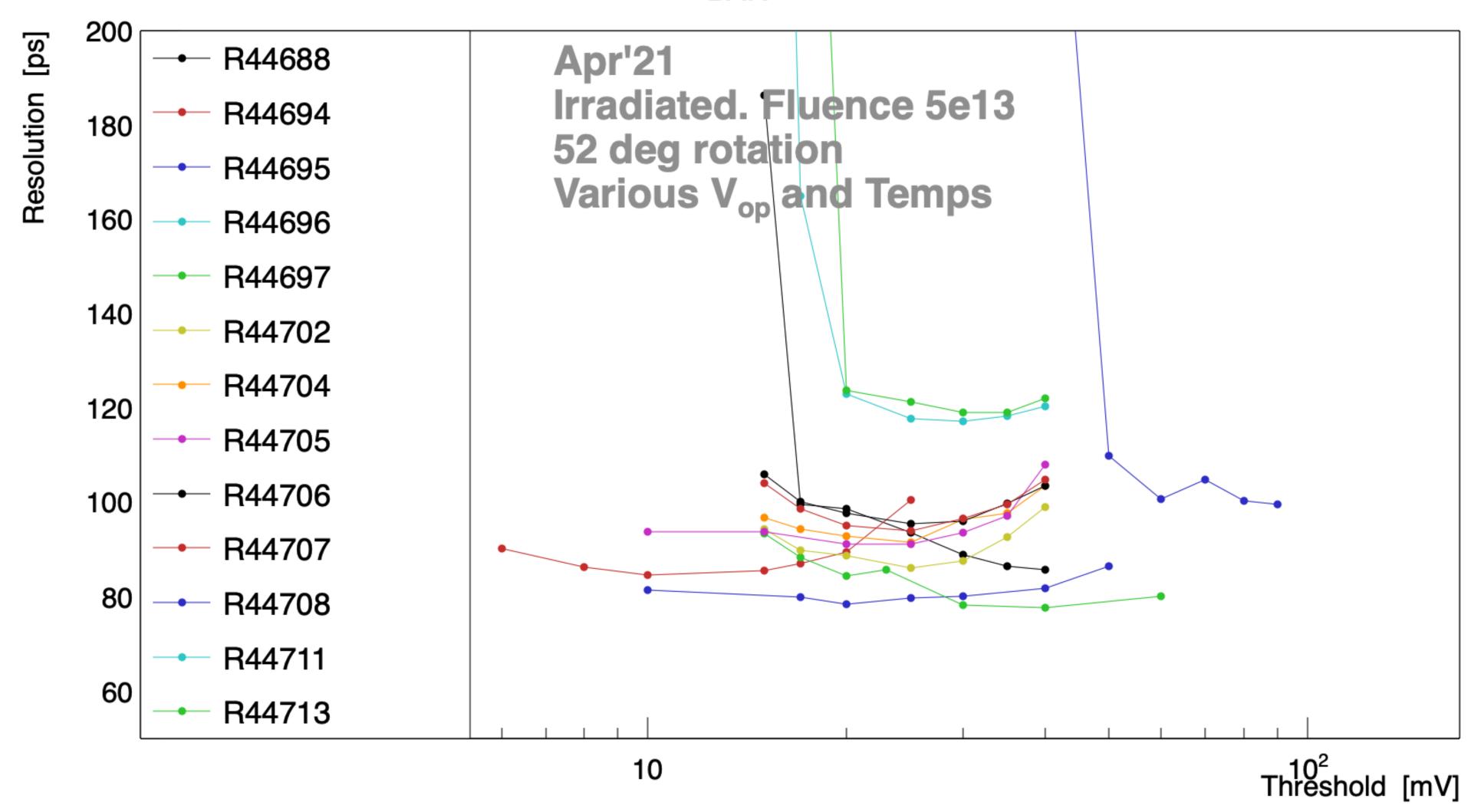
Optimal resolutions within 91 to 96 ns

Optimal thresholds within 15 and 30 mV

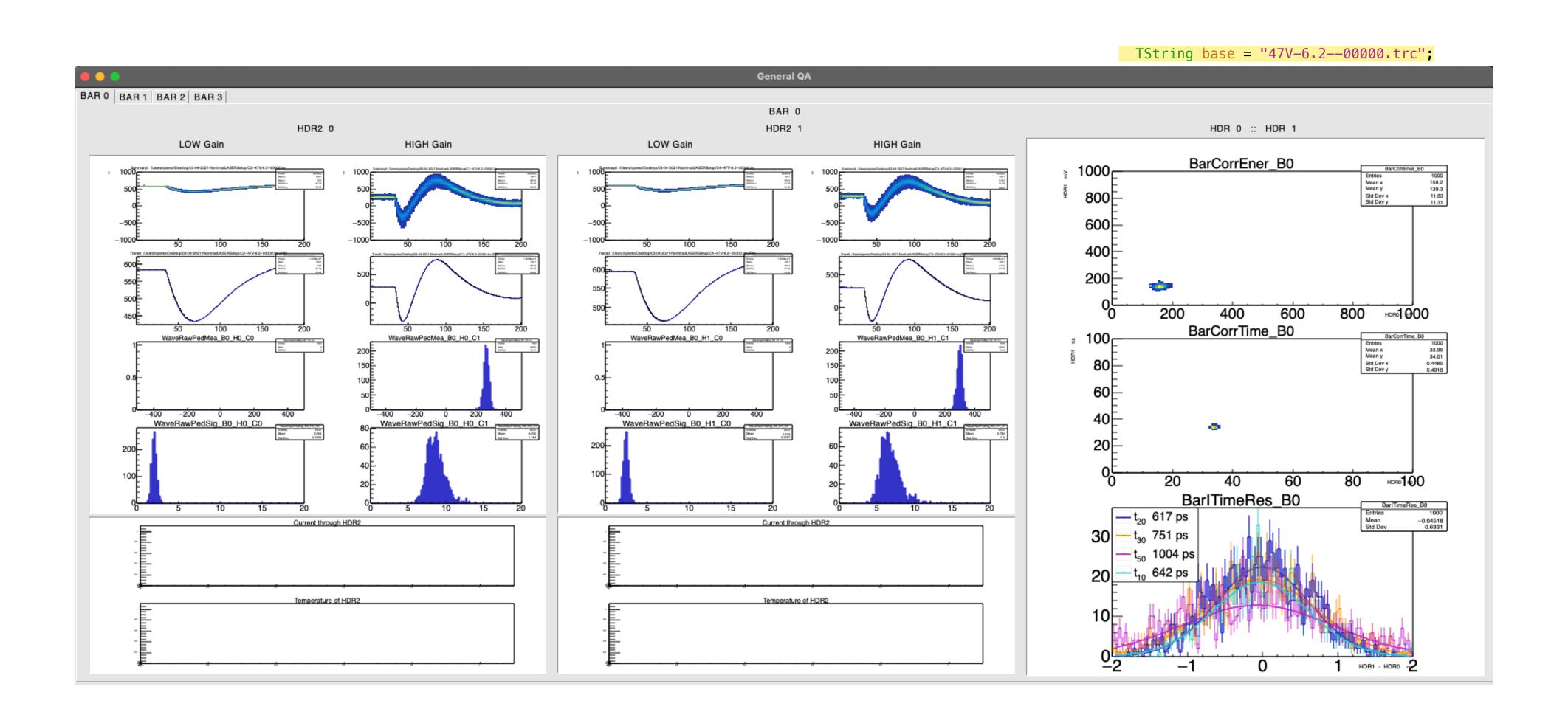
Sigma_plus suffers from the 50ps jitter from DRS

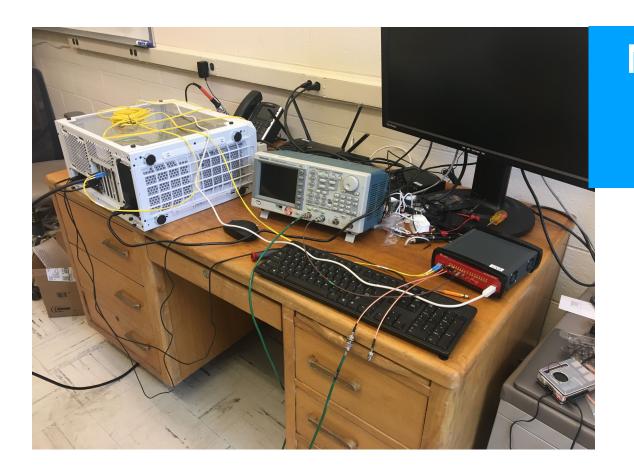
Performance of runs Wed evening (OV / Temp scan)





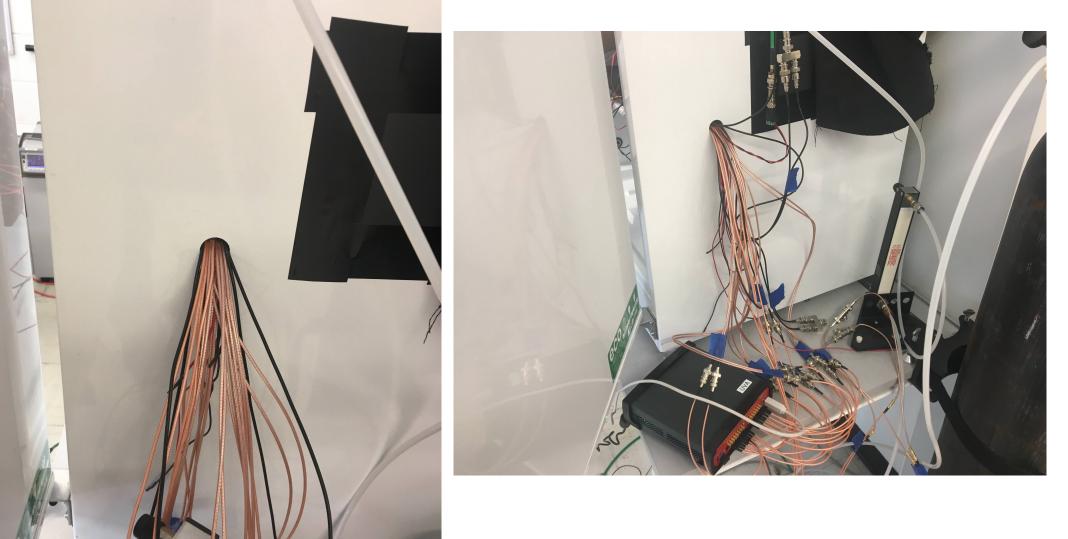
Real response of UV-laser on LYSO + HDR2 + FEElectronics





New DAQ Machine running fedora and talking to DRS at top speed. All software installed and ready. Need to work on channel mapping and few tweaks once in fnal

4-bar setup complete. Last cables arrived yesterday. All cables fit through fridge's hole







All channels show normal waveforms.

Measured with DRS



HDR2 Annealing

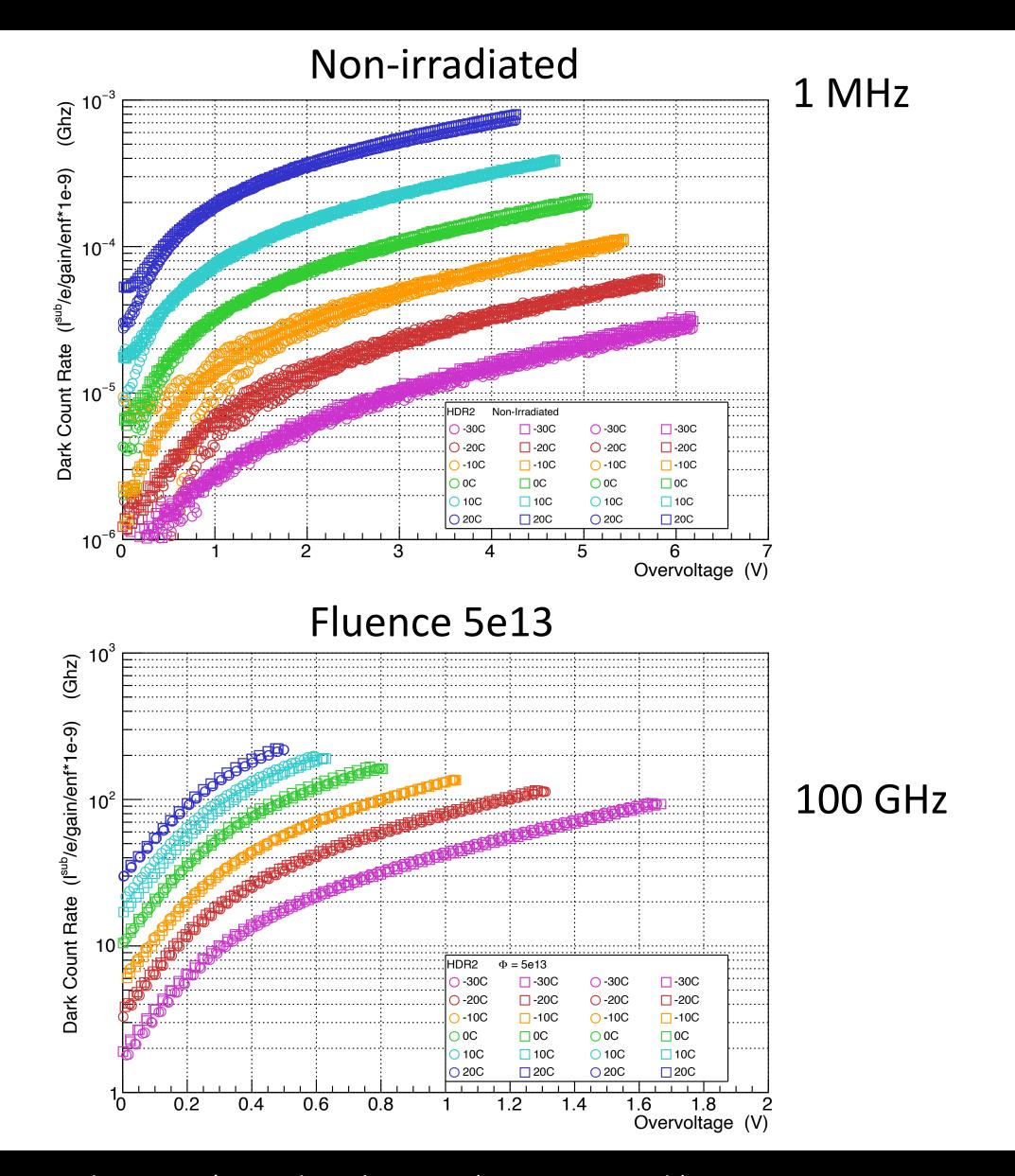
Notes on the annealing procedure taken for most irradiated SiPMs

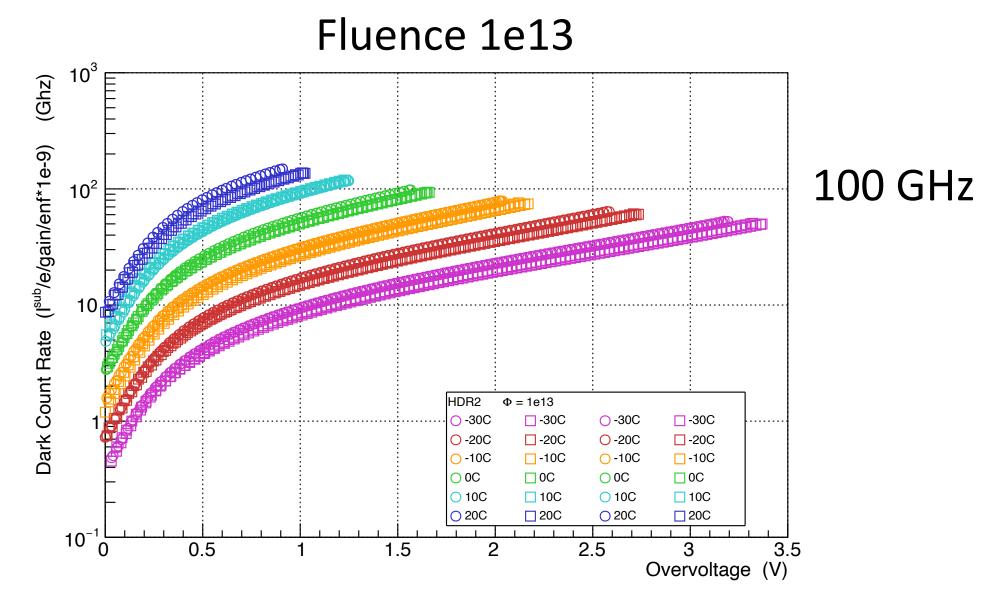
T. Anderson, B. Cox, M. Joyce, A. Ledovskoy, C. Pérez Lara, S. White

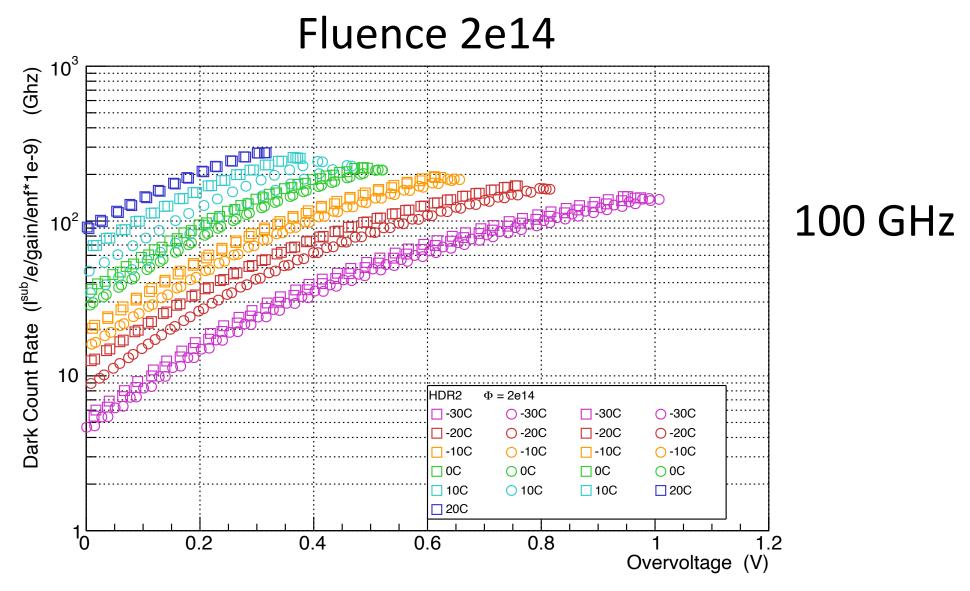
Big thanks to: M.Lucchini, A. Benaglia, A. Heering, I. Musienko

Context

DCR HDR2 measured on Oct 2020







Meeting March 18th 2021

Attended by people listed in first slide. Minutes:

Hi,

just a quick recap and action items from our meeting. Please correct mistakes:

- 1) the goal of the annealing is to achieve a **SiPM condition representative of the end of life BTL conditions** (including PDE and gain loss in the SiPM) under the assumption of an optimistic annealing scenario and test it on beam. Thus:
 - + the SiPM irradiated to 2e14 should be annealed to the level of 30GHz at 1.5V OV @ -25°C
 - + the SiPM irradiated to 5e13 should be annealed to have the same DCR as of the 2e14 SiPMs (thus also 30 GHz at 1.5V OV @ -25°C)
 - it will be possible to span higher DCR levels by raising the environmental temperature in the test beam box
- to achieve the desired annealing of about a factor 10 a high temperature annealing is required (Sasha working on the exact numbers, T and time)
- 2) As annealing to temperatures higher than 85°C (for relatively long time) may imply some risk for the SiPM performance (anomalous dark current behavior observed by Yuri or epoxy aging) it is agreed to start ASAP by annealing the samples at 85°C and monitor every ~2 days the DCR level (and if possible the response to a calibrated LED source).
- 3) In the meantime Arjan will inquire with HPK if they consider safe to anneal at higher temperatures and for how long. Marco will also try to make some high temperature annealing on silicone resin samples from HPK to see if any degradation in optical transparency occurs.
- 4) In about one week from now, and depending on the outcome of 3), we could consider to further raise the annealing temperature if this is deemed necessary to achieve the DCR level desired for the test beam.

cheers,

Marco

How long will it take to anneal?

5e13 **@1 OV**

Measured DCR for 5e13 SiPM is 43GHz at -30C.

Target DCR is 30GHz at -25C or 23.4GHz at -30C. The annealing factor is 43/23.4 = 1.84

Estimated annealing time at different temperatures:

Time
202 days 21 hours 2 min
42 days 7 hours 22 min
9 days 17 hours 42 min
2 days 10 hours 52 min
0 days 16 hours 12 min
0 days 4 hours 52 min

@1 OV 2e14

Time

The annealing factor is x4 of 5e13 or 4 * 1.84 = 7.36Estimated annealing time at different temperatures:

Temp 745 days 0 hours 12 min 234 days 7 hours 52 min 78 days 10 hours 52 min 100 27 days 19 hours 42 min ____ 10 days 9 hours 42 min 110

If we anneal at 80C we would need several months to reach such levels

> If we anneal at this temperature, what do we chose as time intervals?

> > Still we need to hear from Hamamatsu if we can go to 110C

4 days 2 hours 2 min

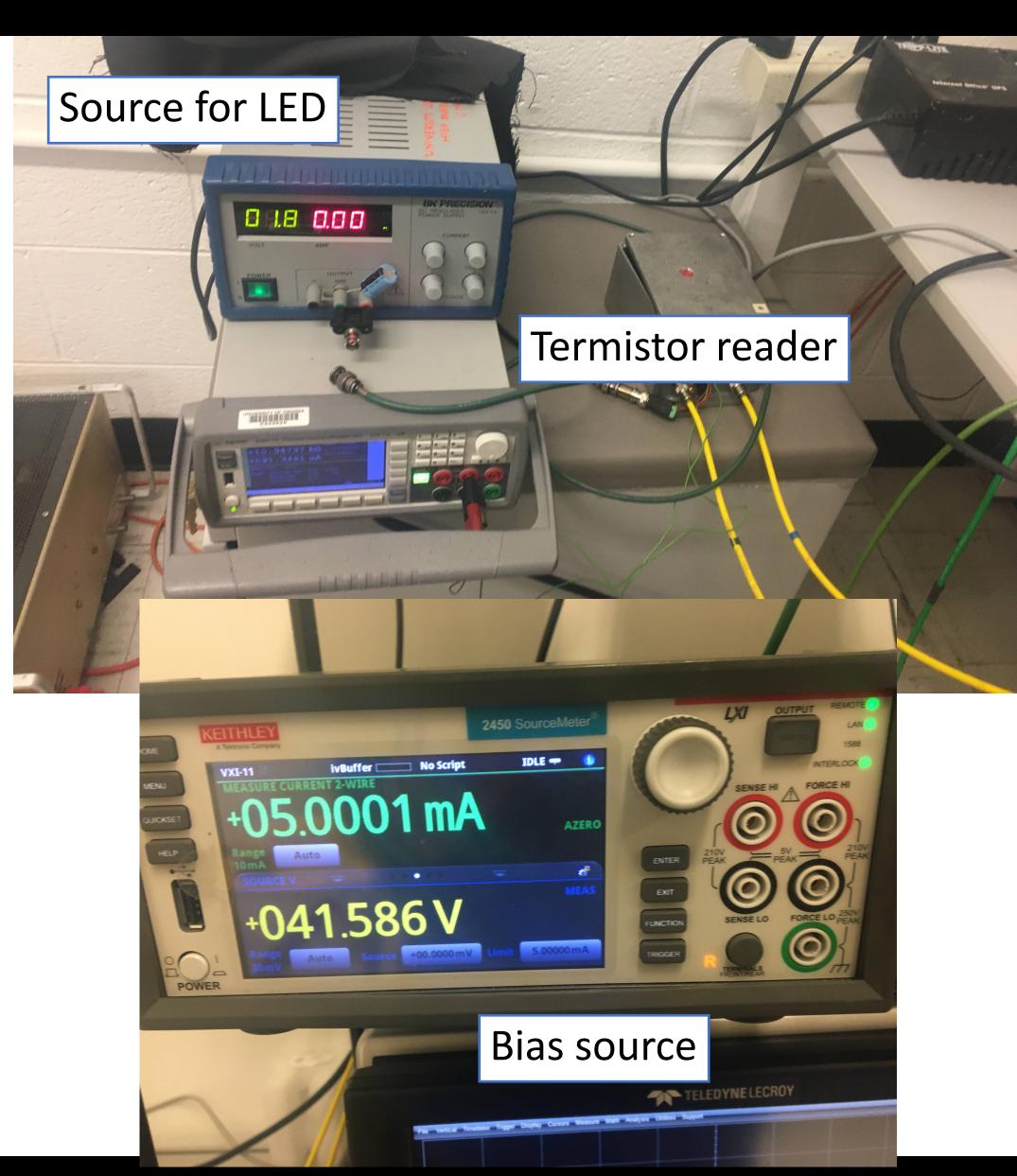
1 days 16 hours 22 min

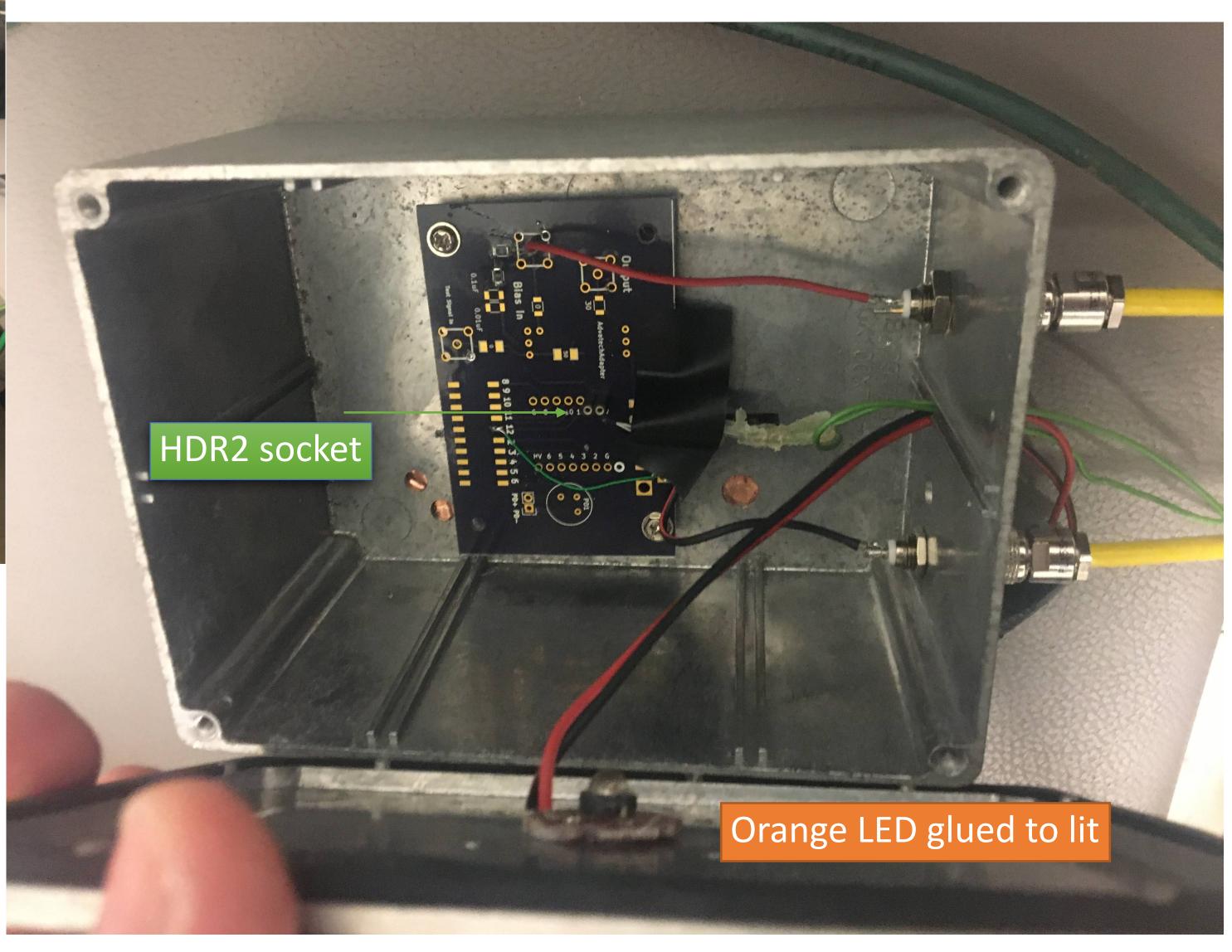
120

130

Initial Setup

IV-Setup





Apr, 15th 2021 | Carlos Pérez Lara (cperez@cern.ch) 58

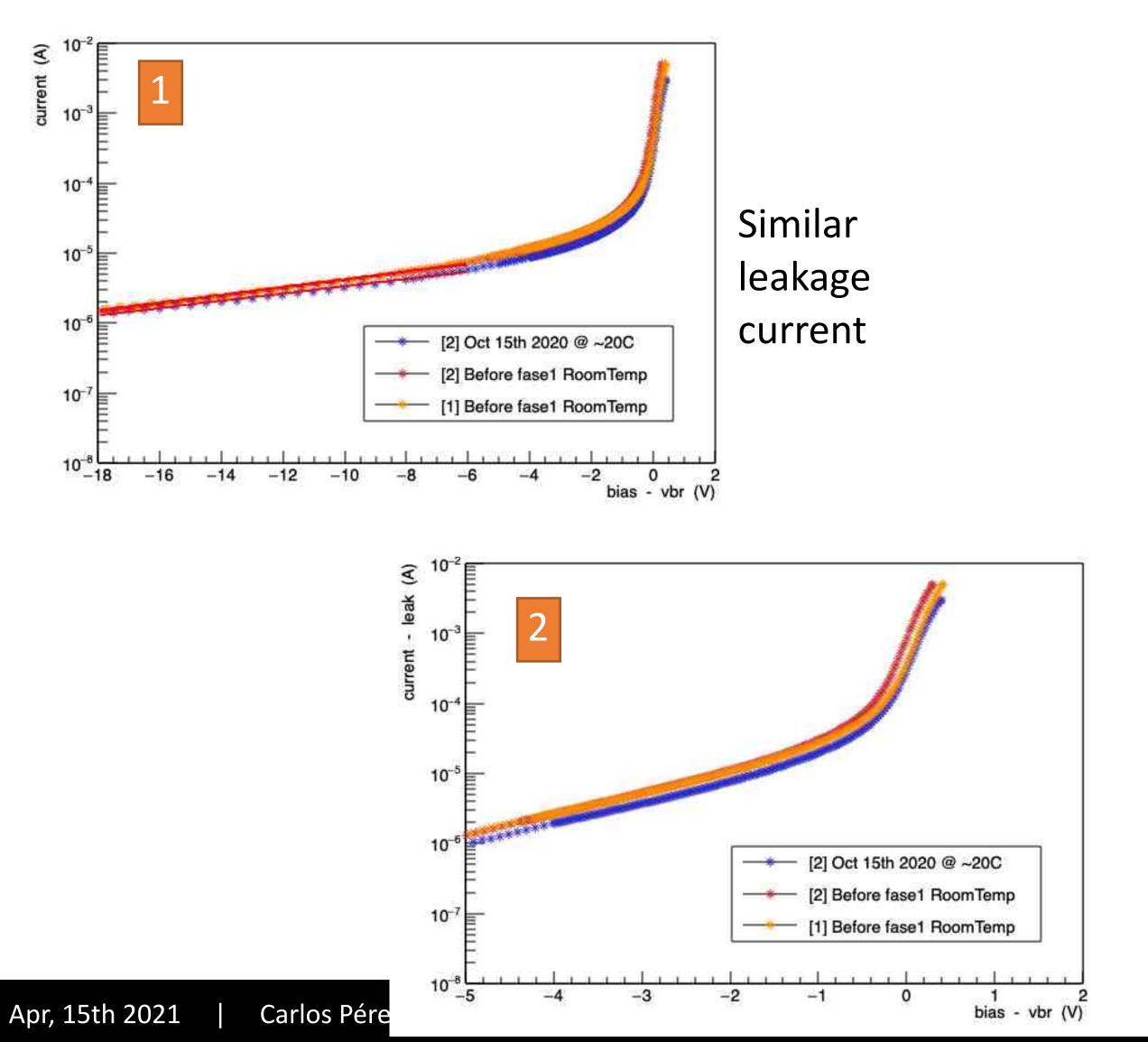
Take one

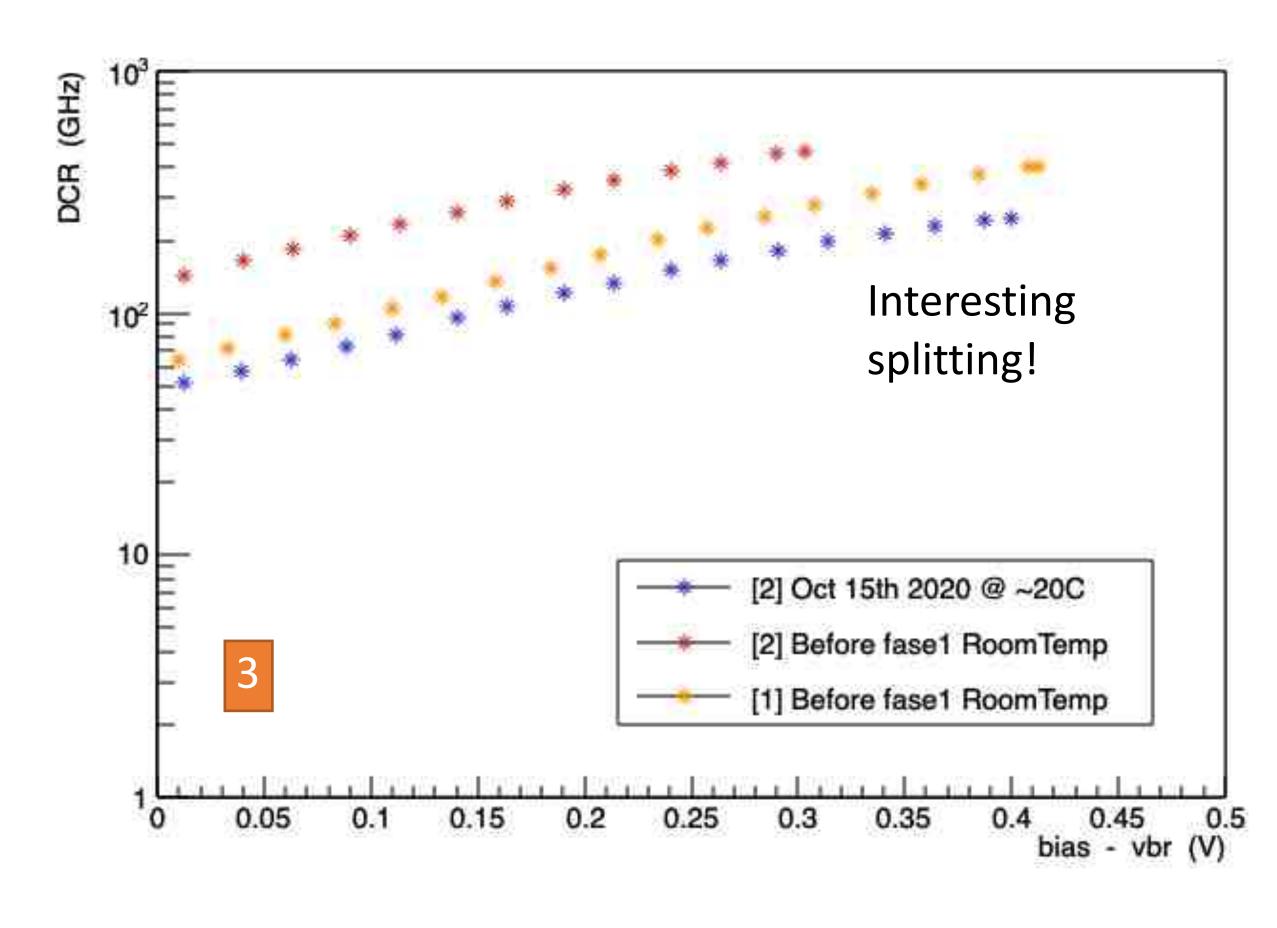
Annealing for 2 hours at 80C



Measurements before first annealing interval

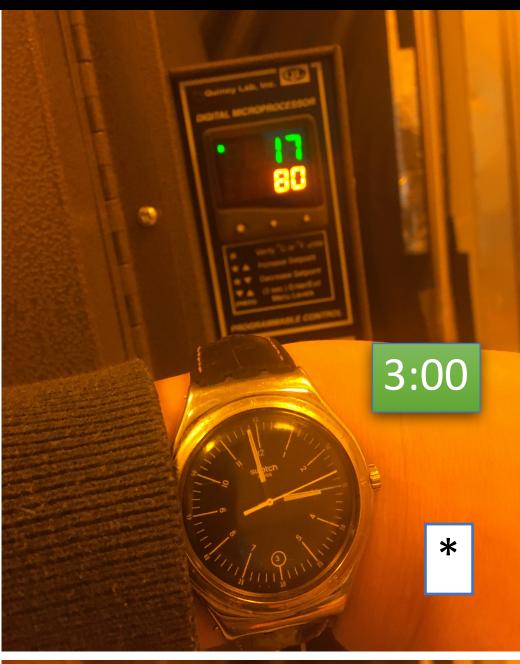
Once Vbr was determined via DARK/LED procedure, we compute DCR

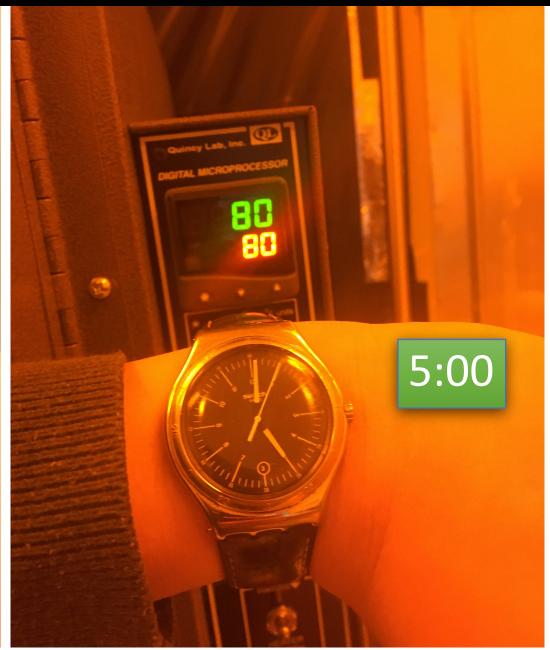


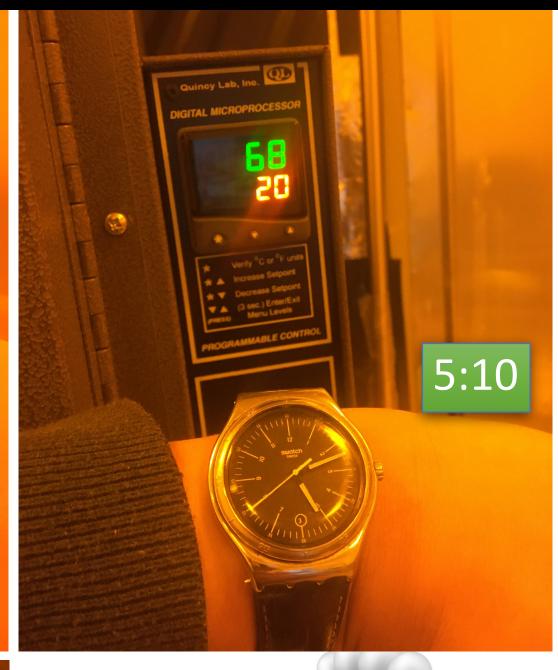


Cooking HDR2 2e14

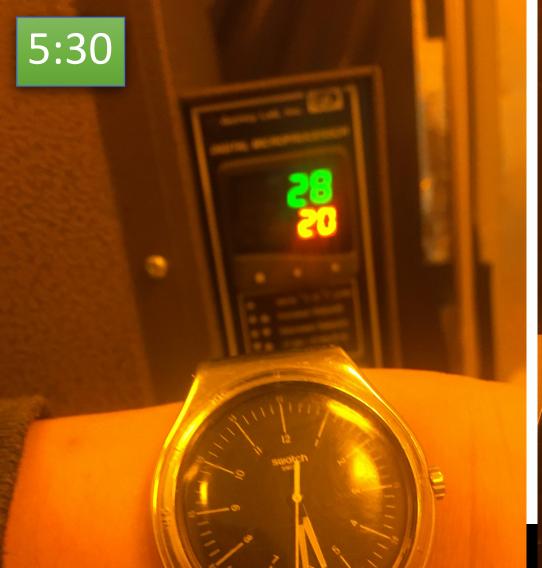


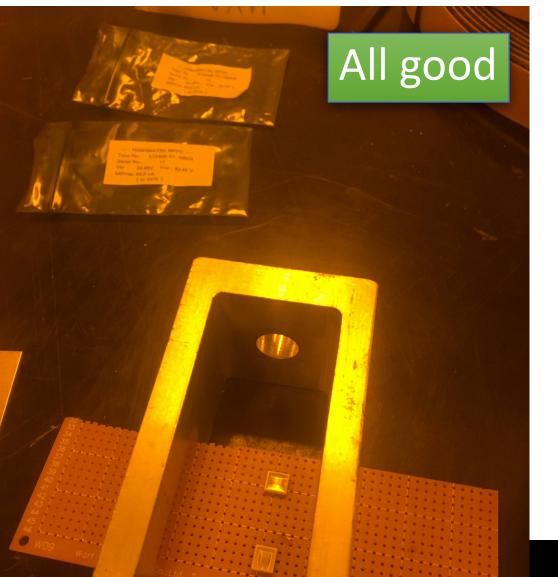












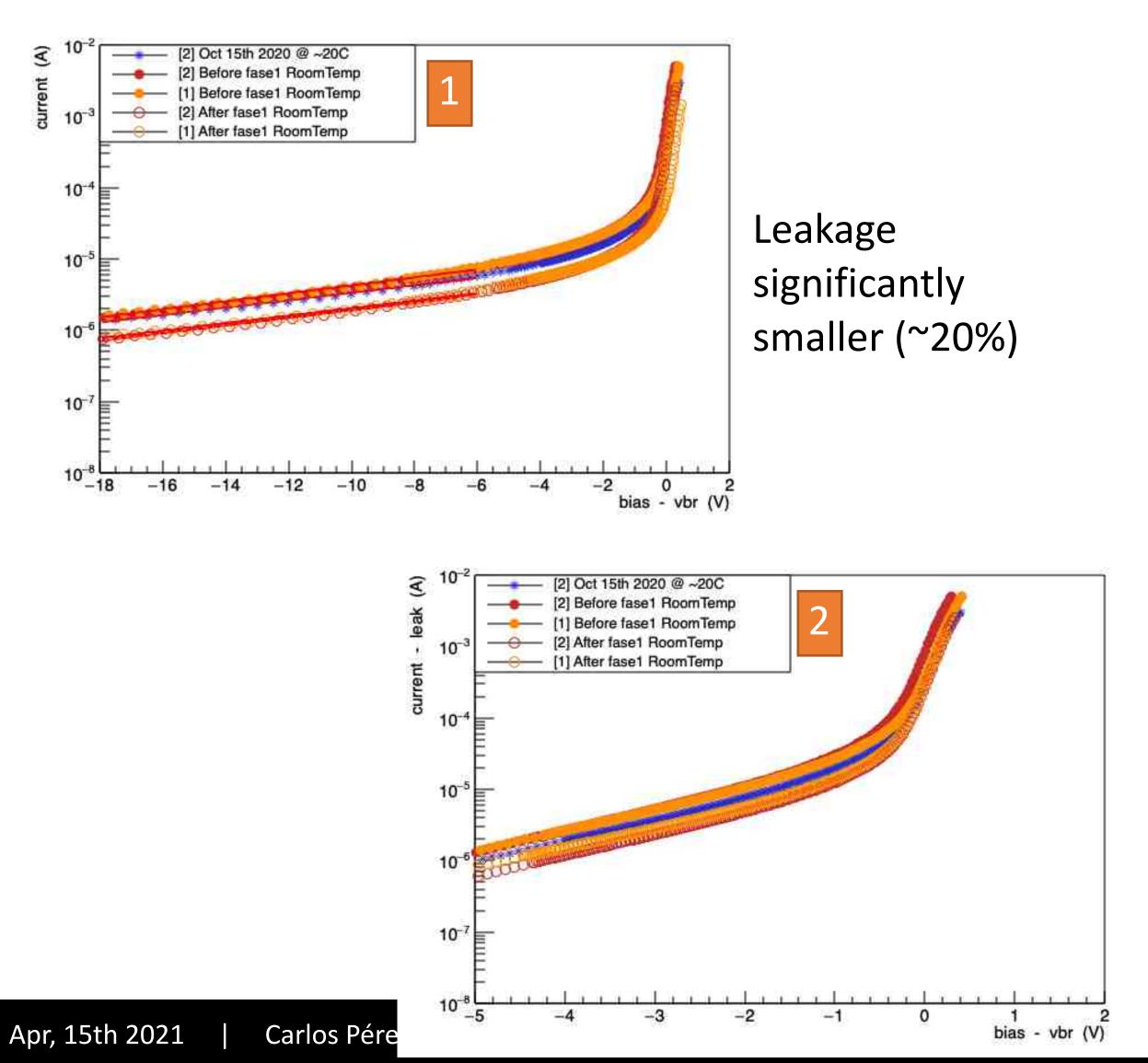


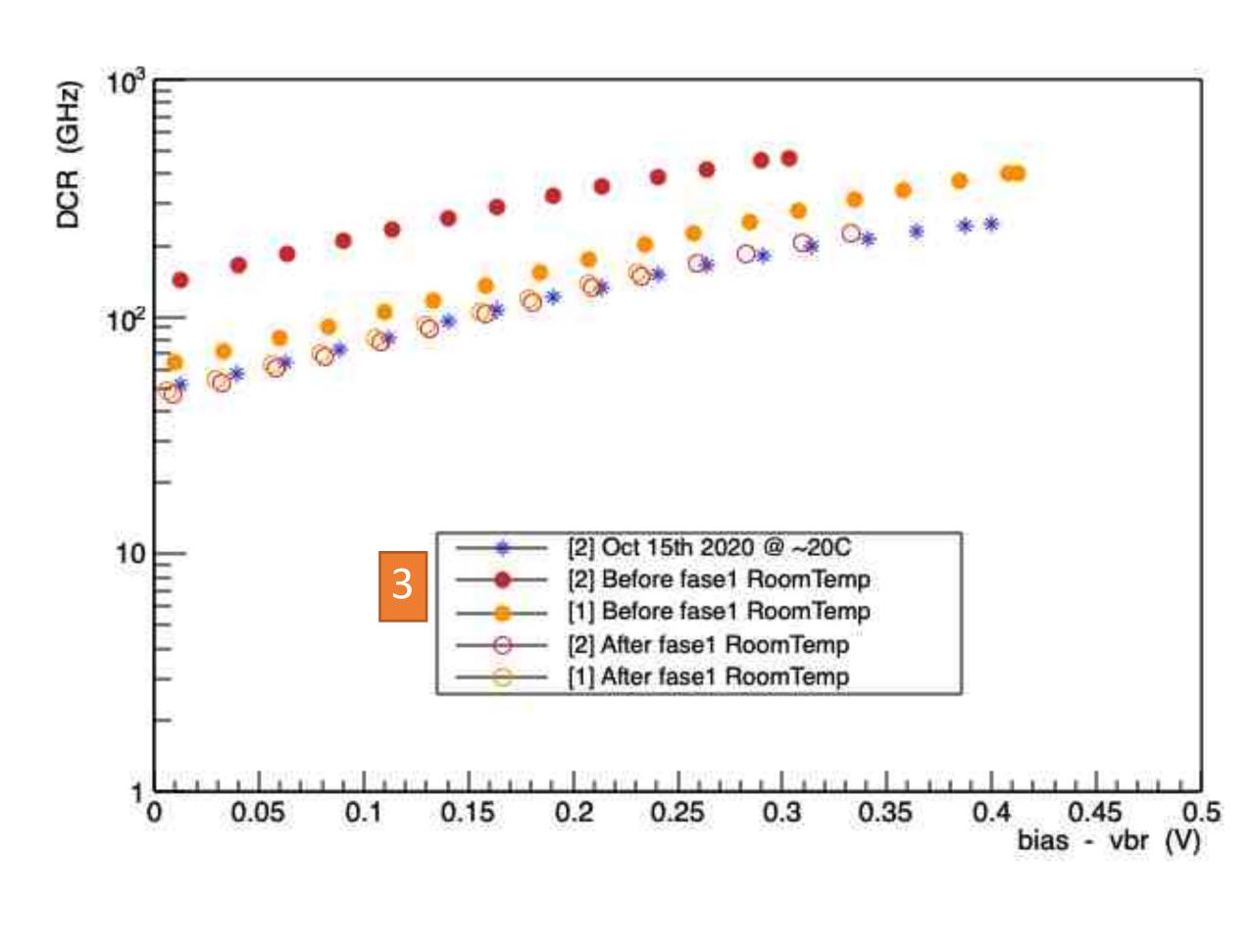
*Lost the picture, but checked that after 10 minutes we reached 80C

Apr, 15th 2020

Measurements after first annealing interval

Once Vbr was determined via DARK/LED procedure, we compute DCR



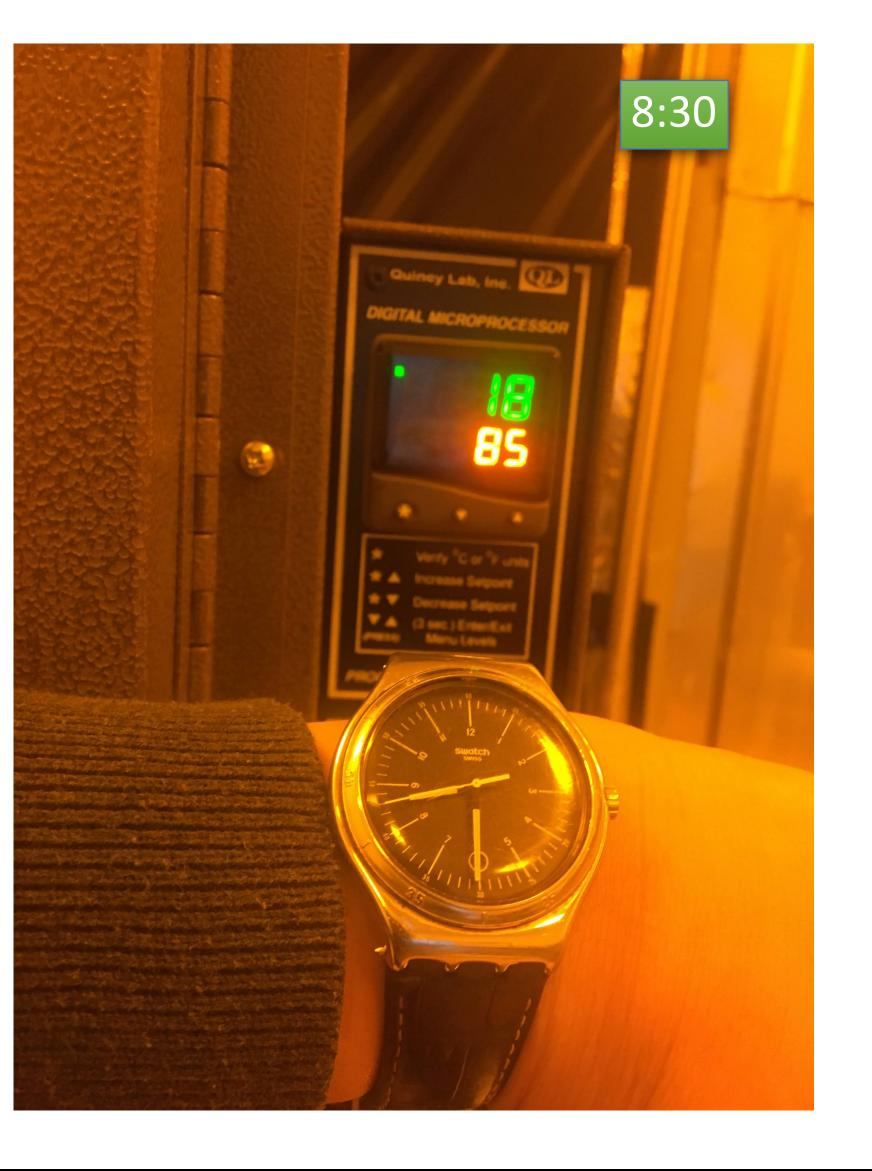


Take two

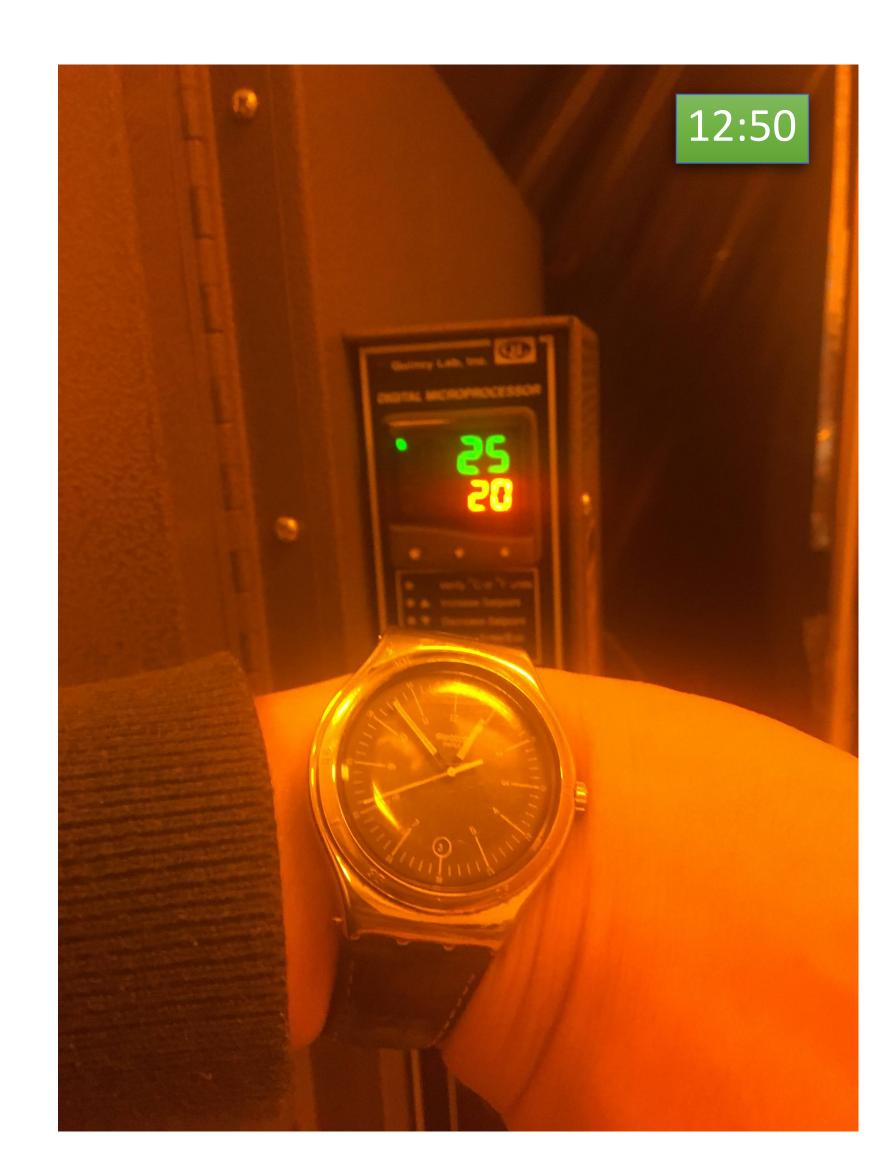
Annealing for 3.5 hours at 85C



Cooking HDR2 2e14



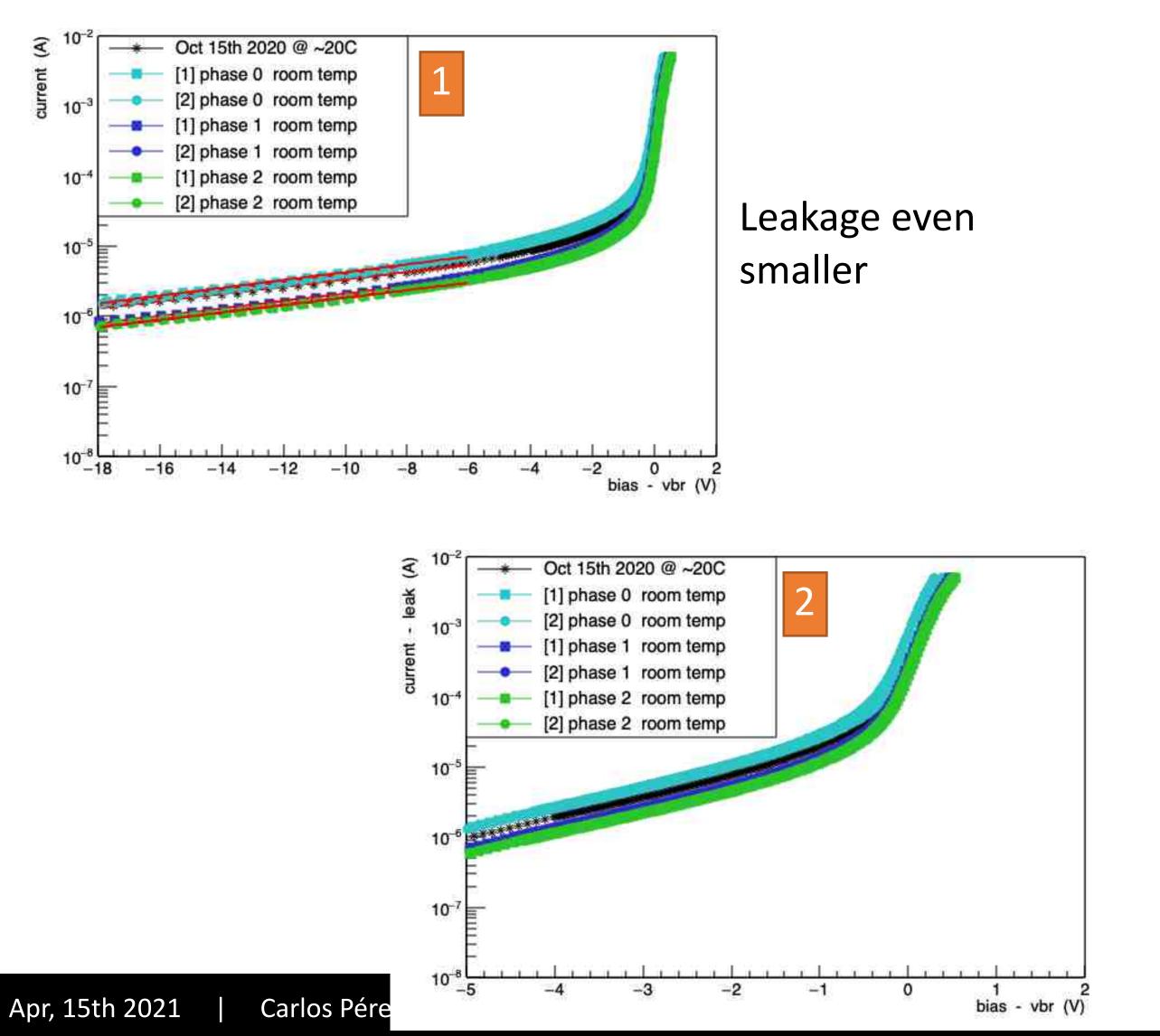


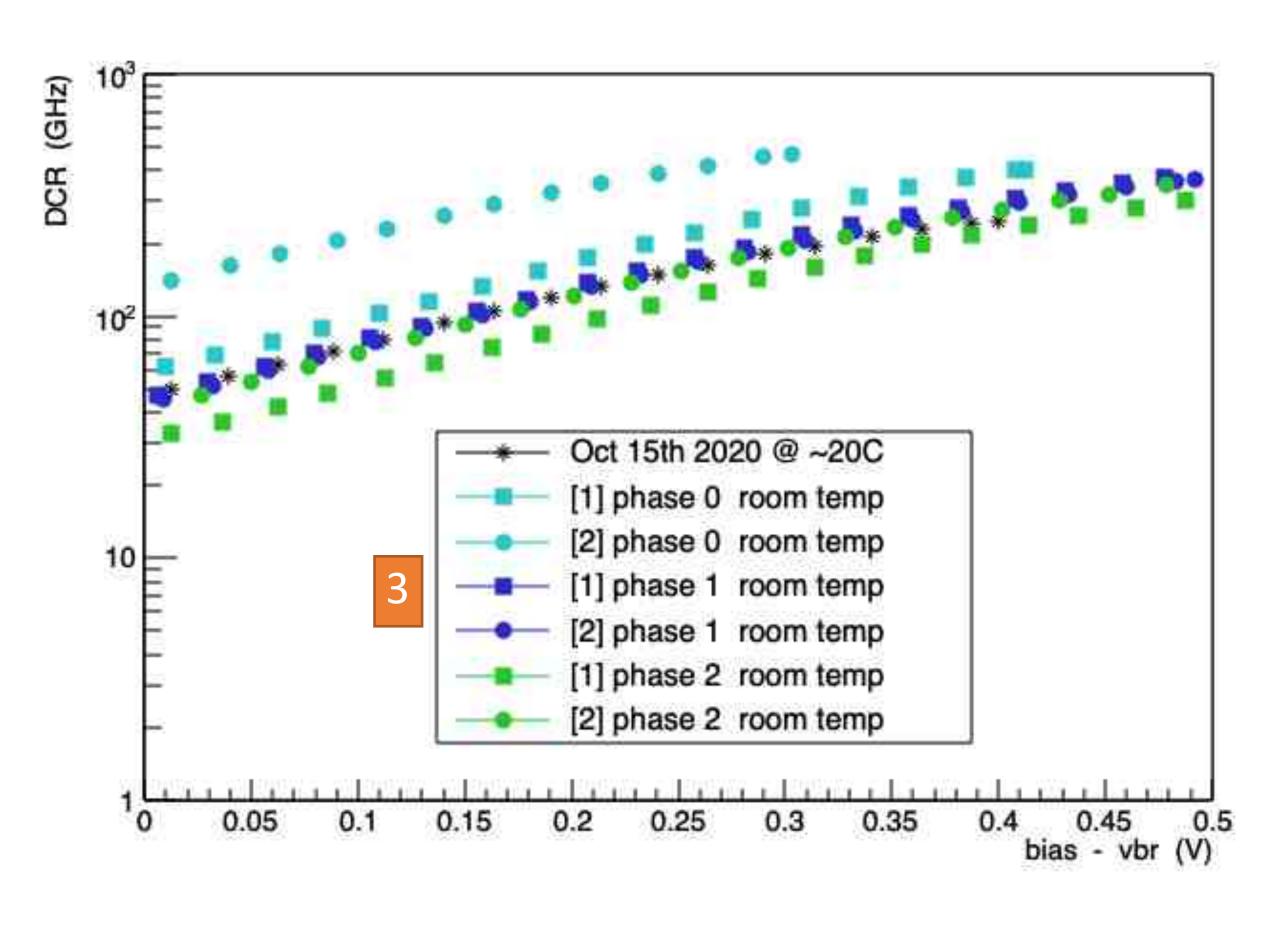


Apr, 15th 2020 | Carlos Pérez Lara (cperez@cern.ch)

Measurements after first annealing interval

Once Vbr was determined via DARK/LED procedure, we compute DCR





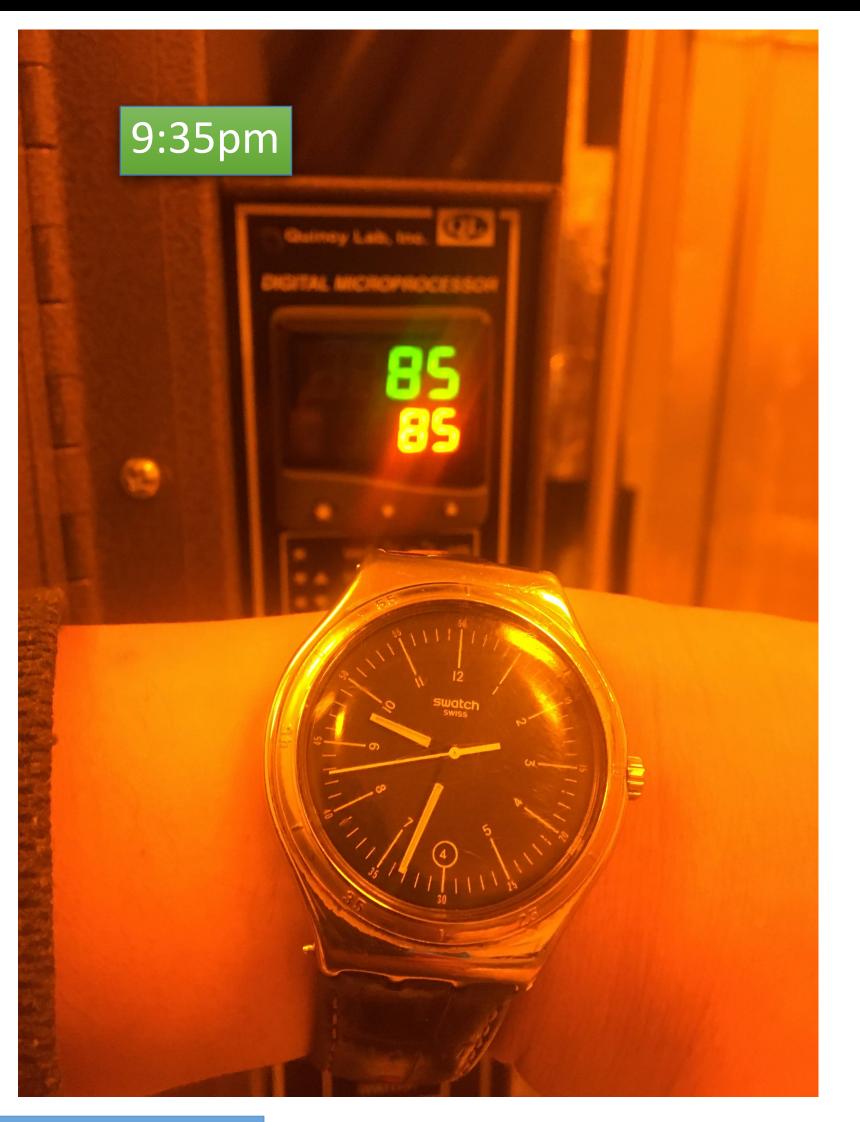
PRODUCTION TAKE SCENE Annealing 3rd try HDR2 2e14 DIRECTOR CAMERA DATE

Take four

Annealing for 8.3 hours at 85C

Cooking HDR2 2e14

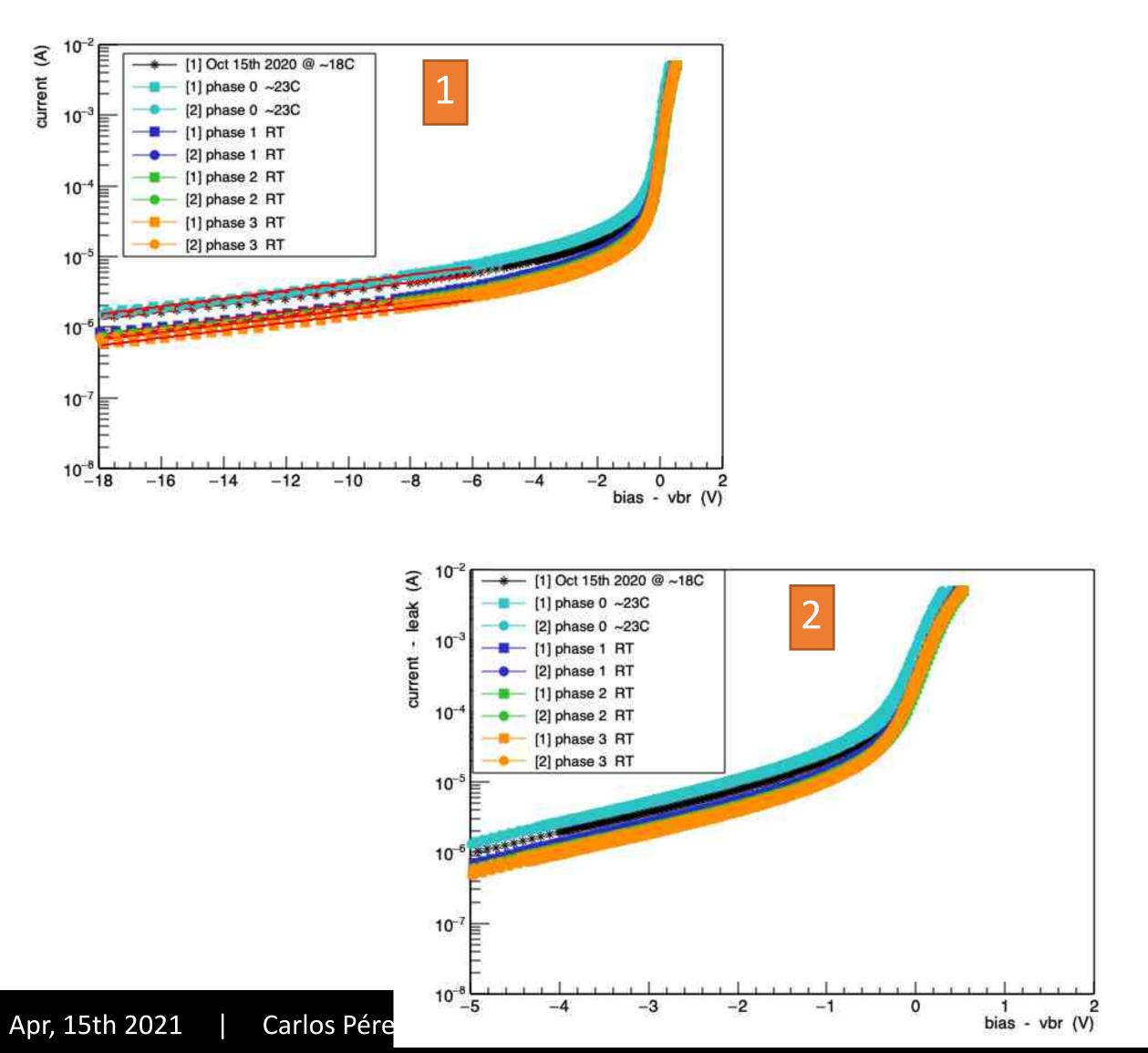


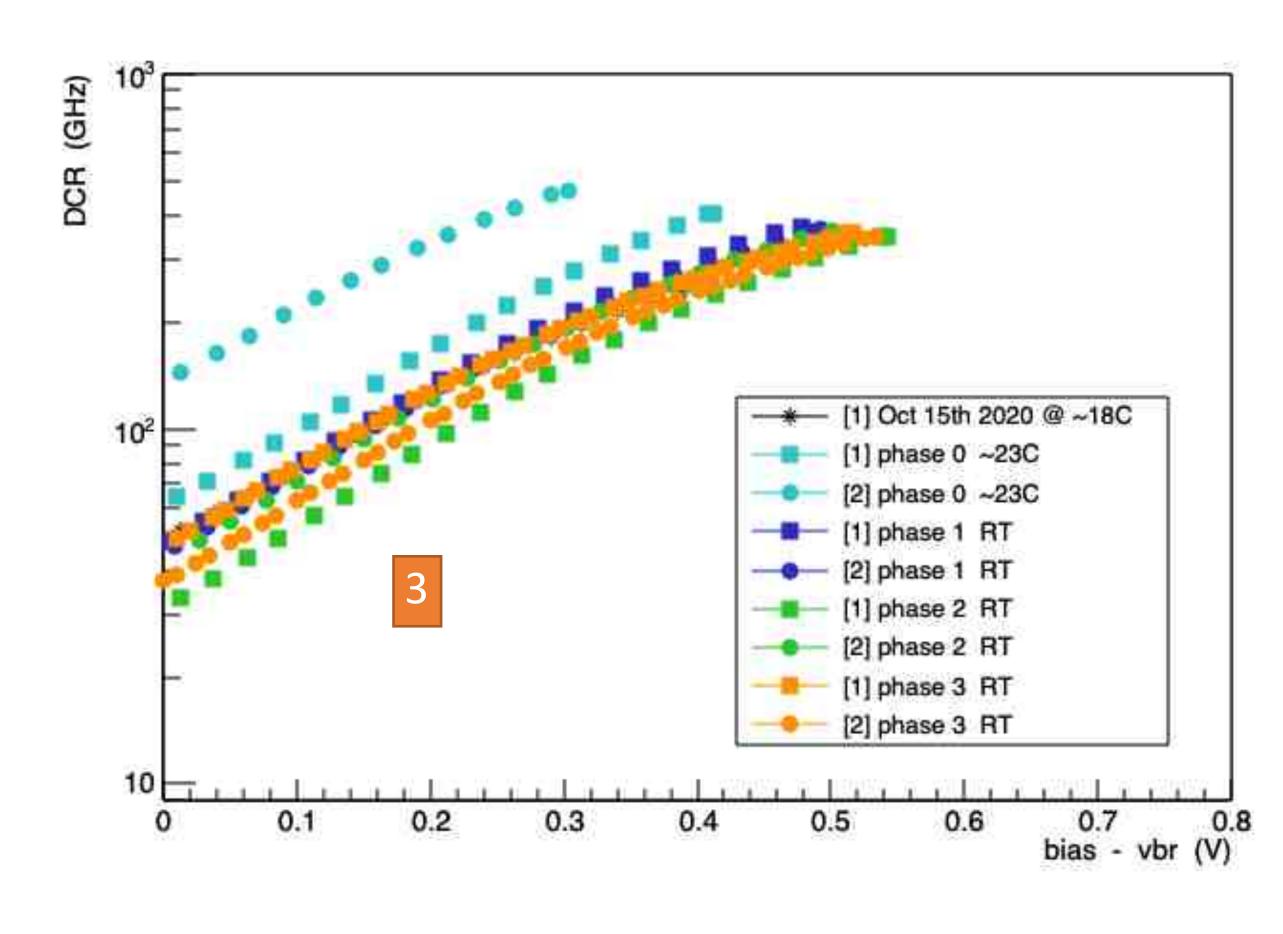


Cooking for around 8h 20m at 85C

Measurements after first annealing interval

Once Vbr was determined via DARK/LED procedure, we compute DCR



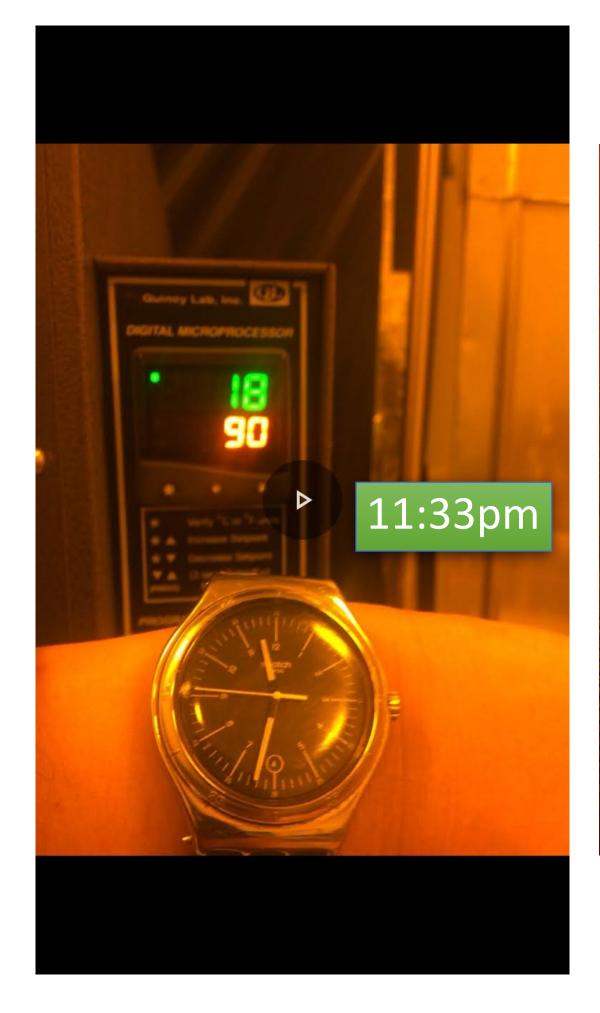


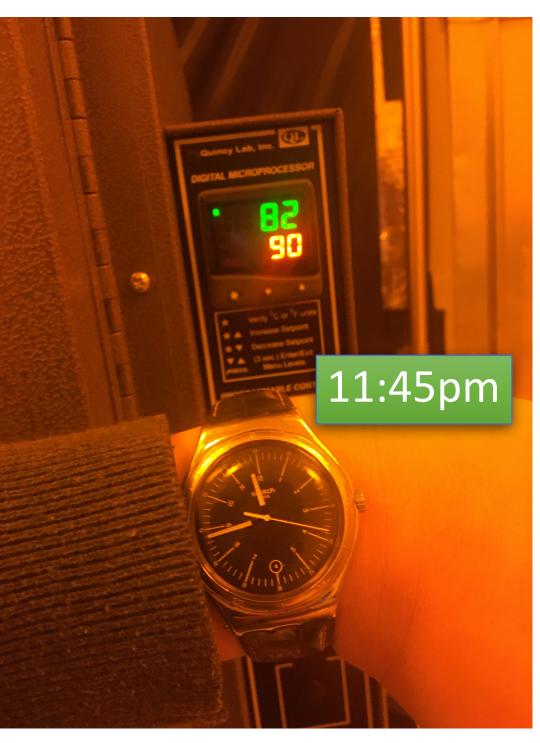
Take five

Annealing for 2.0 hours at 90C

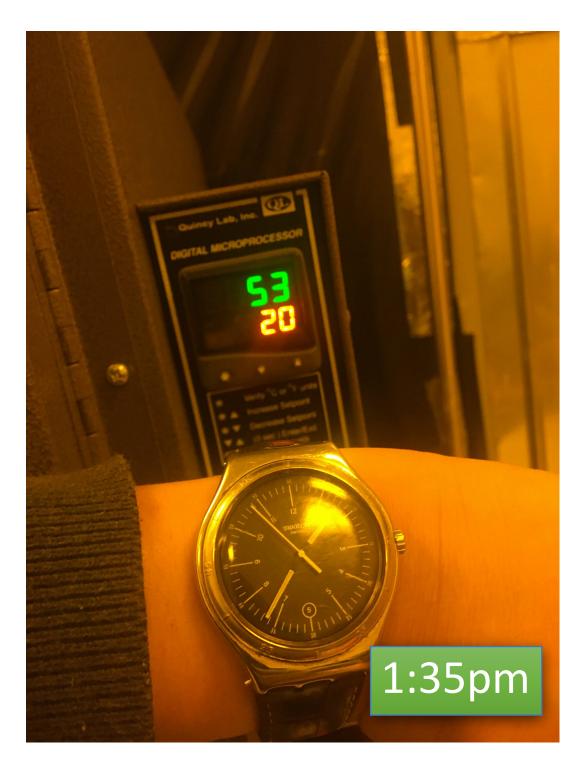


Cooking HDR2 2e14





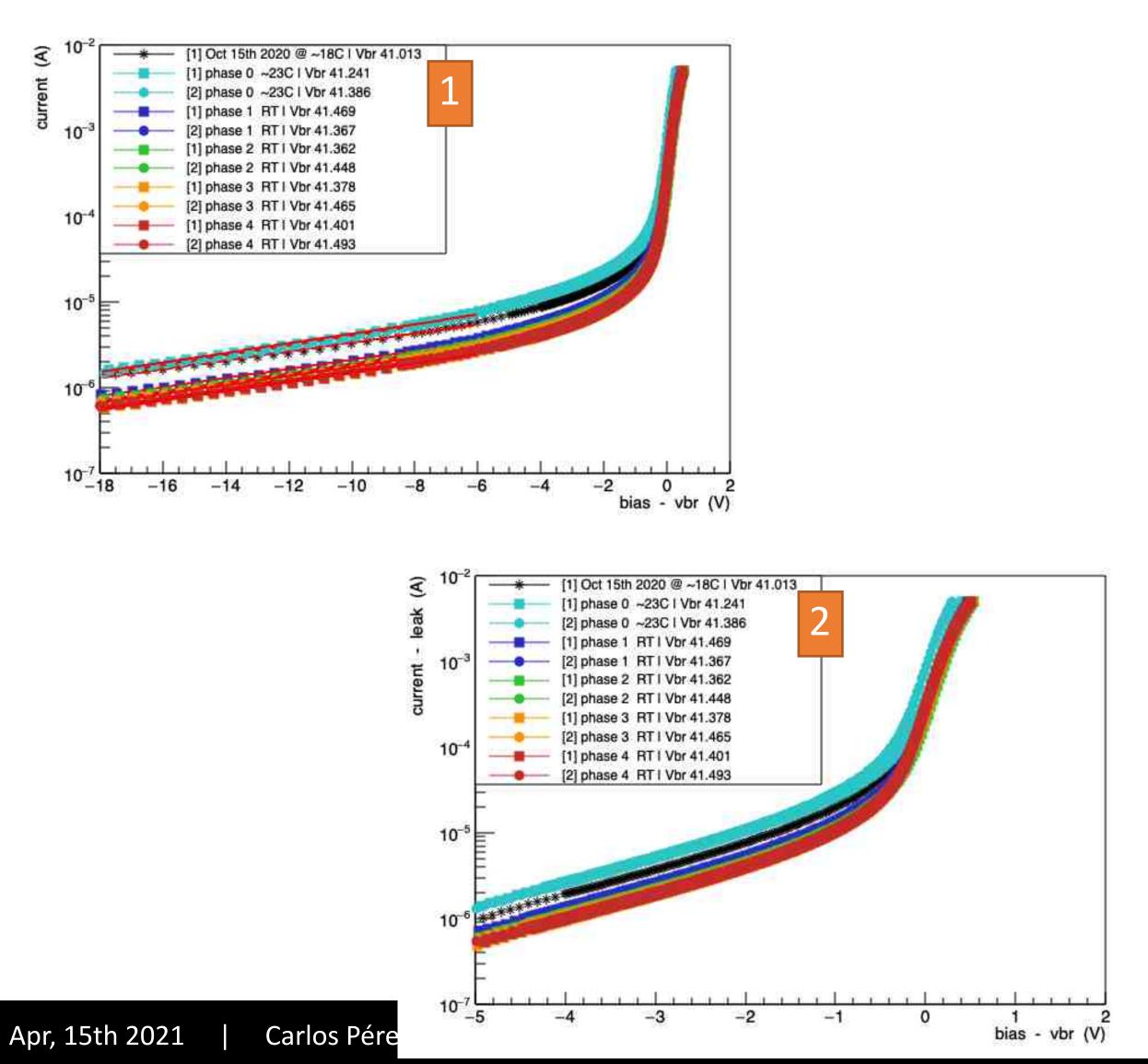


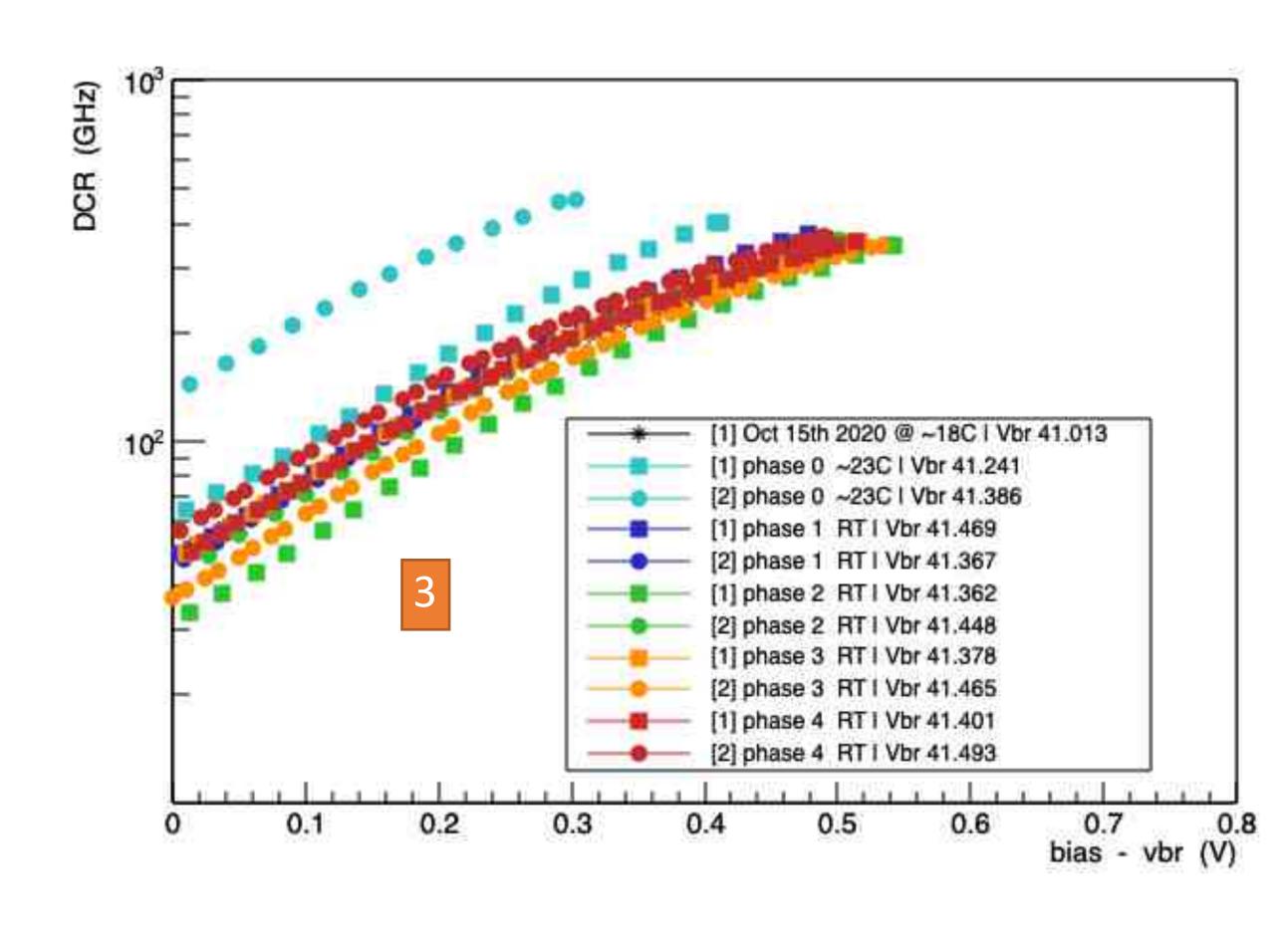


Cooking for around 2h at 90C

Measurements after first annealing interval

Once Vbr was determined via DARK/LED procedure, we compute DCR





Cooking HDR2 2e14

Fri 1:40pm - Sat2:20 at RT => 11 hours Sat 2:20pm - Sat 6:55pm at 90C => 2.5 hours Sat 7pm - Mon 7:45am at RT => 36 hours Move to cold storage

ROOM TEMP

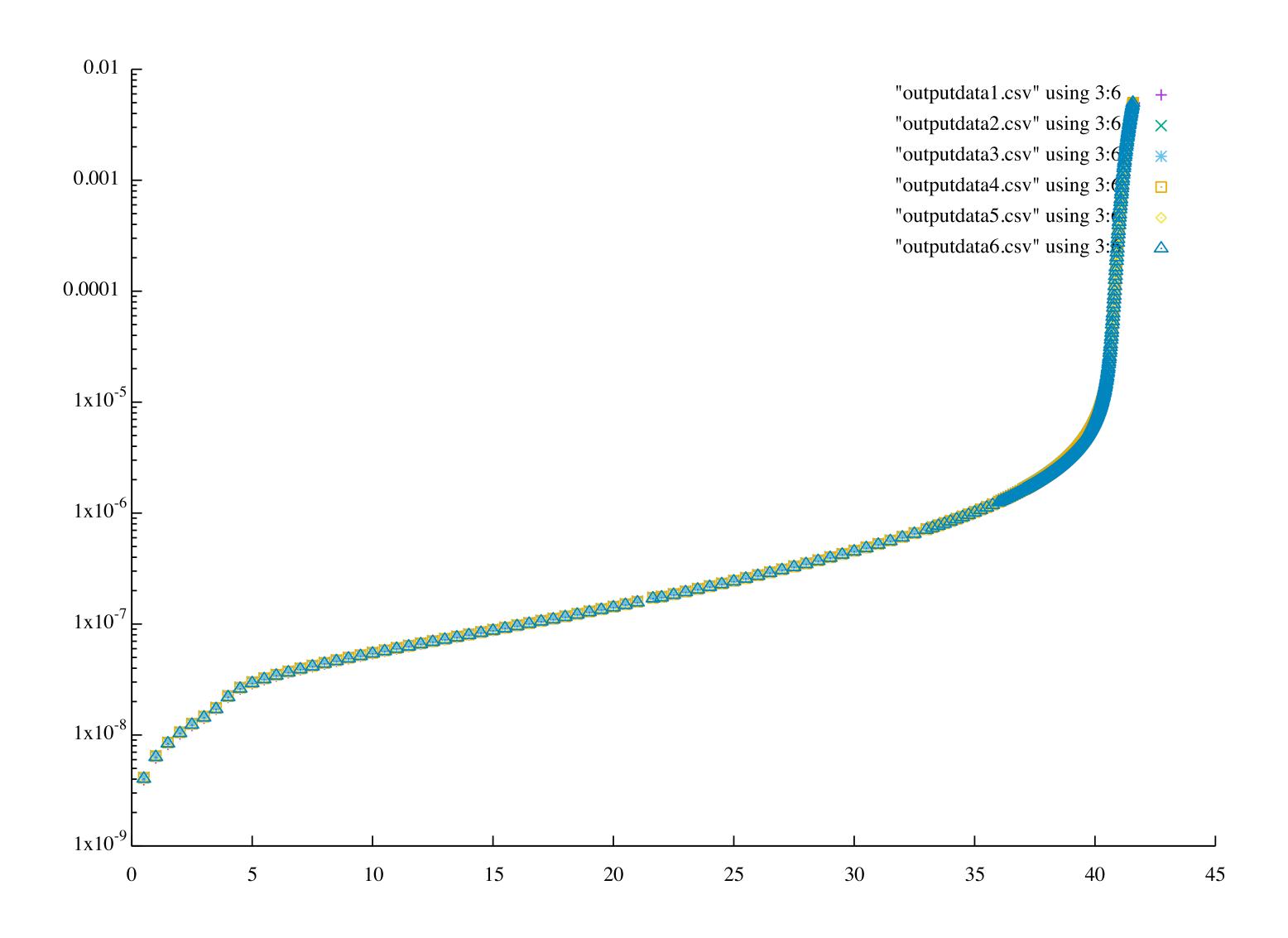




ROOM TEMP



Fase5 stability



6 consecutive runs of ~40 secs each

Apr, 15th 2021 | Carlos Pérez Lara (cperez@cern.ch)



Hamamatsu HDR2 5e13

Study of HDR2s timing resolution

Based on data taken during Apr'21, May'21 TB and Jul'21 bench-test

T. Anderson, B. Cox, J.P. Dervan, M. Joyce, A. Krishna, A. Ledovskoy, C. Pérez Lara, S. White



April Results

Setup at FNAL Testbeam (Apr'21)

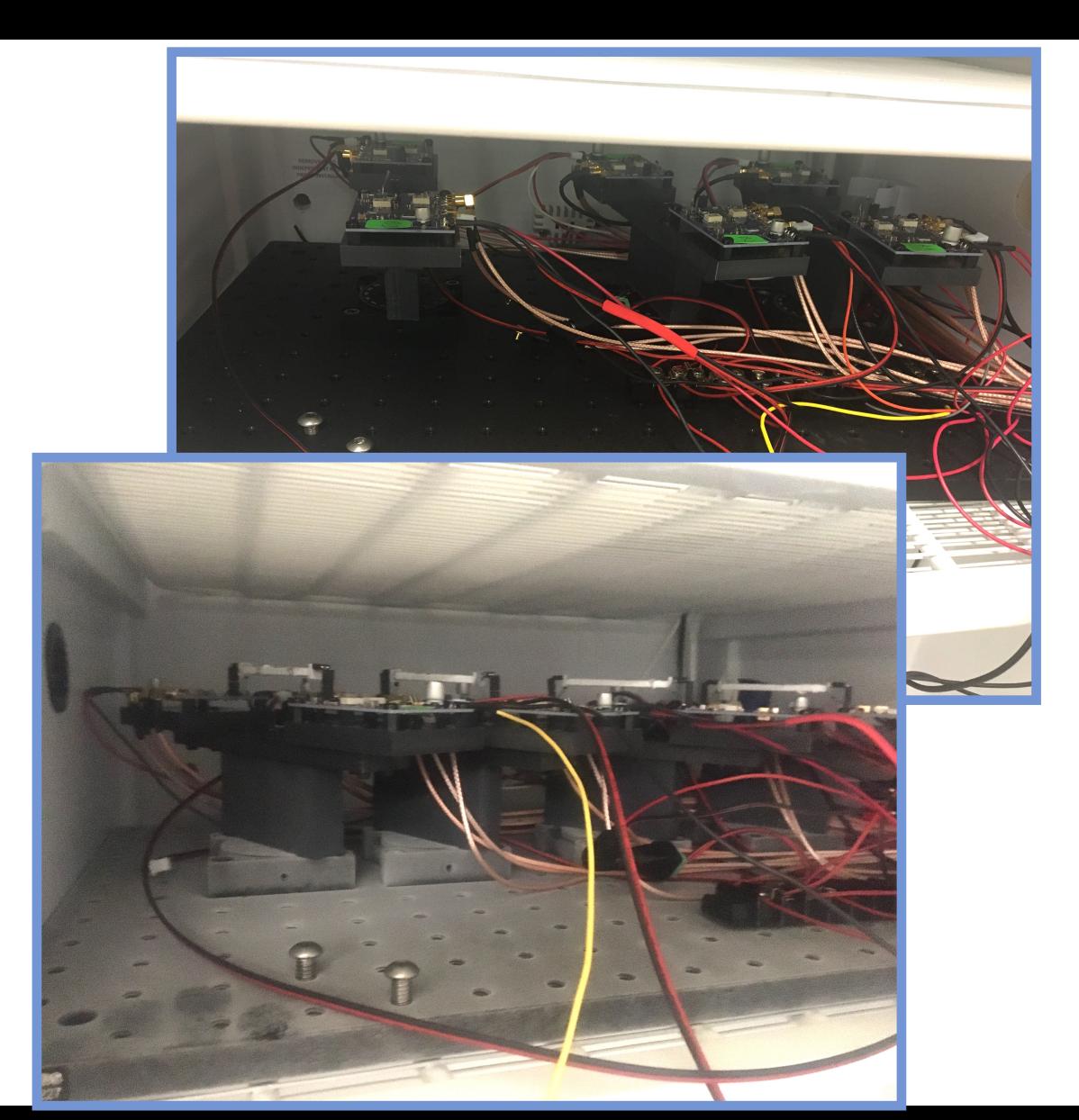
Data available

Four bars

- NH, 1e13, 5e13, 2e14
- 0 deg and 40 deg
- Several temperatures

Three bars:

- NI, 5e13, 2e14
- 52 deg
- Several temperatures



Setup at FNAL Testbeam (Apr'21)

This presentation:

Only looked a fraction of this data set

Data available

Four bars

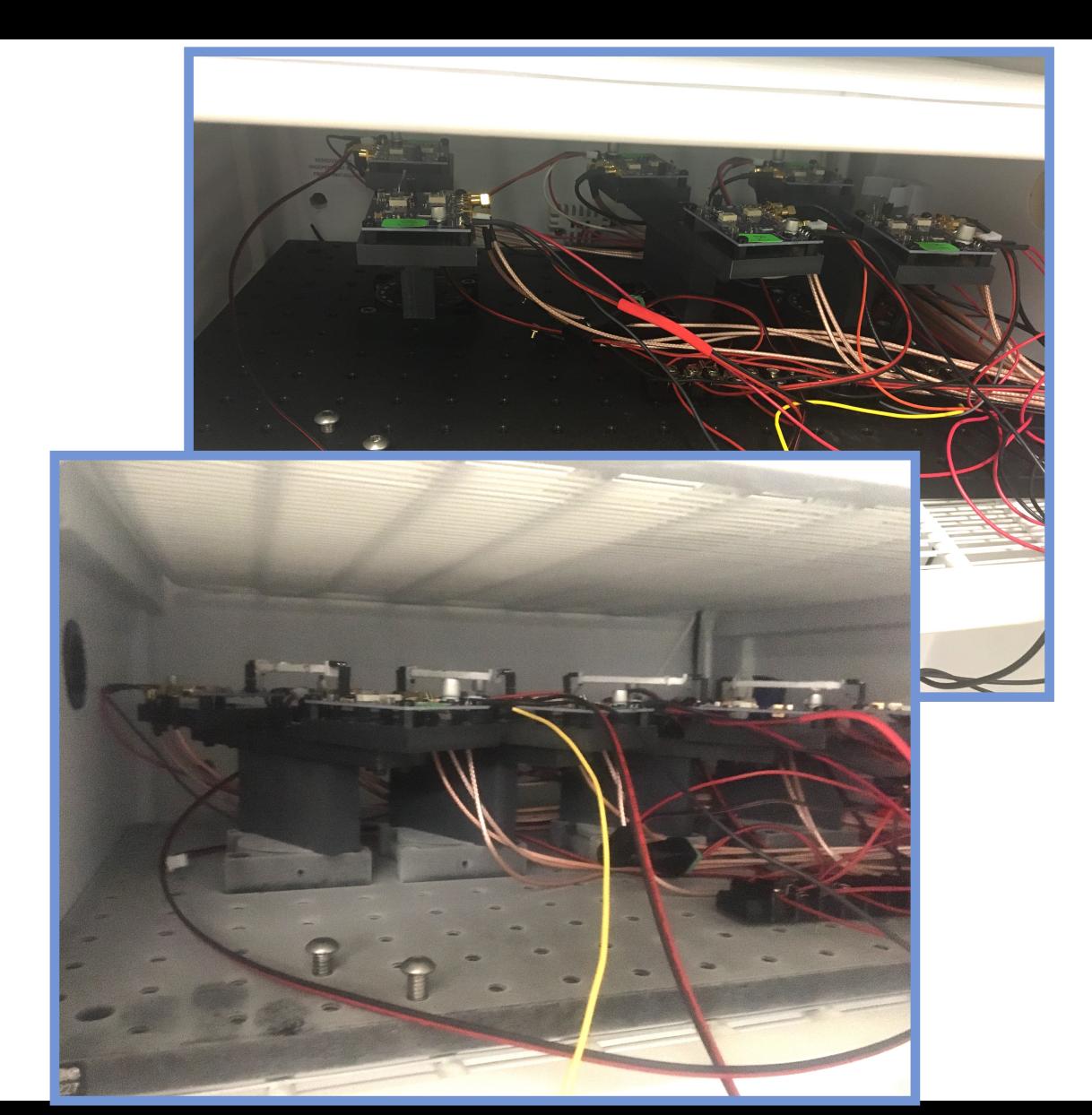
- NH, 1e13, 5e13, 2e14
- 0 deg and 40 deg
- Several temperatures

Three bars:

• N(, 5e13, 2e14

• 52 deg

Several temperatures



Data available

Apr'21

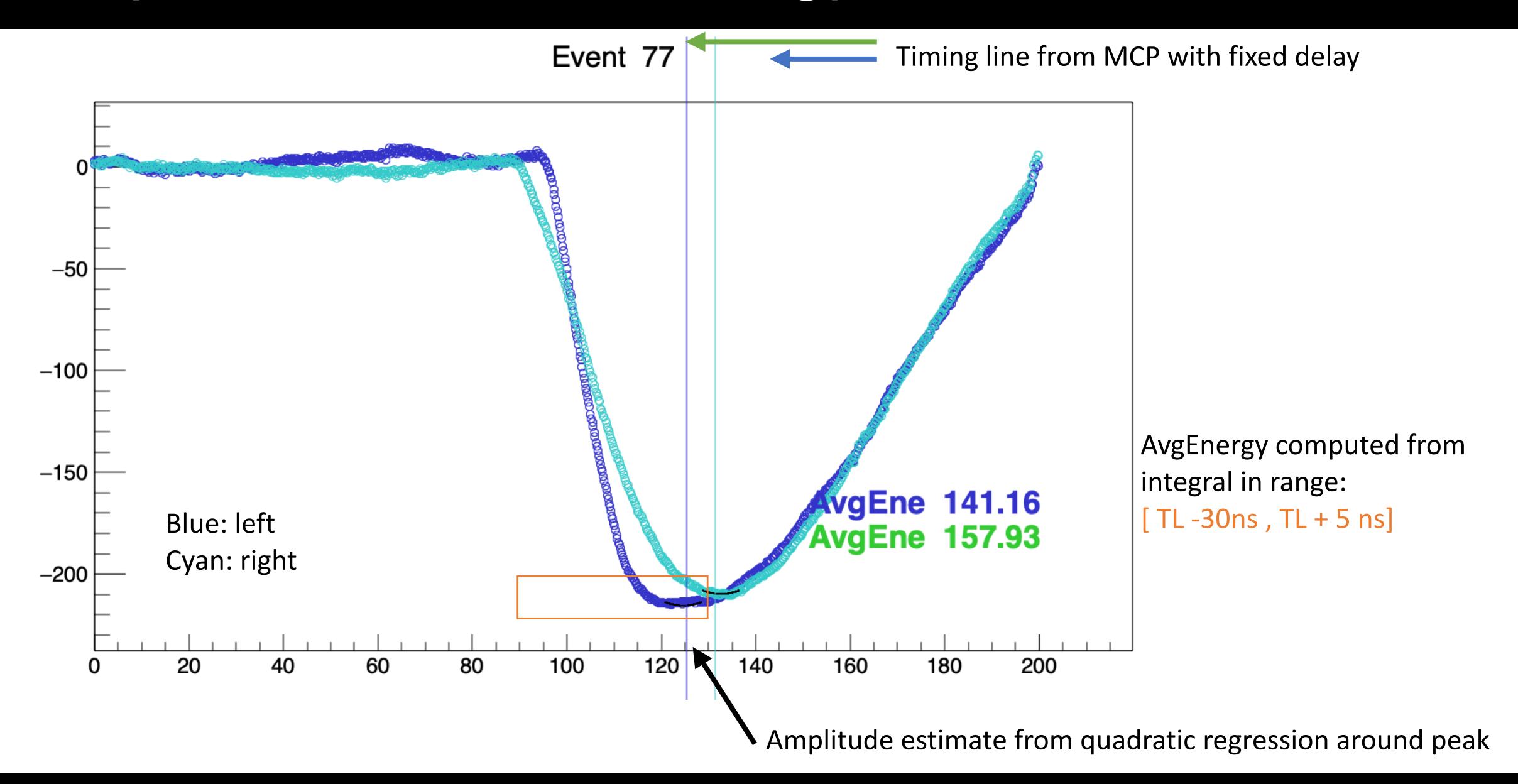
Wed Apr 21st @ -19 C , 52 deg 44725, 44728, 44730, 44731, 44732, 44733, 44734, 447435 Vop = 39.4 V (left) 39.5 V (right)

DRS CHN 4, 12 SiPM5 DRS CHN 5, 13 SiPM6

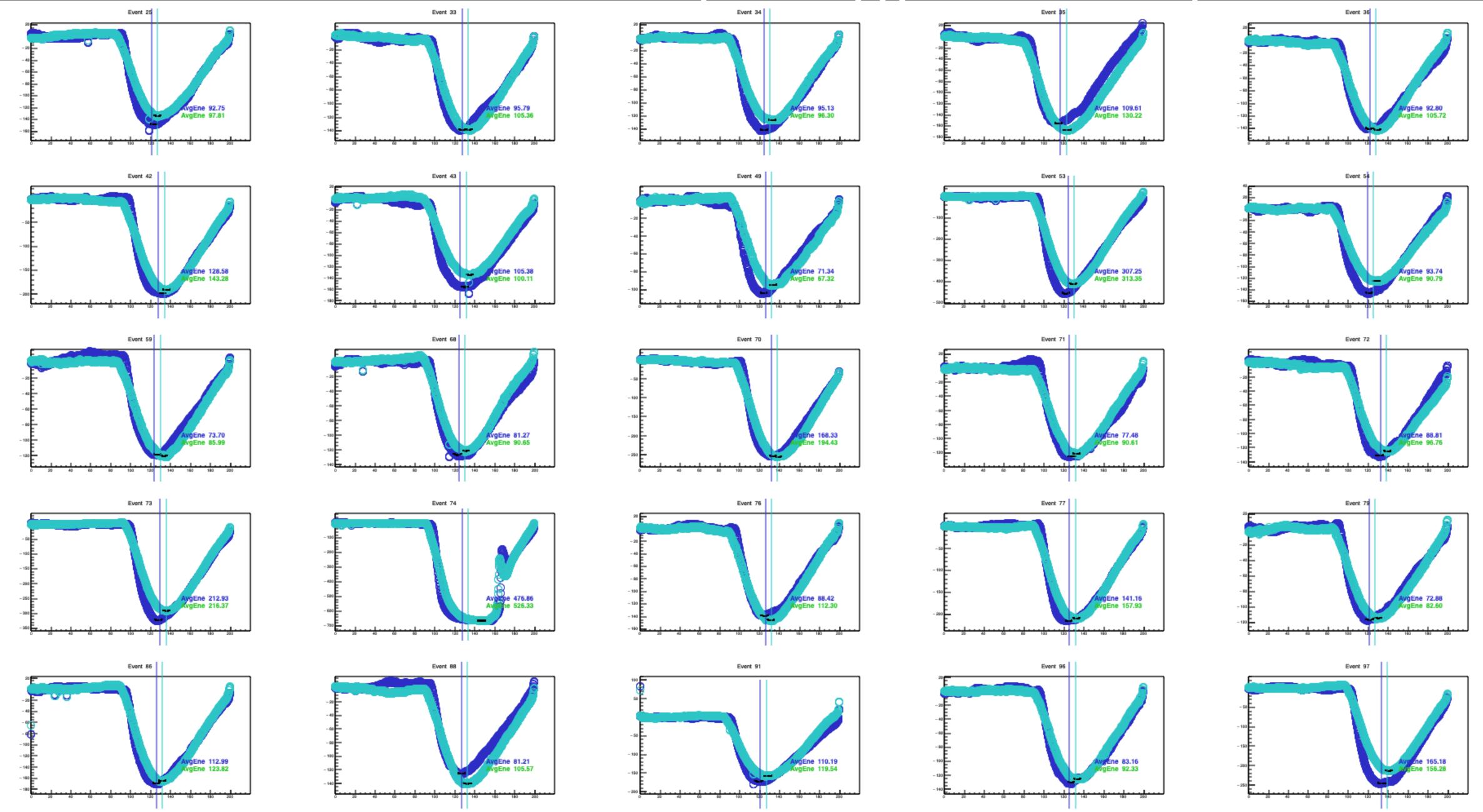
Length of LYSO: 56.5 mm

X-Projection at 52 deg = 34.8 mm

Example of one event [Energy Channel]

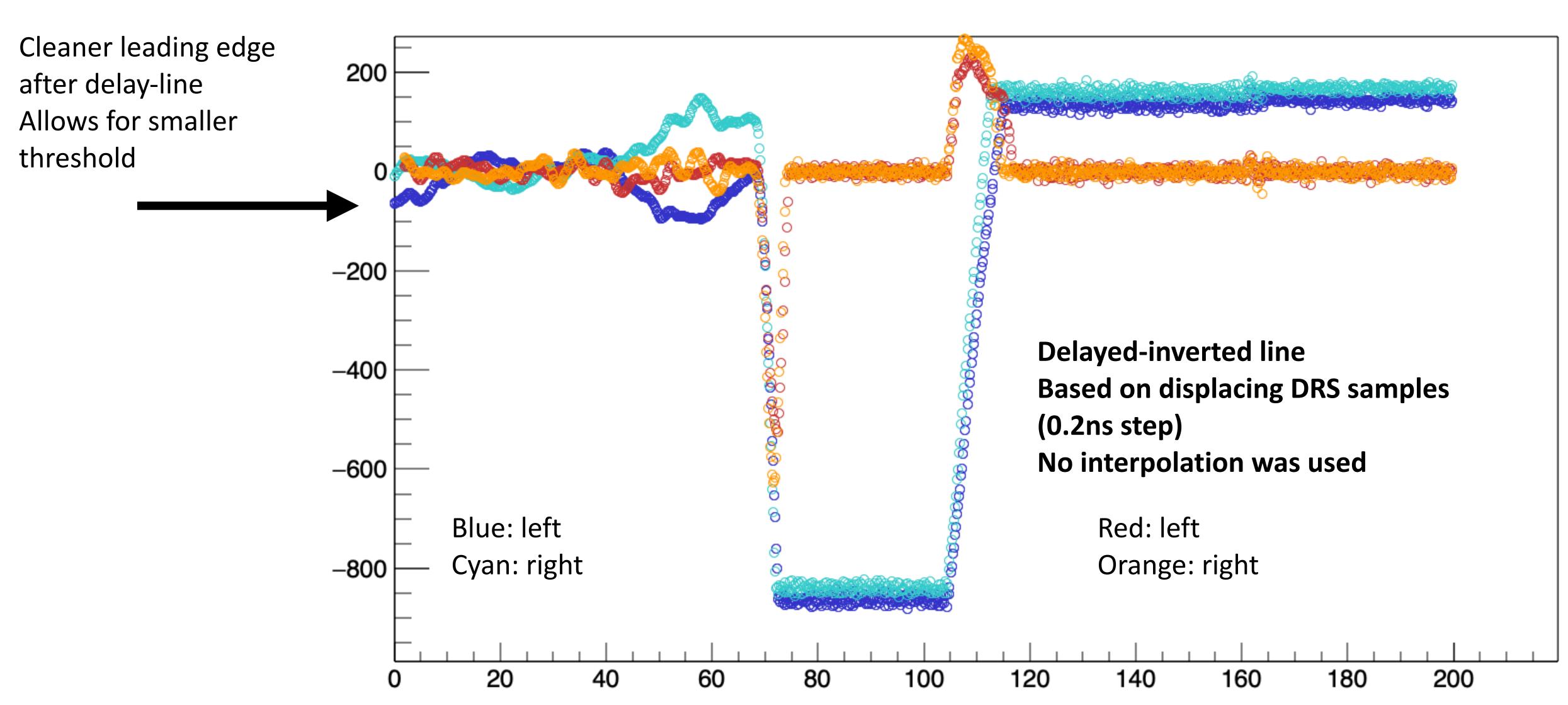


First 25 Events selected [Energy Channel]

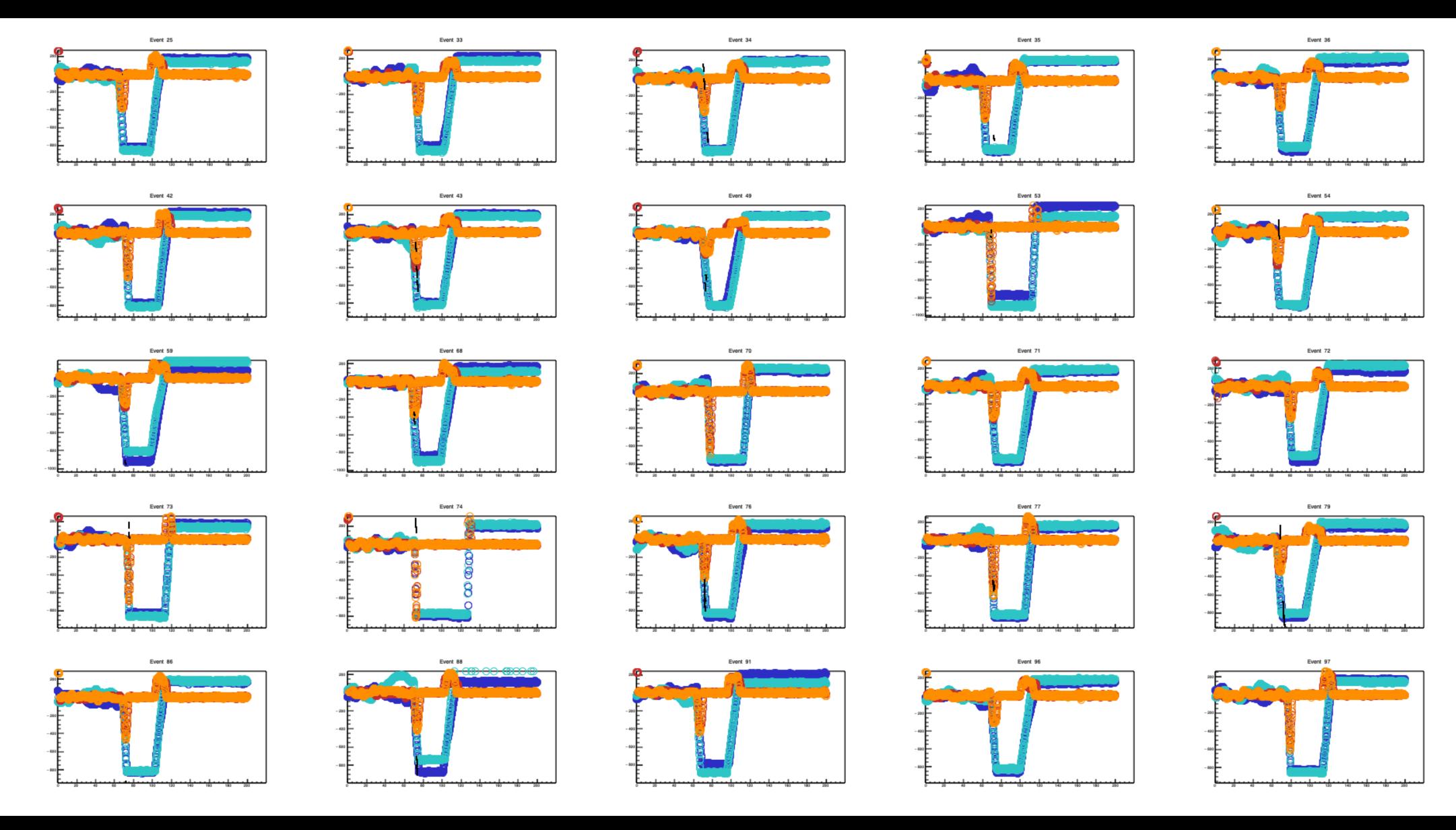


Example of one event [Timing Channel]

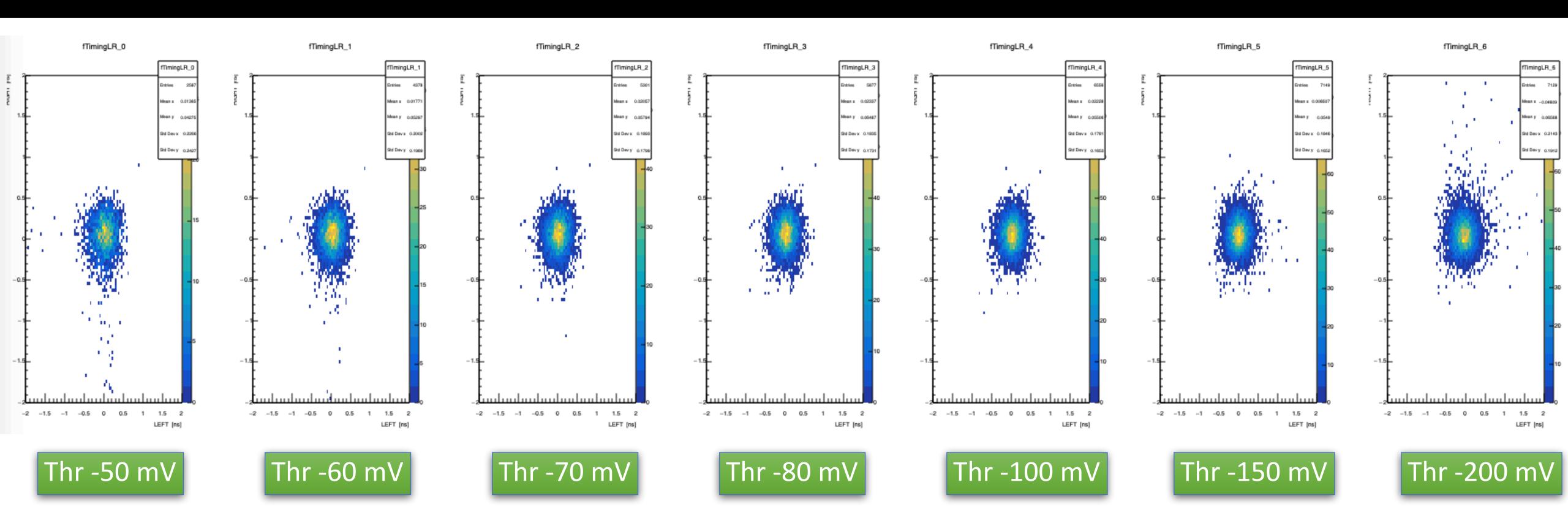




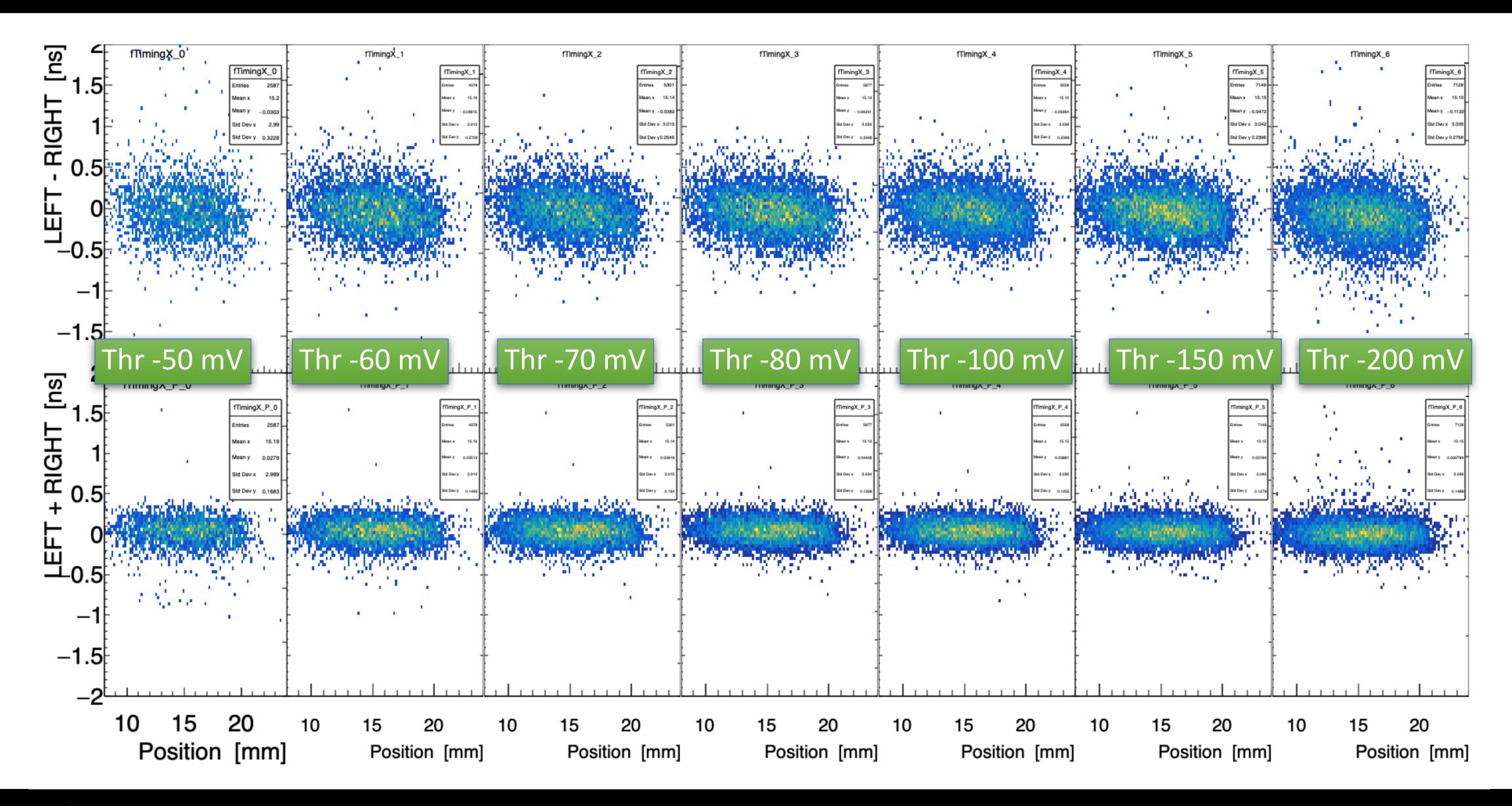
First 25 Events selected [Timing Channel]



LEFT [ns] vs RIGHT [ns]

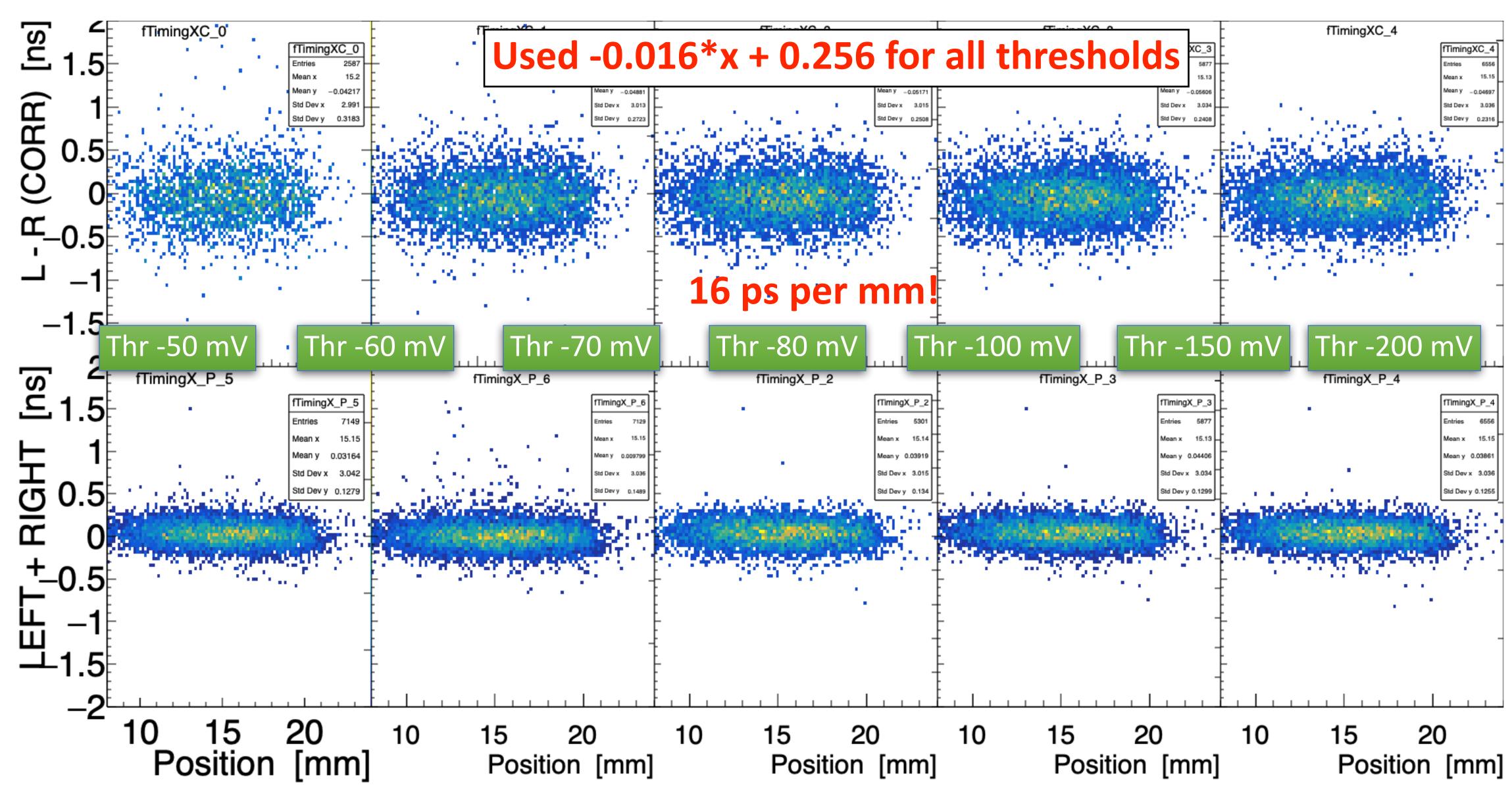


Time offset with X-along the bar



Aug, 1st 2021 | Carlos Pérez Lara (cperez@cern.ch)

Time offset with X-along the bar



Aug, 1st 2021 Carios i cicz Lara jepciez weetin.enj



Each group is composed by 8 channels (GROUP 0 = CHANNEL 0 - 7, GROUP 1 = CHANNEL 8 - 15, etc.) and by the special channel TRn: such signal is common to two groups; it can be used as Local Trigger or "digitized" and stored with the data for high resolution timing analysis between the ADC channels and the TRn itself (refer to **Sec. TRO and TR1 Inputs**).

The values of the theoretical "average" trigger rate, computed upon the given formulas, are reported in the following tables for $N_S = 1024$ samples.

N _G	TR Not Digitized	TR Digitized
1	6.813 kHz	6.058 kHz
2	3.409 kHz	3.030 kHz

Tab. 7.3: Theoretical "average" trigger rate values for the Optical Link

N _G	TR Not Digitized	TR Digitized
1	2.556 kHz	2.272 kHz
2	1.278 kHz	1.136 kHz

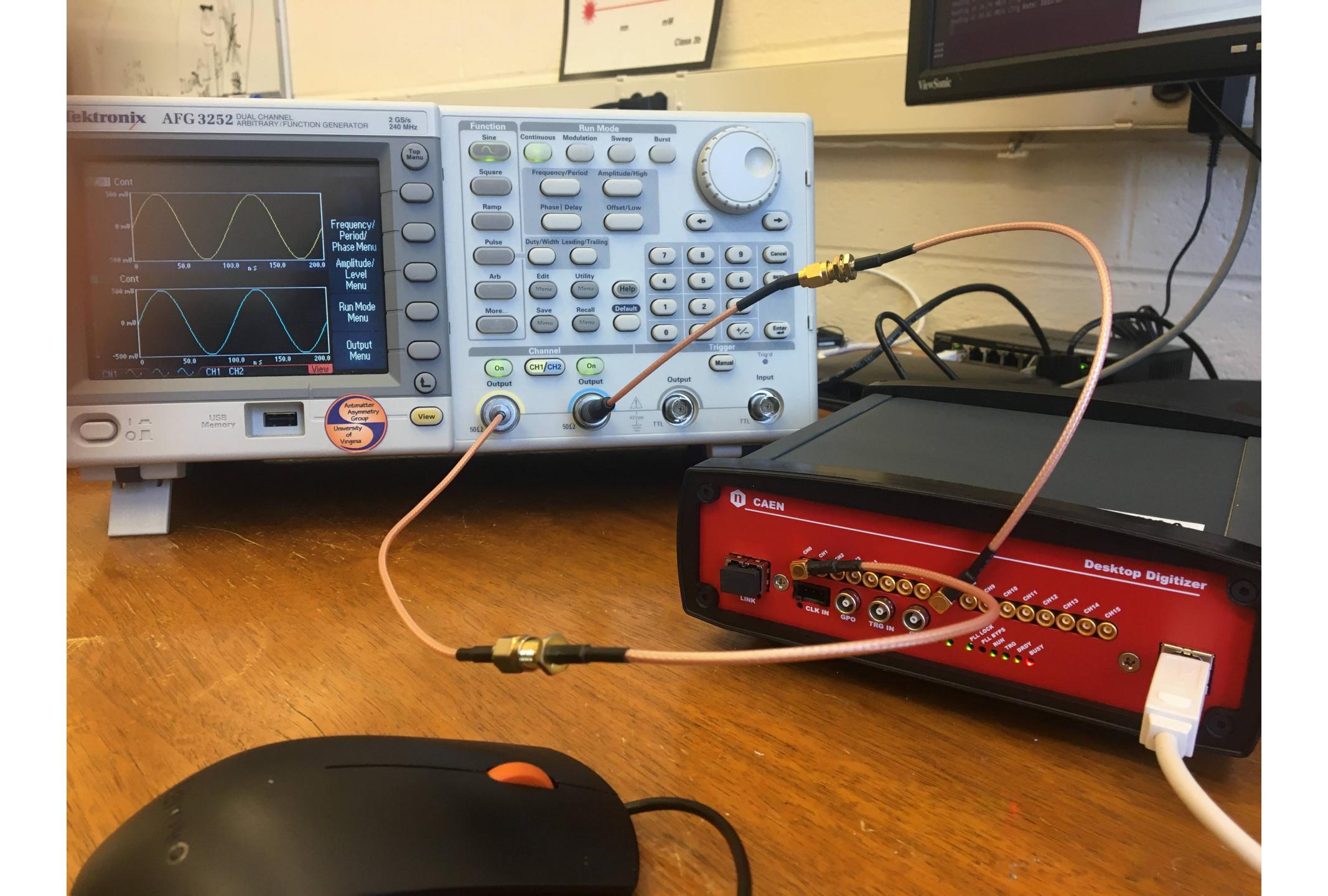
Tab. 7.4: Theoretical "average" trigger rate values for the USB Link

So theoretically for our use 16CH + TR0 digitized we will get

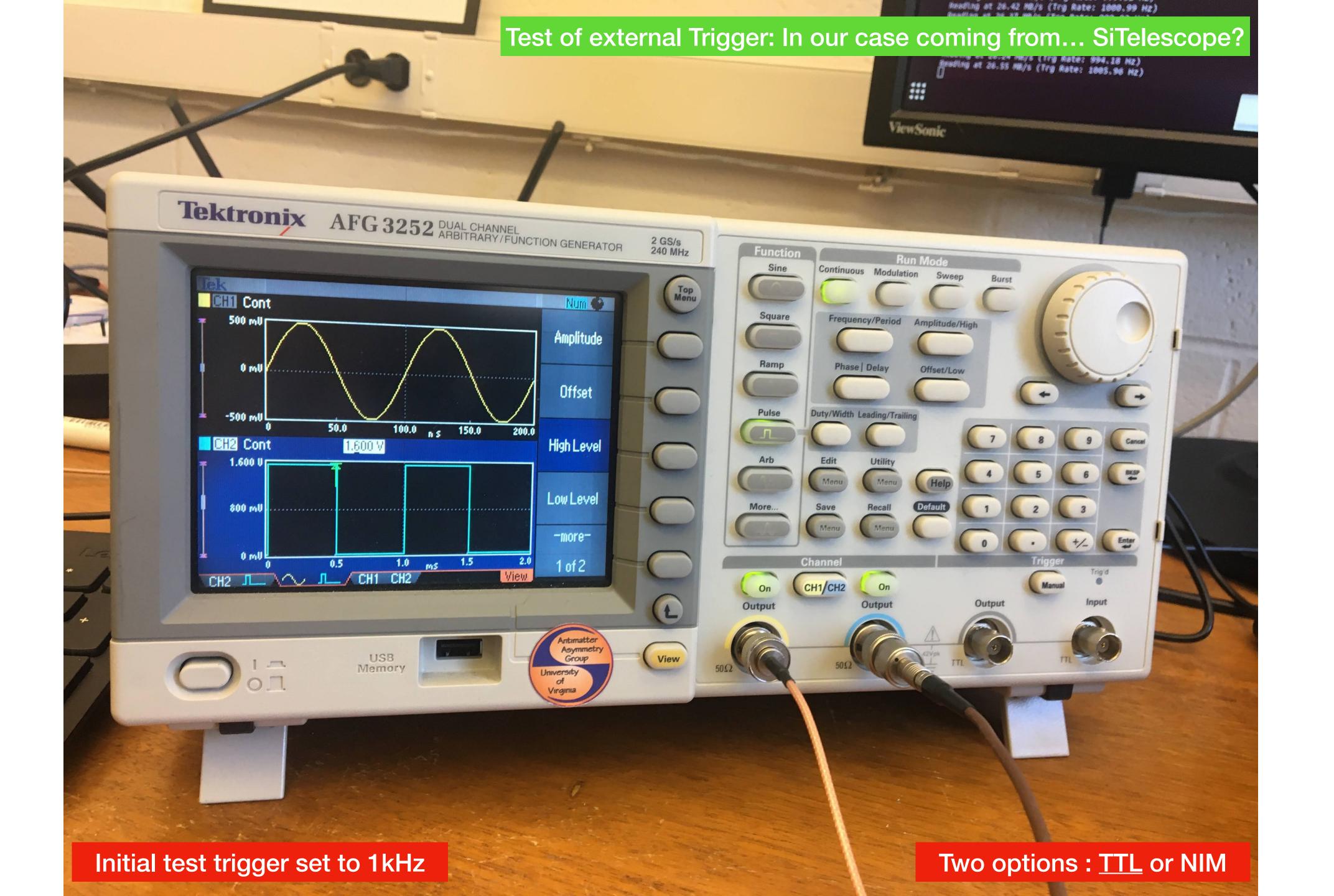
USB 1.136 kHz

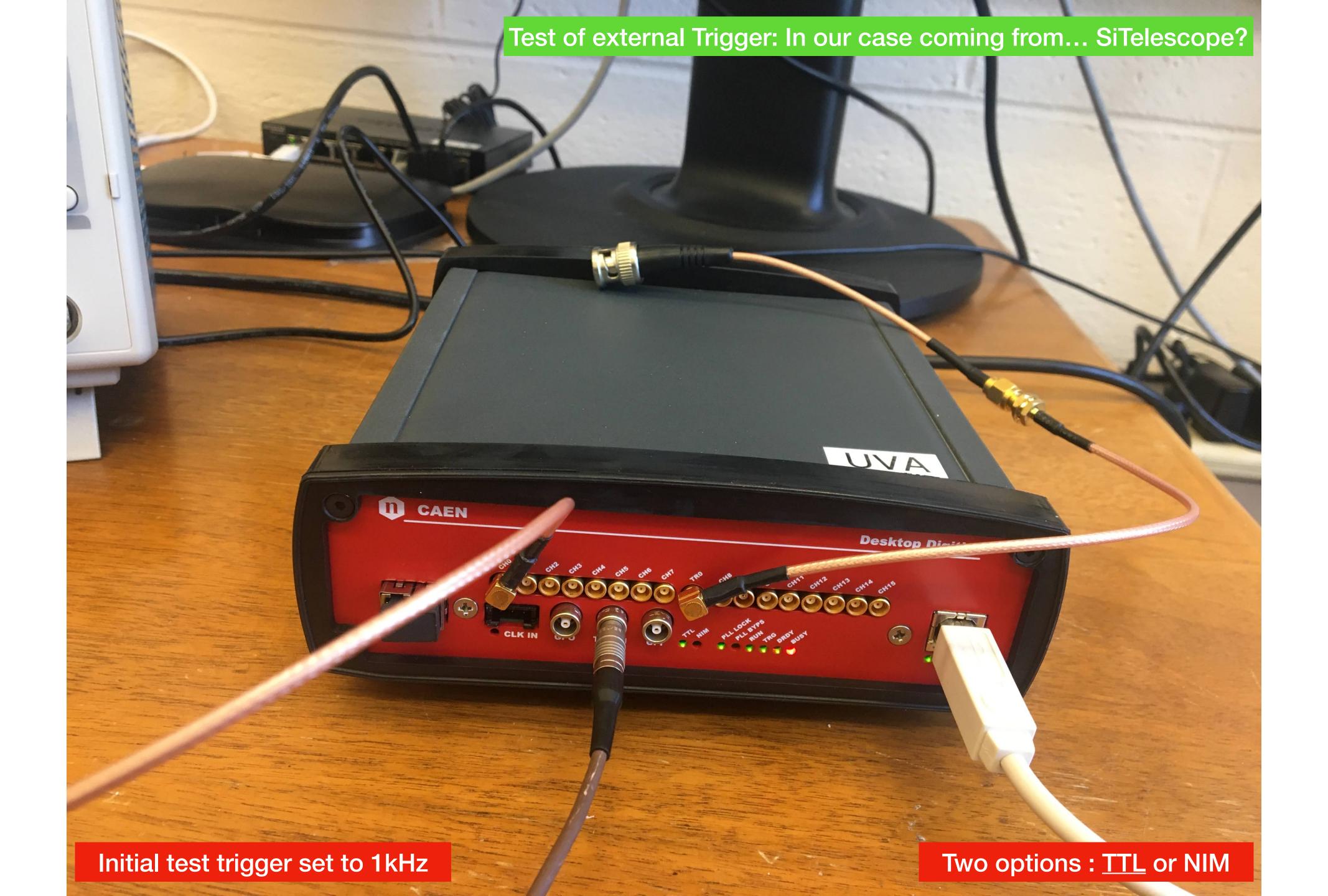
PCI 3.030 kHz

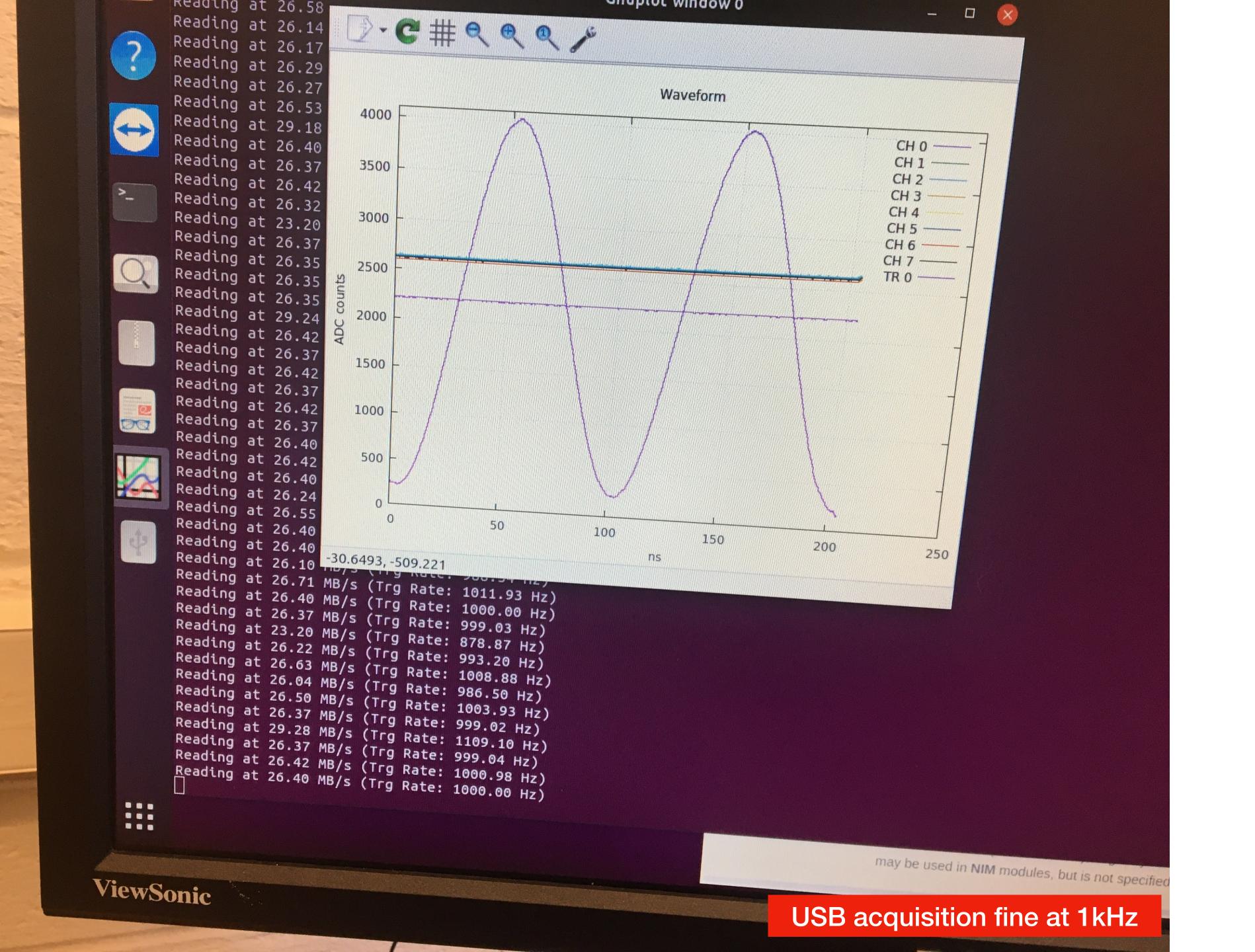
50k MIPS in 13 min 4 min



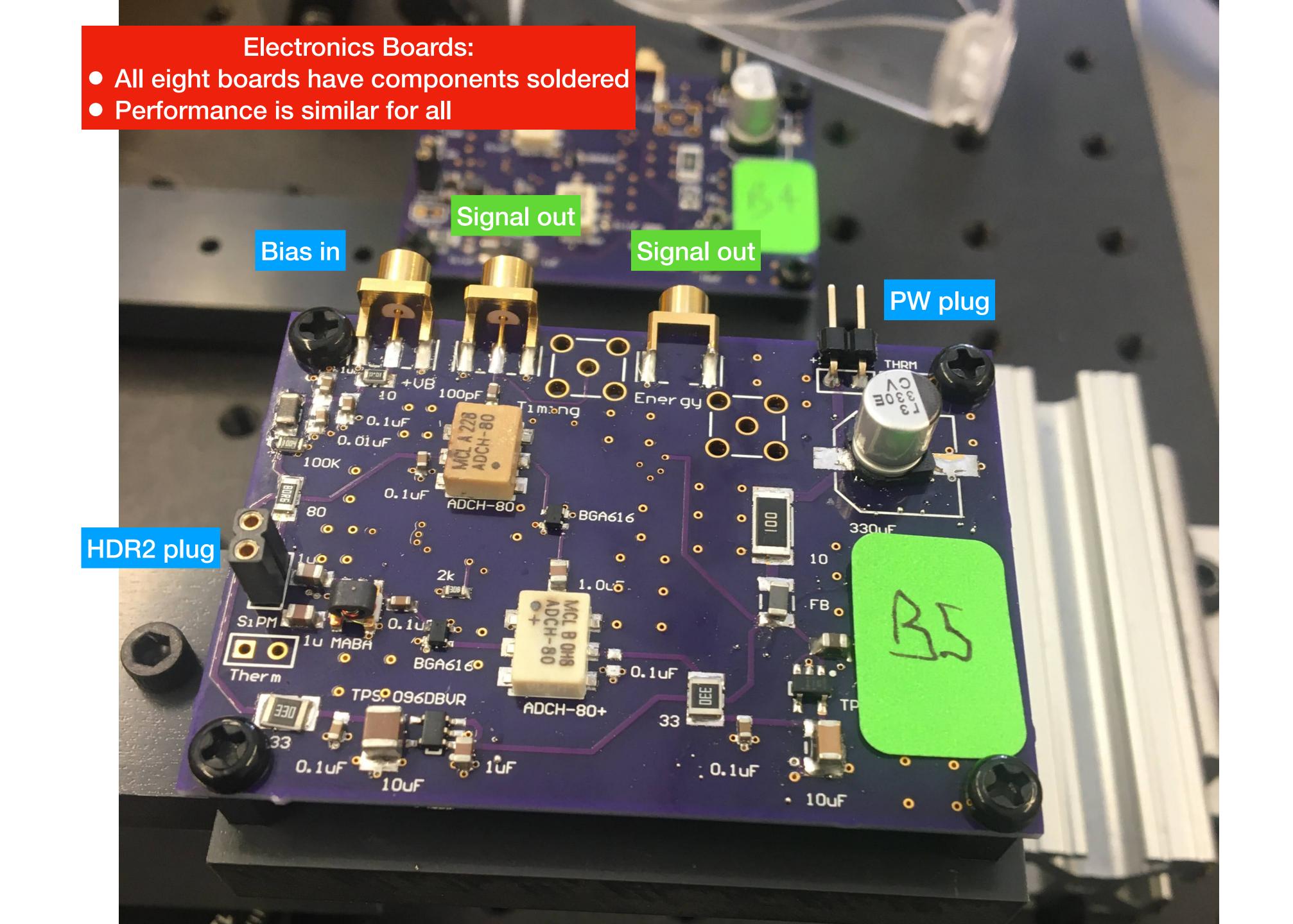
```
Reading at 26.55 MB/s (Irg Rate: 1003.90 Hz)
Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                            Using CAEN's tool wavedump
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Plot group set to 0
Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
Reading at 26.58 MB/s (Trg Rate: 1006.89 Hz)
Reading at 26.61 MB/s (Trg Rate: 1007.88 Hz)
                                                                                                                         Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
                                                                                  Gnuplot window 0
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 27.00 MB/s (Trg Rate: 1023.00 Hz)
                                                     Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                         Waveform
Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
                                                       4000
                                                                                                                       CH 0
Reading at 26.98 MB/s (Trg Rate: 1021.98 Hz)
                                                                                                                       CH 1
Reading at 26.76 MB/s (Trg Rate: 1013.88 Hz)
                                                                                                                       CH 2
                                                       3500
 Reading at 26.74 MB/s (Trg Rate: 1012.87 Hz)
                                                                                                                       CH 3
 Reading at 26.84 MB/s (Trg Rate: 1016.90 Hz)
                                                                                                                      CH 4
 Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
                                                                                                                      CH 5
                                                       3000
 Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
                                                                                                                      CH 6
                                                                                                                      CH 7 -
 Reading at 26.82 MB/s (Trg Rate: 1015.89 Hz)
                                                                                                                      TR 0
 Reading at 26.84 MB/s (Trg Rate: 1016.90 Hz)
                                                       2500
 Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
                                                    ADC counts
 Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
  Reading at 26.68 MB/s (Trg Rate: 1010.87 Hz)
                                                       2000
  Reading at 26.40 MB/s (Trg Rate: 1000.00 Hz)
  Reading at 23.54 MB/s (Trg Rate: 891.89 Hz)
                                                       1500
  Reading at 26.19 MB/s (Trg Rate: 992.24 Hz)
  Reading at 26.37 MB/s (Trg Rate: 999.02 Hz)
  Reading at 26.90 MB/s (Trg Rate: 1018.92 Hz)
                                                       1000
  Reading at 26.92 MB/s (Trg Rate: 1019.94 Hz)
  Reading at 26.71 MB/s (Trg Rate: 1011.87 Hz)
  Reading at 26.68 MB/s (Trg Rate: 1010.87 Hz)
                                                        500
  Reading at 26.66 MB/s (Trg Rate: 1009.87 Hz)
  Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
  Reading at 26.63 MB/s (Trg Rate: 1008.88 Hz)
  Reading at 26.76 MB/s (Trg Rate: 1013.88 Hz)
                                                                       50
                                                                                    100
  Reading at 26.79 MB/s (Trg Rate: 1014.88 Hz)
                                                                                                 150
                                                                                                               200
   Reading at 26.74 MB/s (Trg Rate: 1012.87 Hz)
                                                                                                                              250
                                                                                          ns
                                                    171.155, 4572.40
                                                                                                           TR0 capable to
                                                                                                          digitize up to 2V
Sonic
```



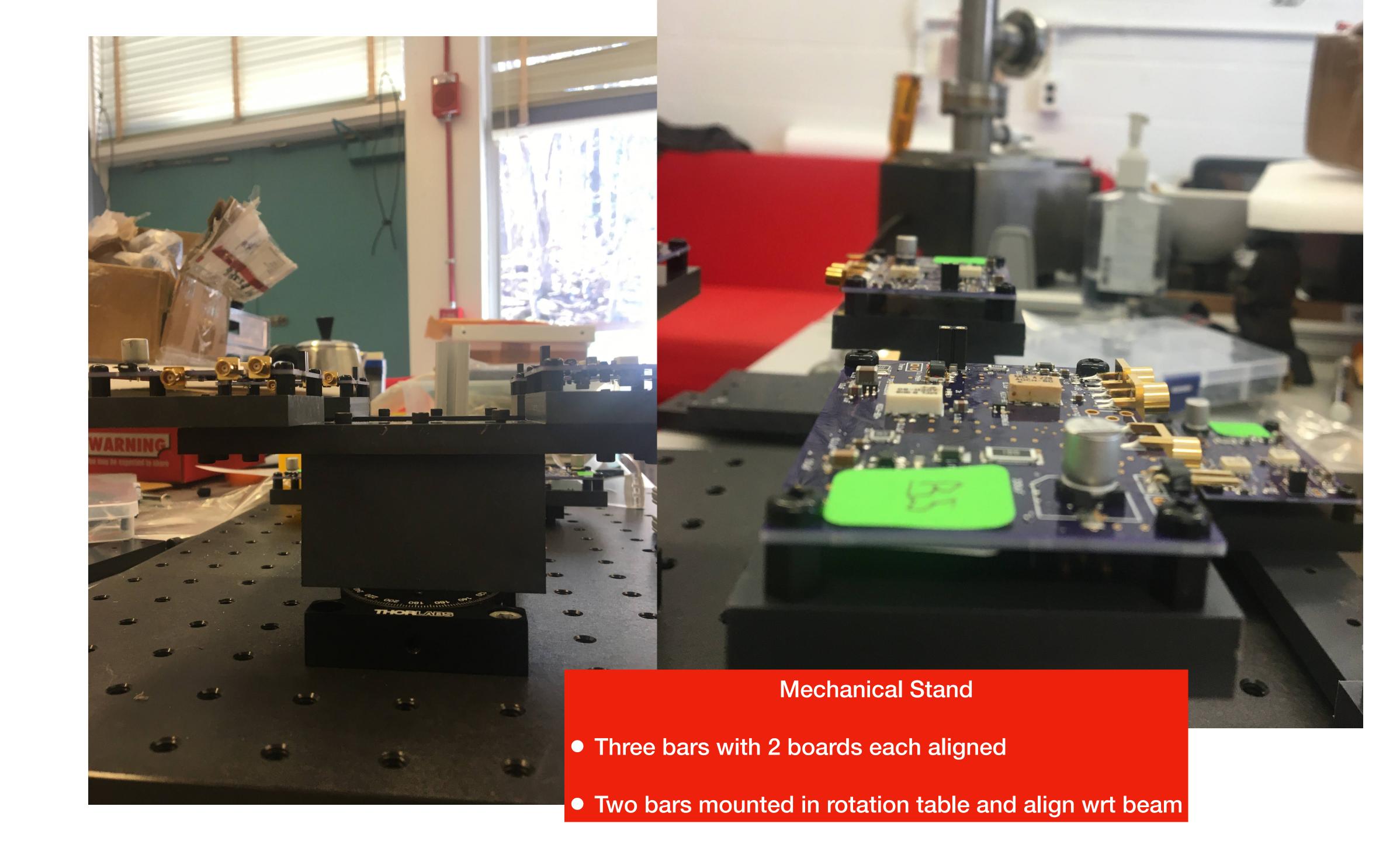




Electronic Board And Mechanical Assembly

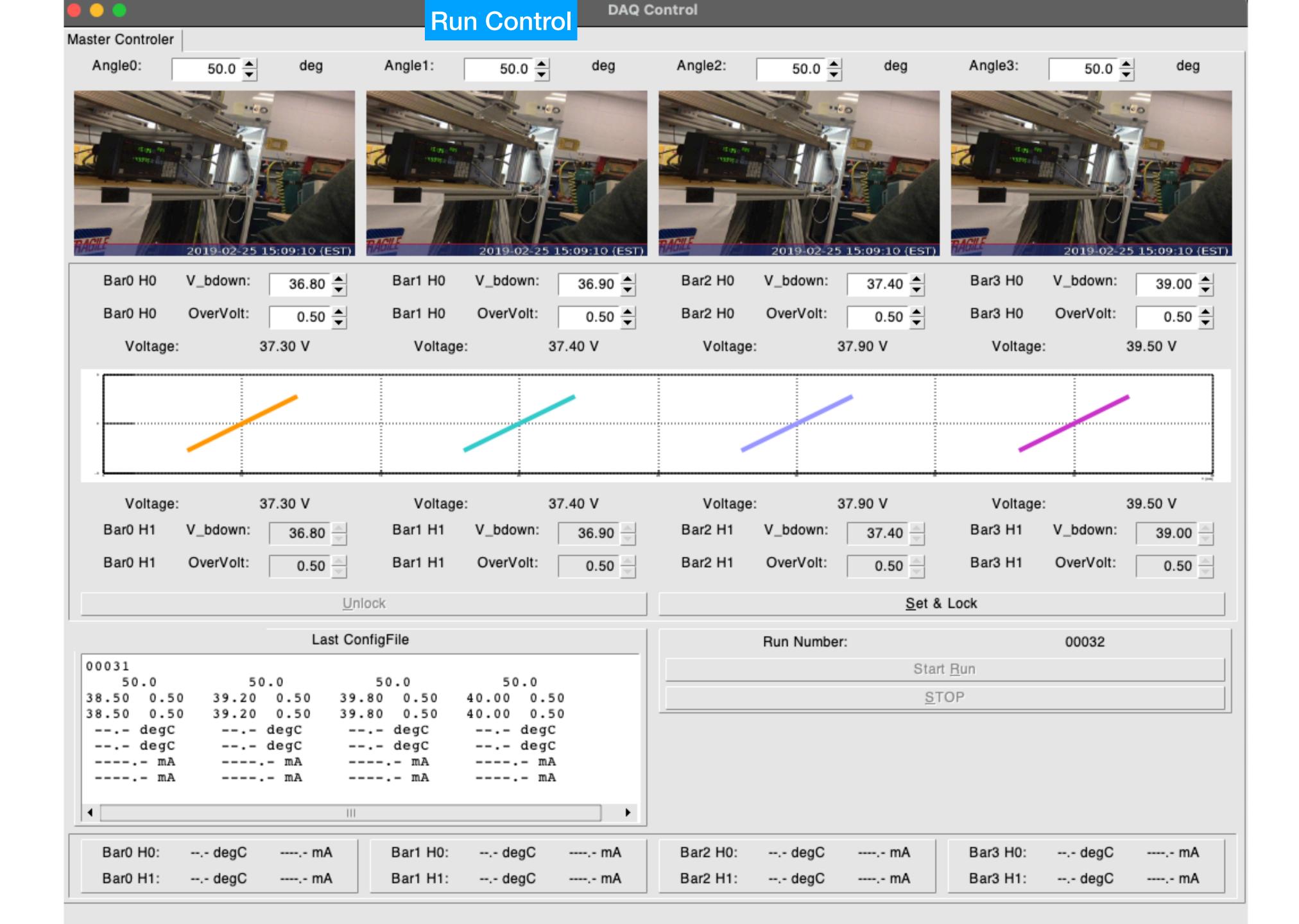








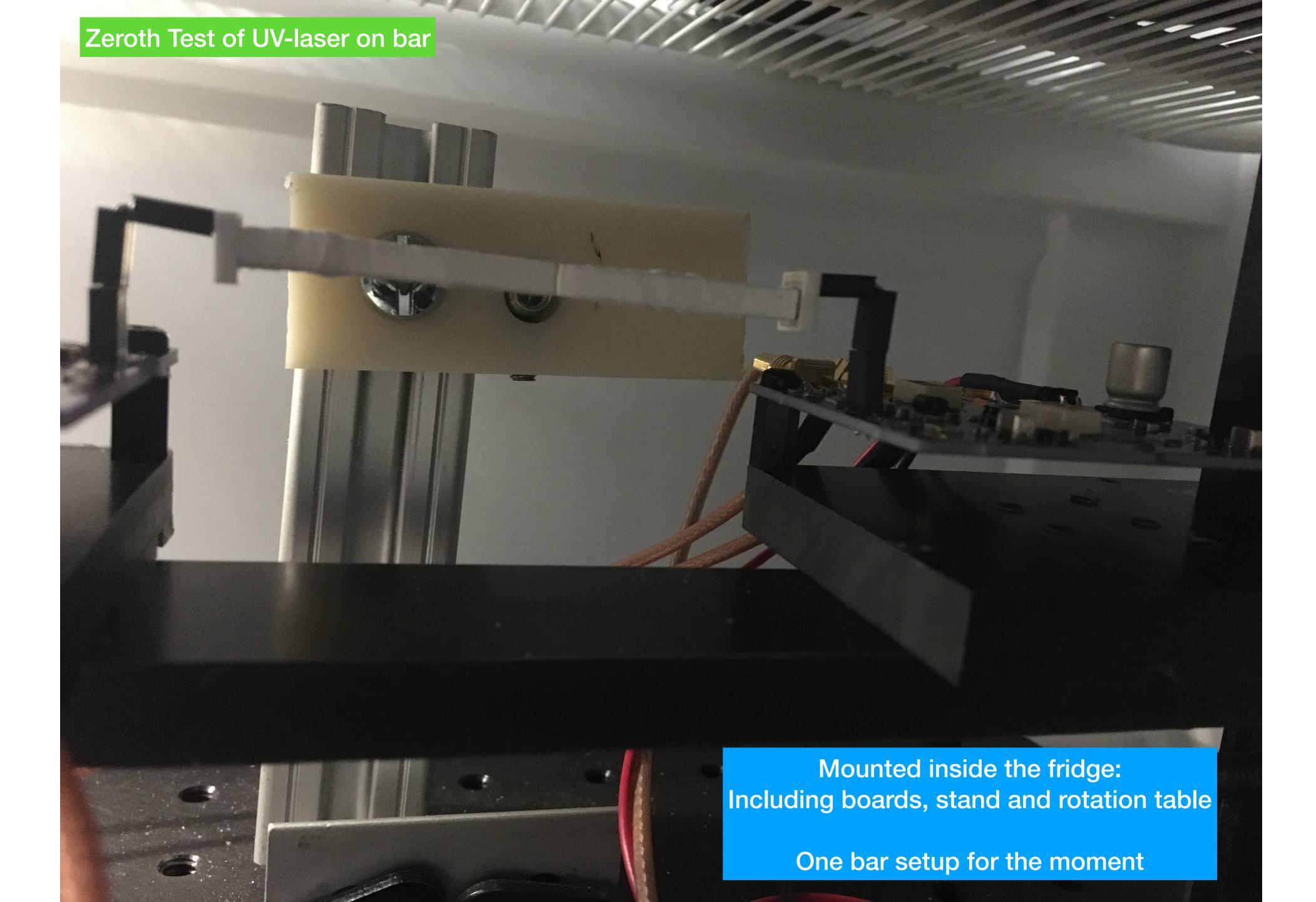
Run Control and Data Monitor



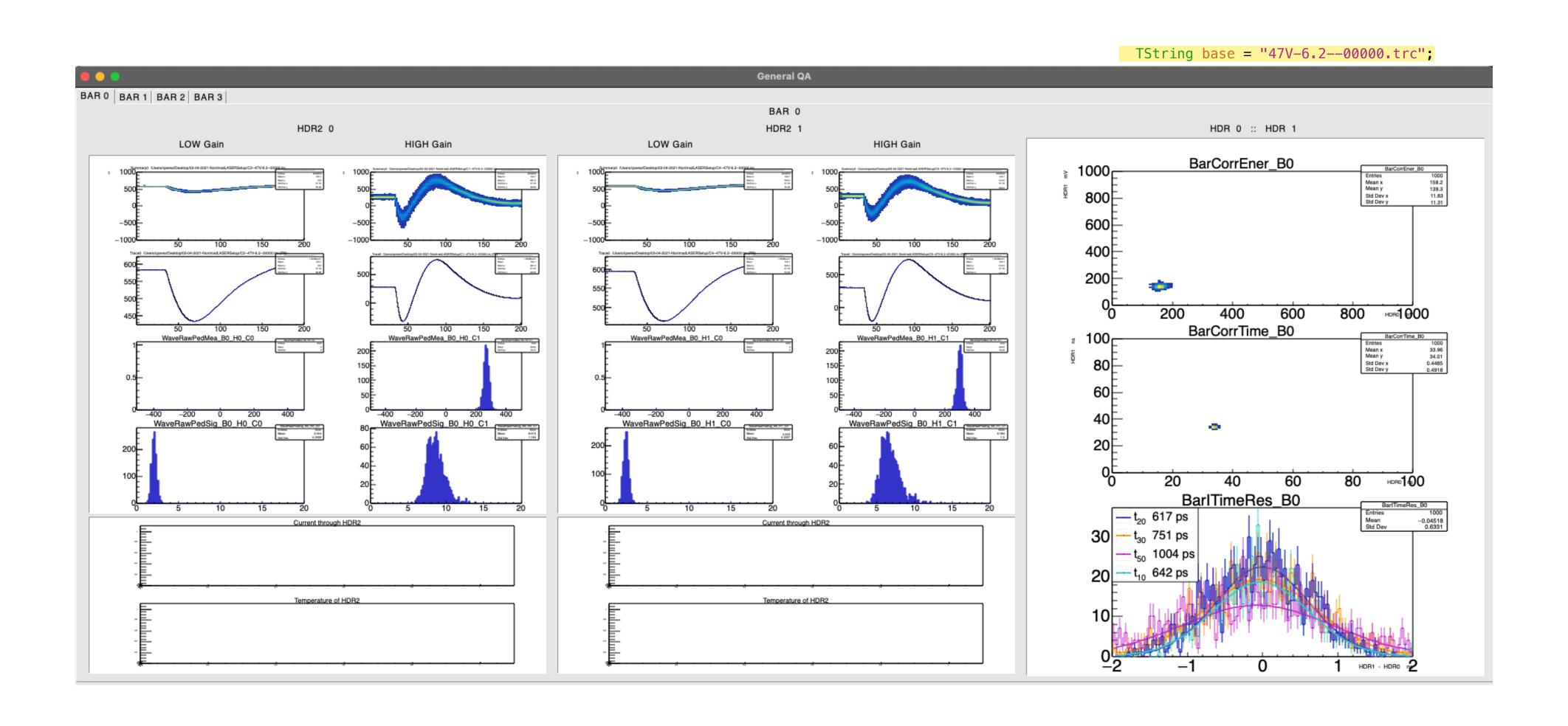
Data Quality Monitoring



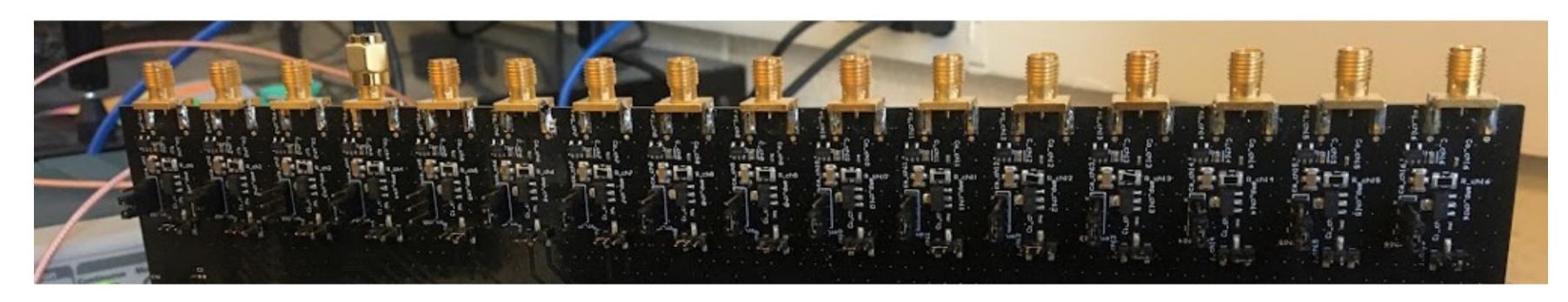
Fake MC signals

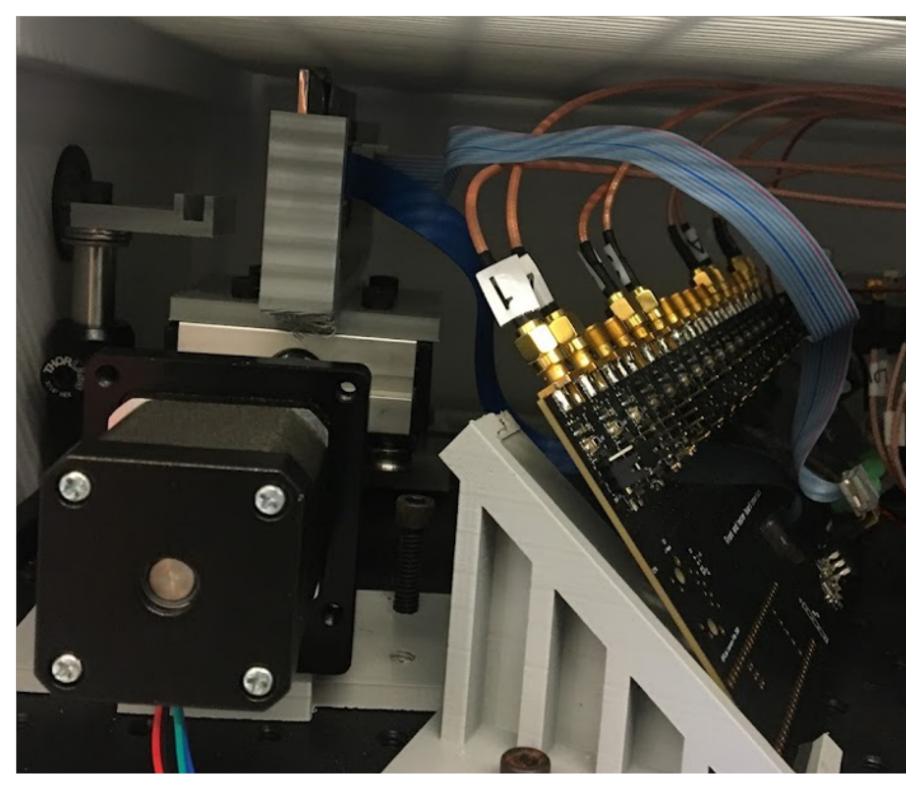


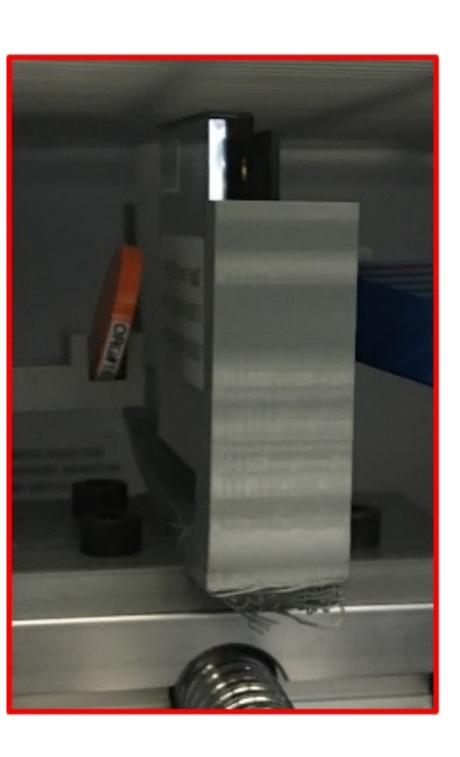
Real response of UV-laser on LYSO + HDR2 + FEElectronics



EBoard allows reading 8 bars at a time







Testing board developed at Caltech using a x5 amplifie

Provides a bridge between flex connector and

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How long will it take to anneal?

5e13 **@1 OV**

Measured DCR for 5e13 SiPM is 43GHz at -30C.

Target DCR is 30GHz at -25C or 23.4GHz at -30C. The annealing factor is 43/23.4 = 1.84

Estimated annealing time at different temperatures:

Time
202 days 21 hours 2 min
42 days 7 hours 22 min
9 days 17 hours 42 min
2 days 10 hours 52 min
0 days 16 hours 12 min
0 days 4 hours 52 min

@1 OV 2e14

Time

The annealing factor is x4 of 5e13 or 4 * 1.84 = 7.36Estimated annealing time at different temperatures:

Temp 745 days 0 hours 12 min 234 days 7 hours 52 min 78 days 10 hours 52 min 100 27 days 19 hours 42 min ____ 10 days 9 hours 42 min 110

If we anneal at 80C we would need several months to reach such levels

> If we anneal at this temperature, what do we chose as time intervals?

> > Still we need to hear from Hamamatsu if we can go to 110C

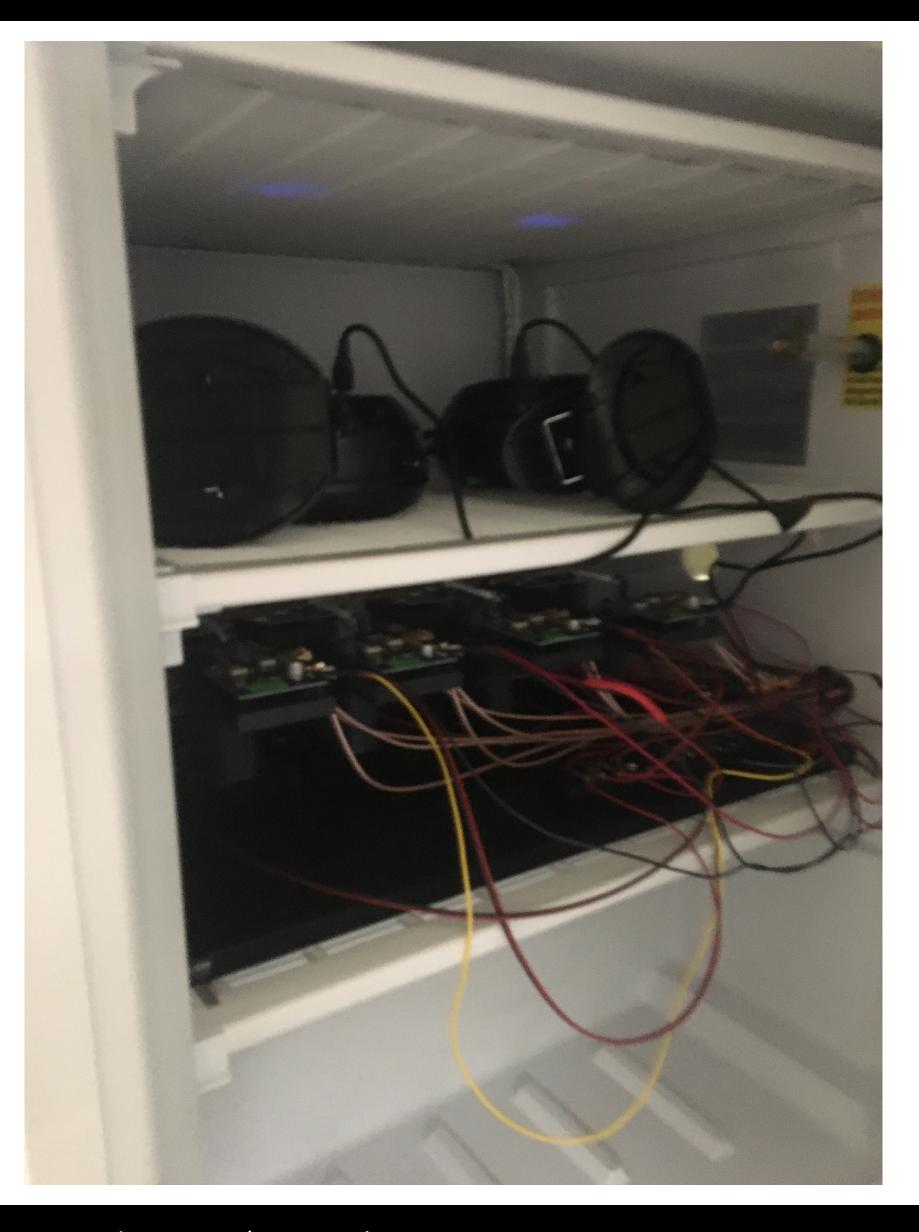
4 days 2 hours 2 min

1 days 16 hours 22 min

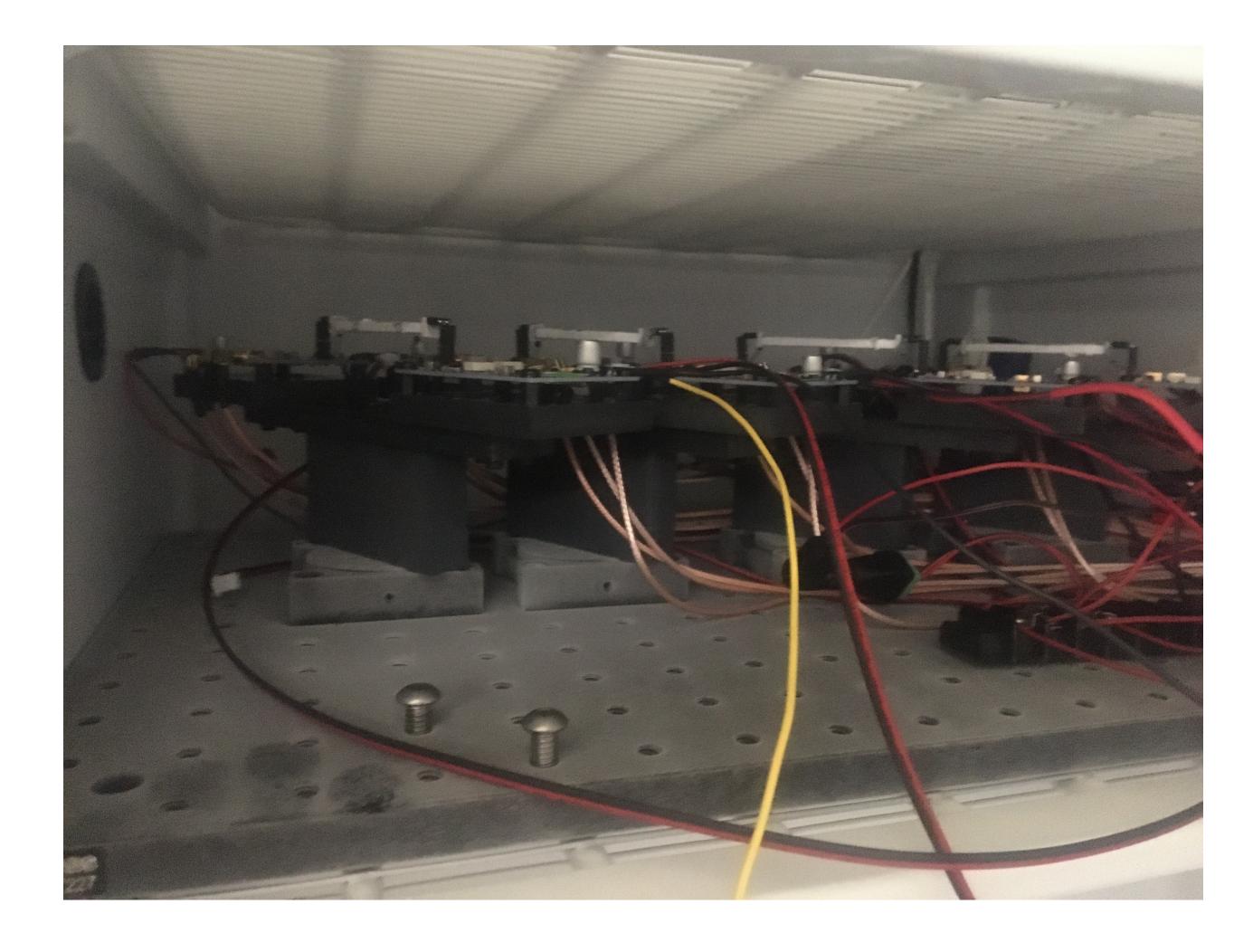
120

130

Running at -30 C

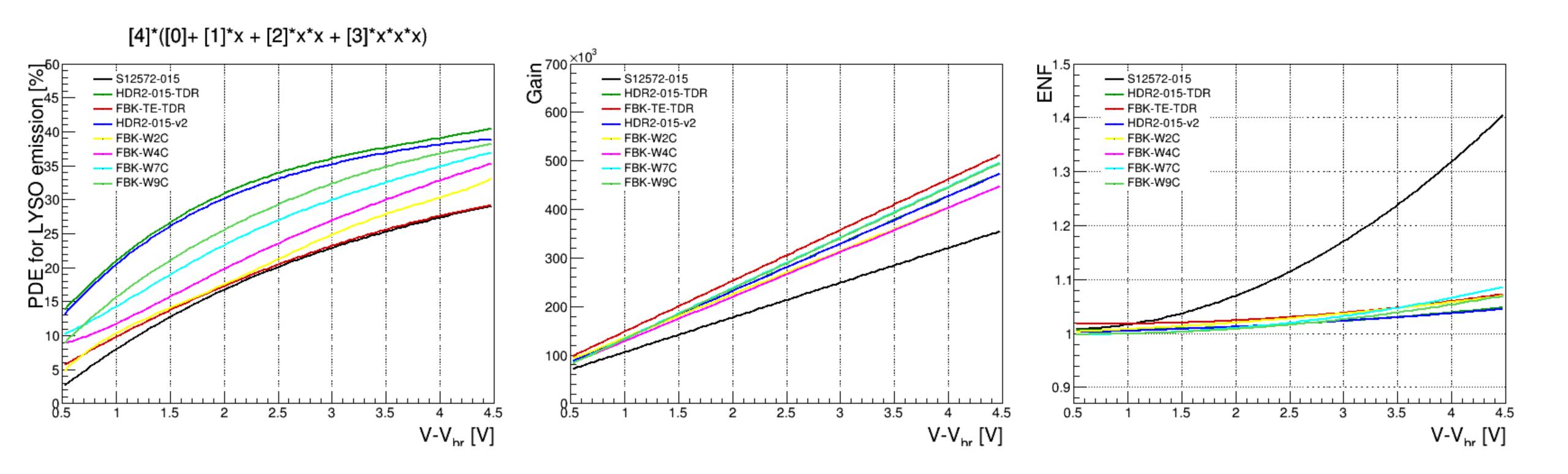


Push nitrogen and installed se



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Some HDR2-015-v2 Parameters



https://twiki.cern.ch/twiki/bin/viewauth/CMS/BTLSensors

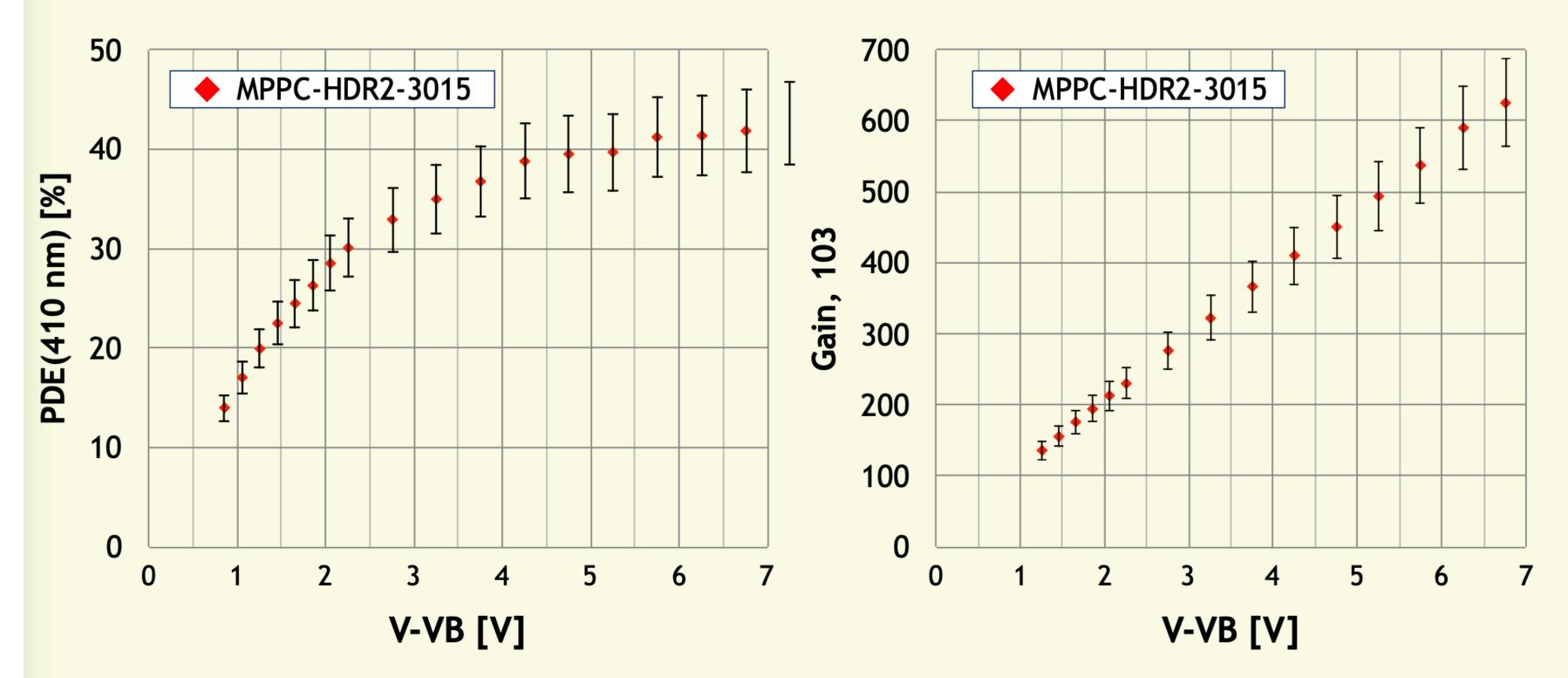
https://twiki.cern.ch/twiki/pub/CMS/BTLSensors/sipm_spec_input_HDR2-015-v2-1e13.root



SiPM parameters



We work with multiple SiPM vendors in the BTL but for this TEC R&D we used the Hamamatsu 3x3 mm HDR2 SiPM

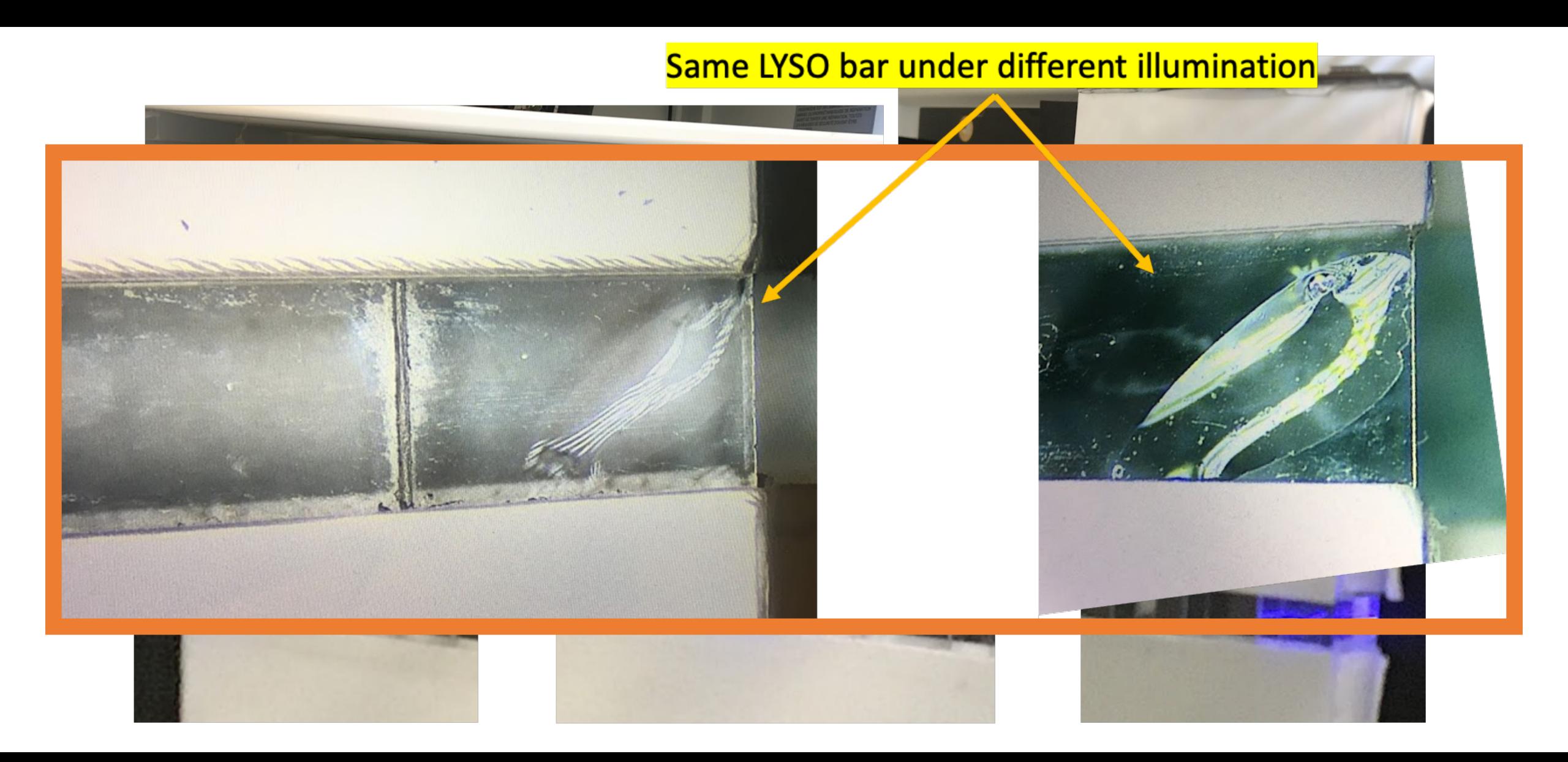


Due to the fast rising PDE data shows that these HDR2 SiPMs have optimum S/N after high irradiation at 1 to 1.5V over voltage (V-Vb)

4

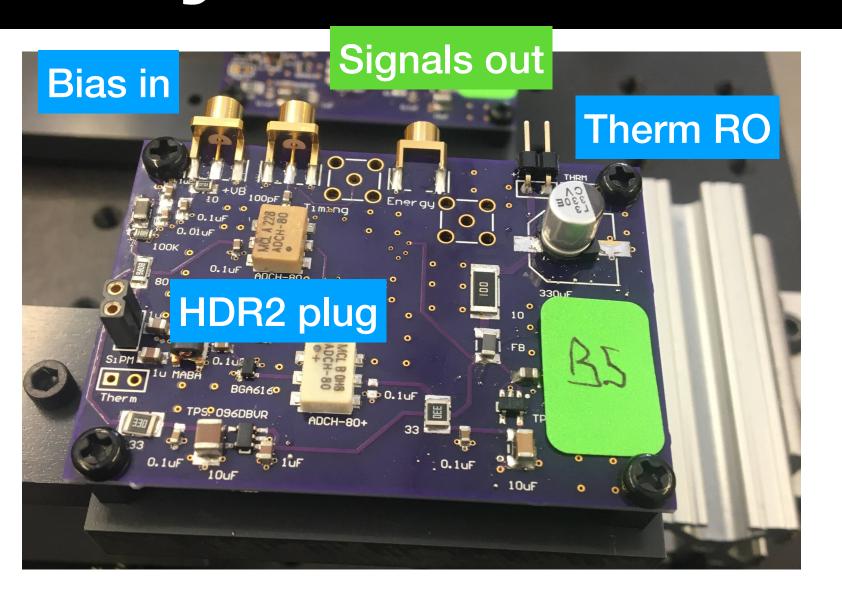
March 18, CPAD 2021 Stony Brook, NY

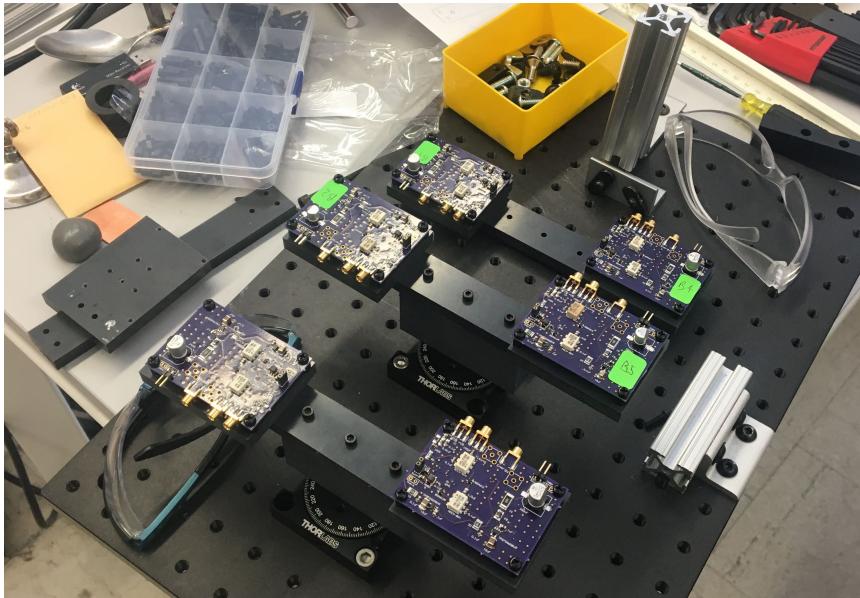
UV-Laser Scan Tests - bubble in bar 16



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May'21 TestBeam









MCP

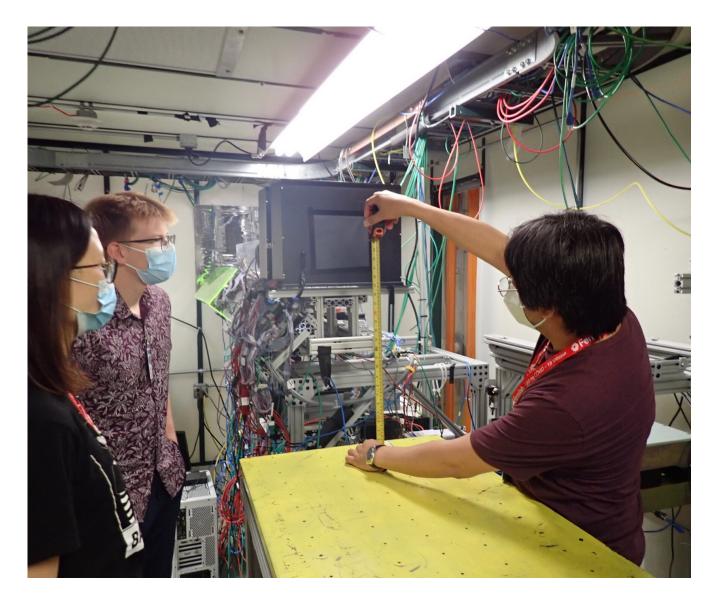
4 HDR2s

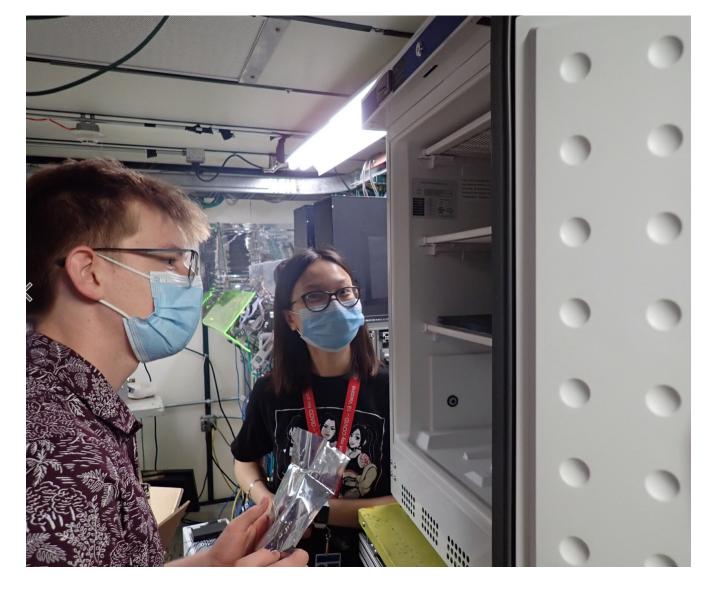
8 Channels

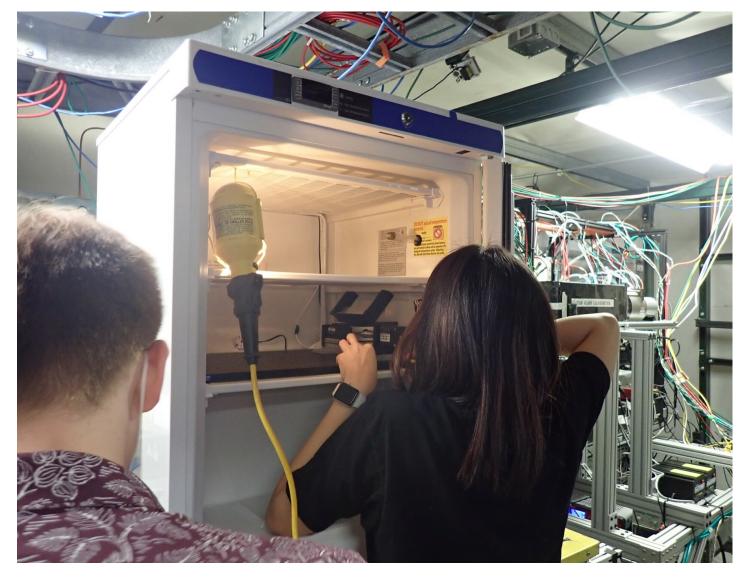
4 HDR2s

8 Channels

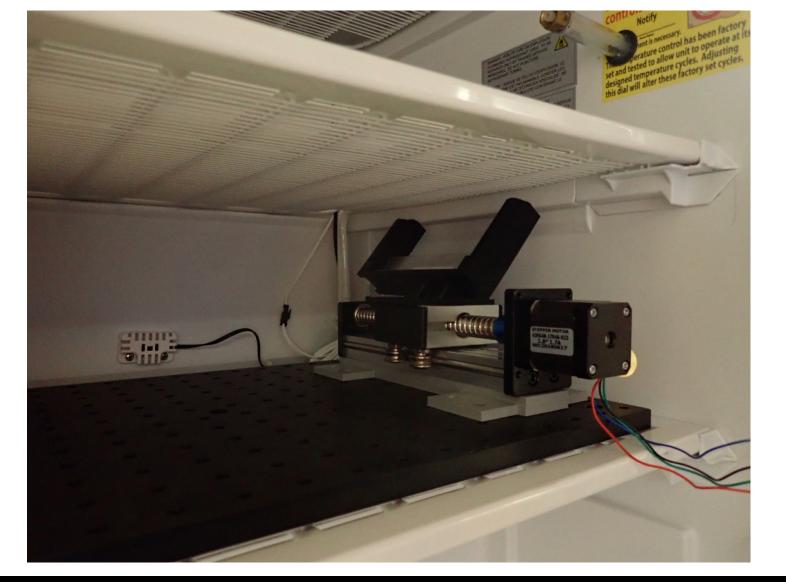
June'22 Testbeam

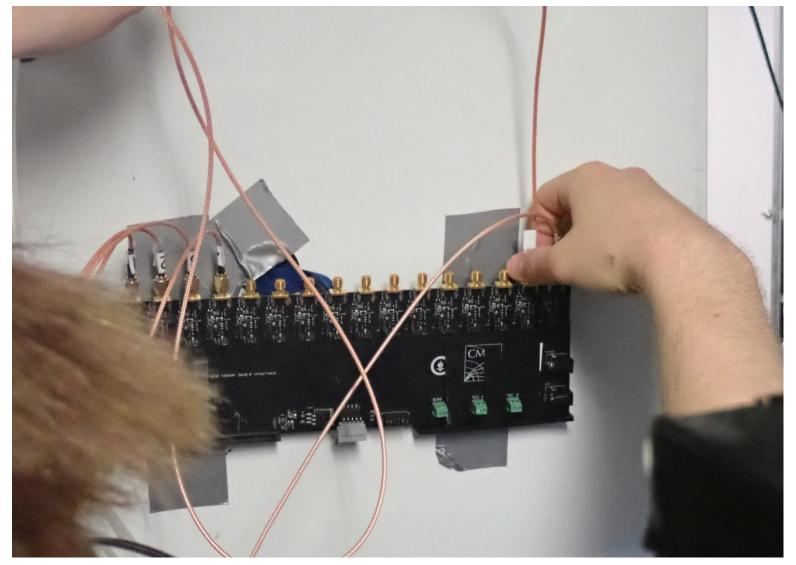






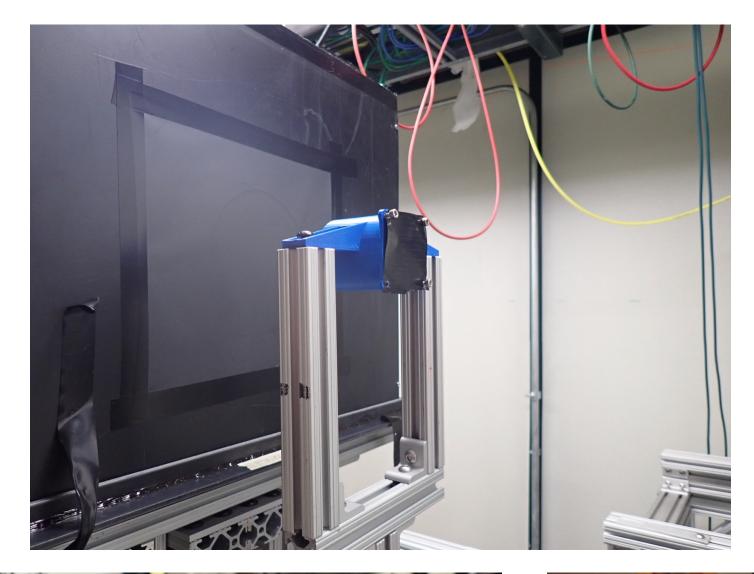


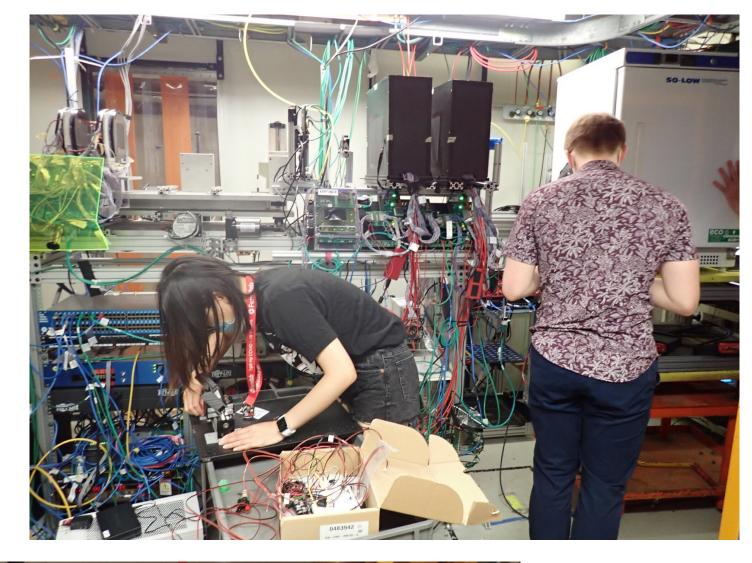


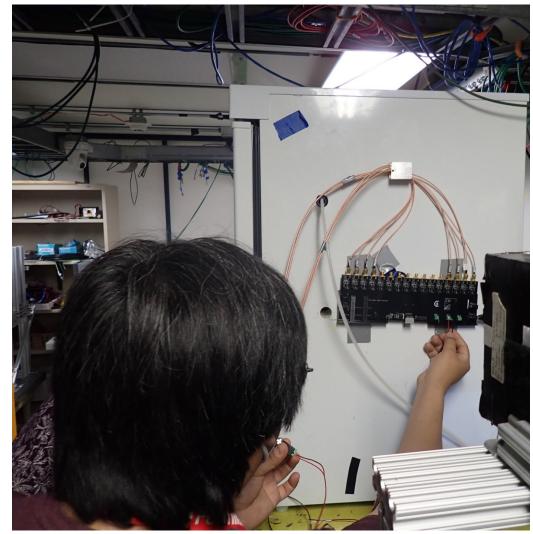


June'22 Testbeam







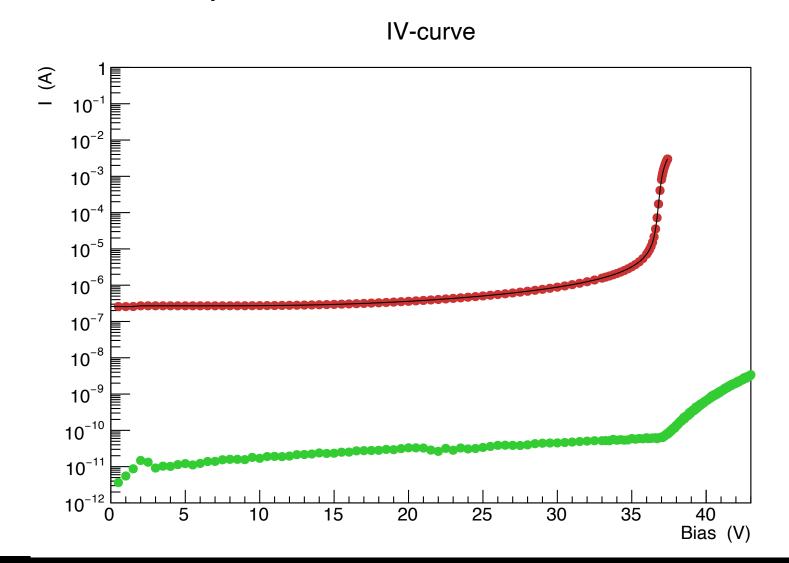






Measuring Radiation Damage on SiPMs at UVA

- We tested eight Hamamatsu HDR2 SiPMs (S14160-3015PS, S15408-02-singl, S15408-01-singl)
 - Three pairs were irradiated to an equivalent fluence of: 1e13, 5e13 and 2e14 N_{eq}/cm²
 - One pair was left un-irradiated (benchmark)
- HDR2 IV-curves were measured at different temperatures from 20 degC to -30 degC
 - Orange LED diode on and off to asses dark current component
 - System place inside a refrigerator
 - Temperature controlled within few degrees and read at the HDR2's ceramic package with thermistors



Example of NonIrradiated (left) and Irradiated (right) HDR2 IV curve response. Green points are I_{dark} , red points are I_{LED} and black curve is the difference (I_{photon}).



IV-curve

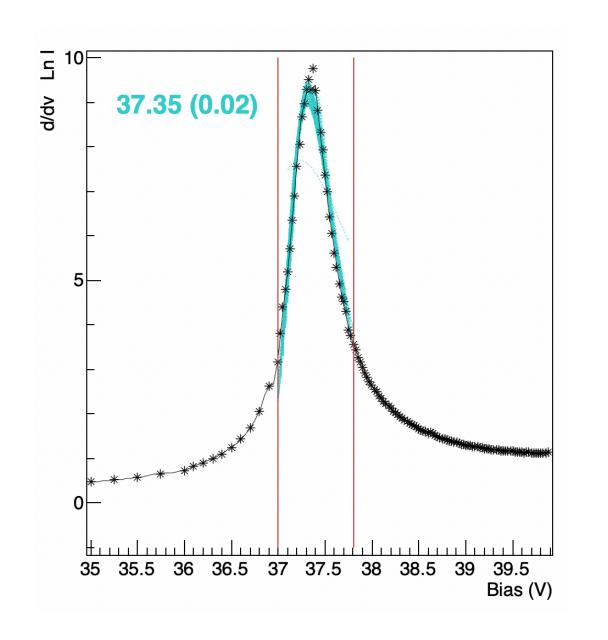
State of the state of

Breakdown Voltage (V_{br}) as function of Temperature

- There are several methods to compute the Vbr of a SiPM [CITE]
- Here I use two methods

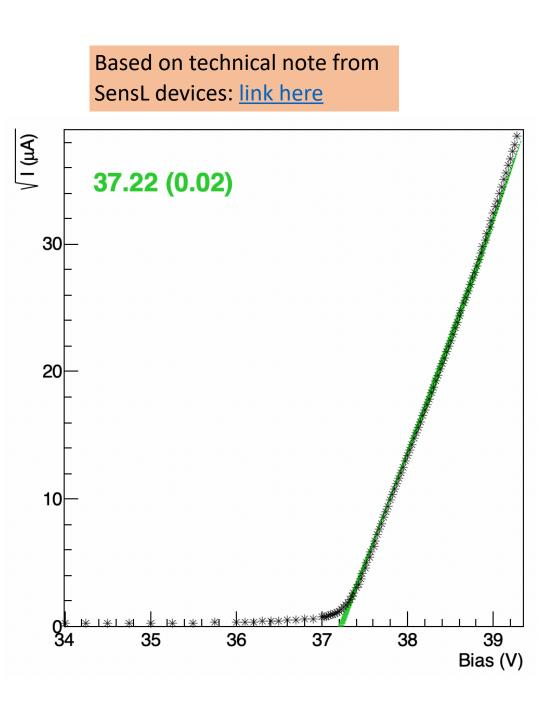
Method A:

- Computes inflection point from IV-curve during rise when in overvoltage
- Method has been widely used before by different groups
- Assumption is thatVbr == InflectionPointX



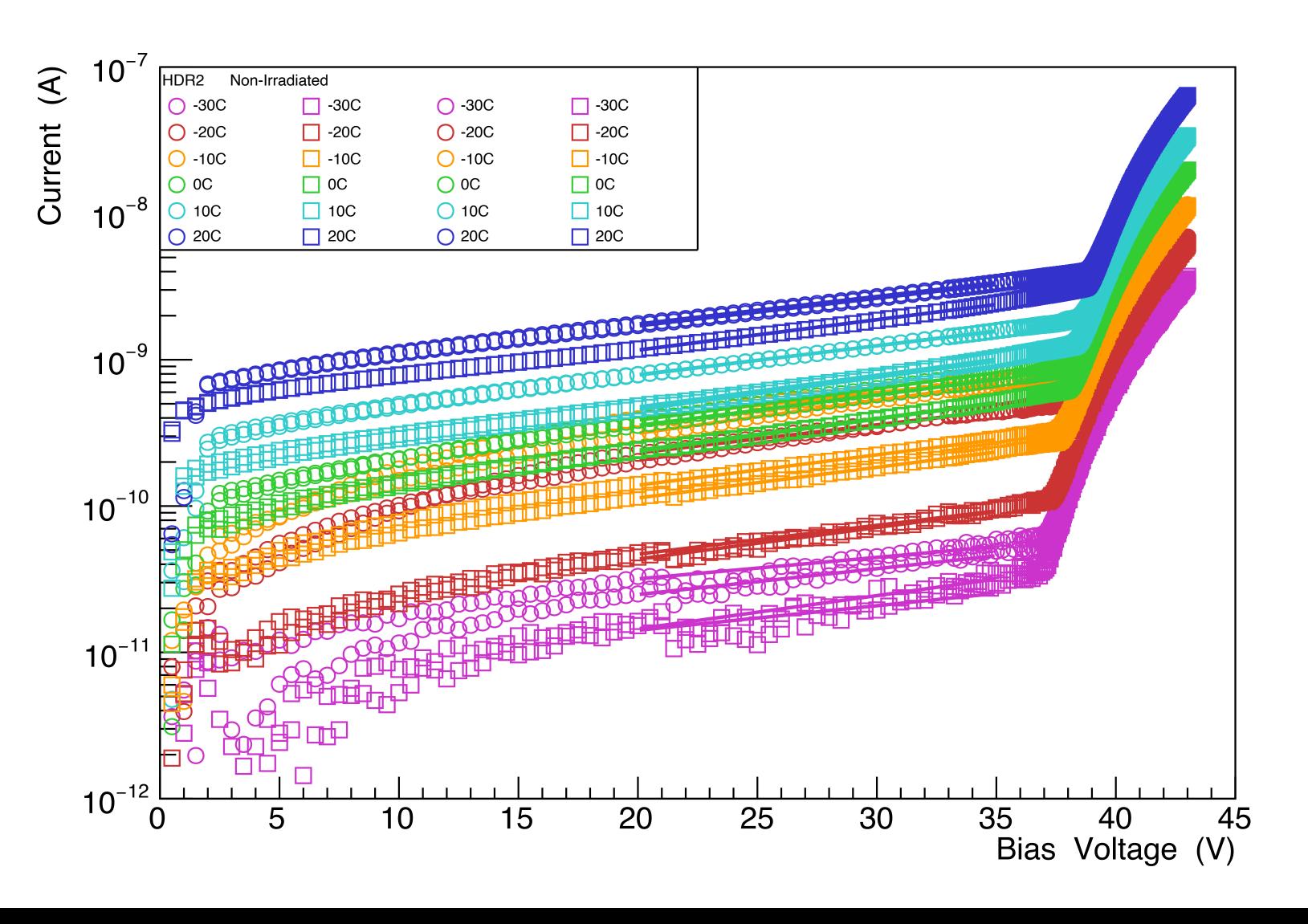
Method B:

- Based on linearity of sqrt(I) when in overvoltage
- Method is promising and as will be seen does a good job in reproducing manufacturer nominal value
- However may present large systematics since for HDR2 the kink is not so sharp



Example of IV curve for HDR2 1e13 at -20C

DCR HDR2 NonIrradiated

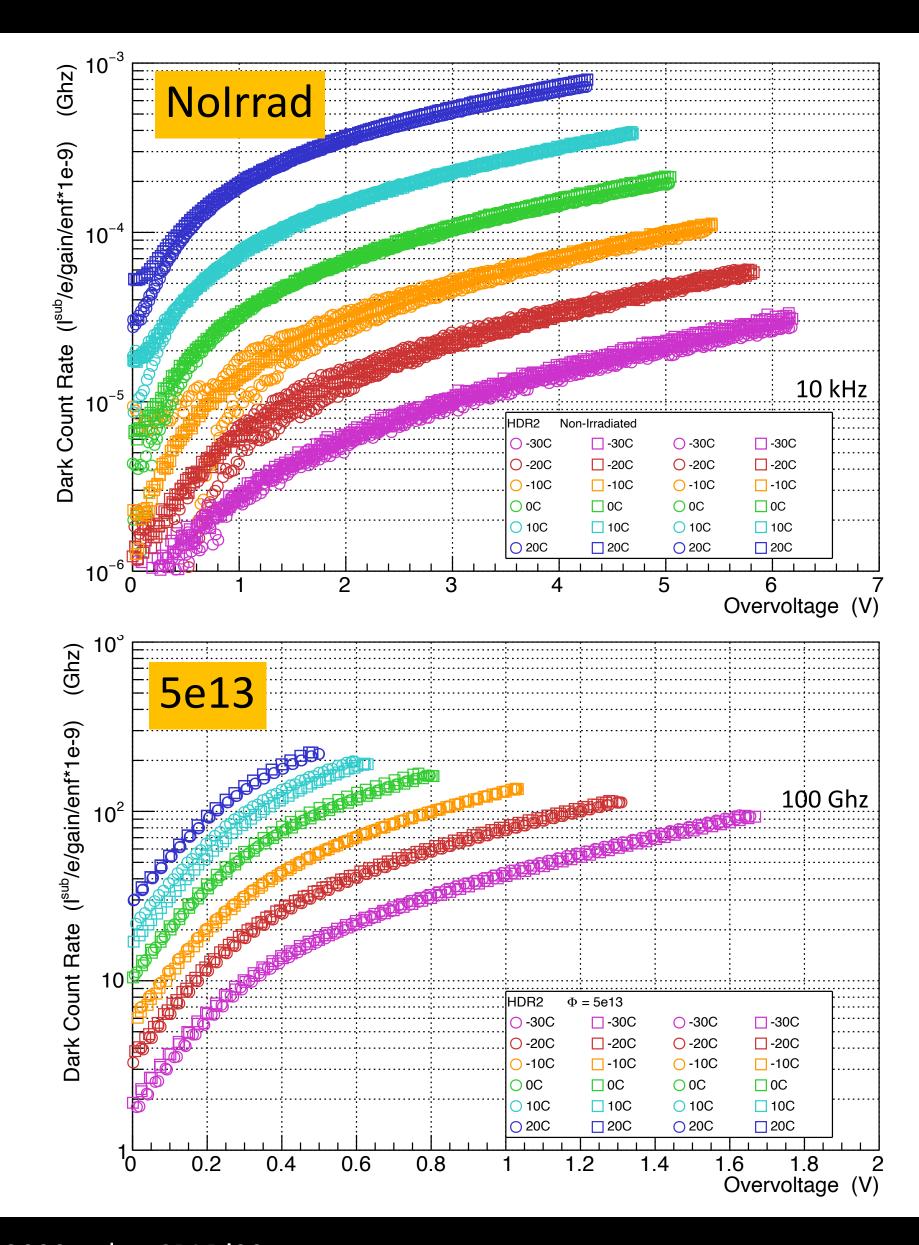


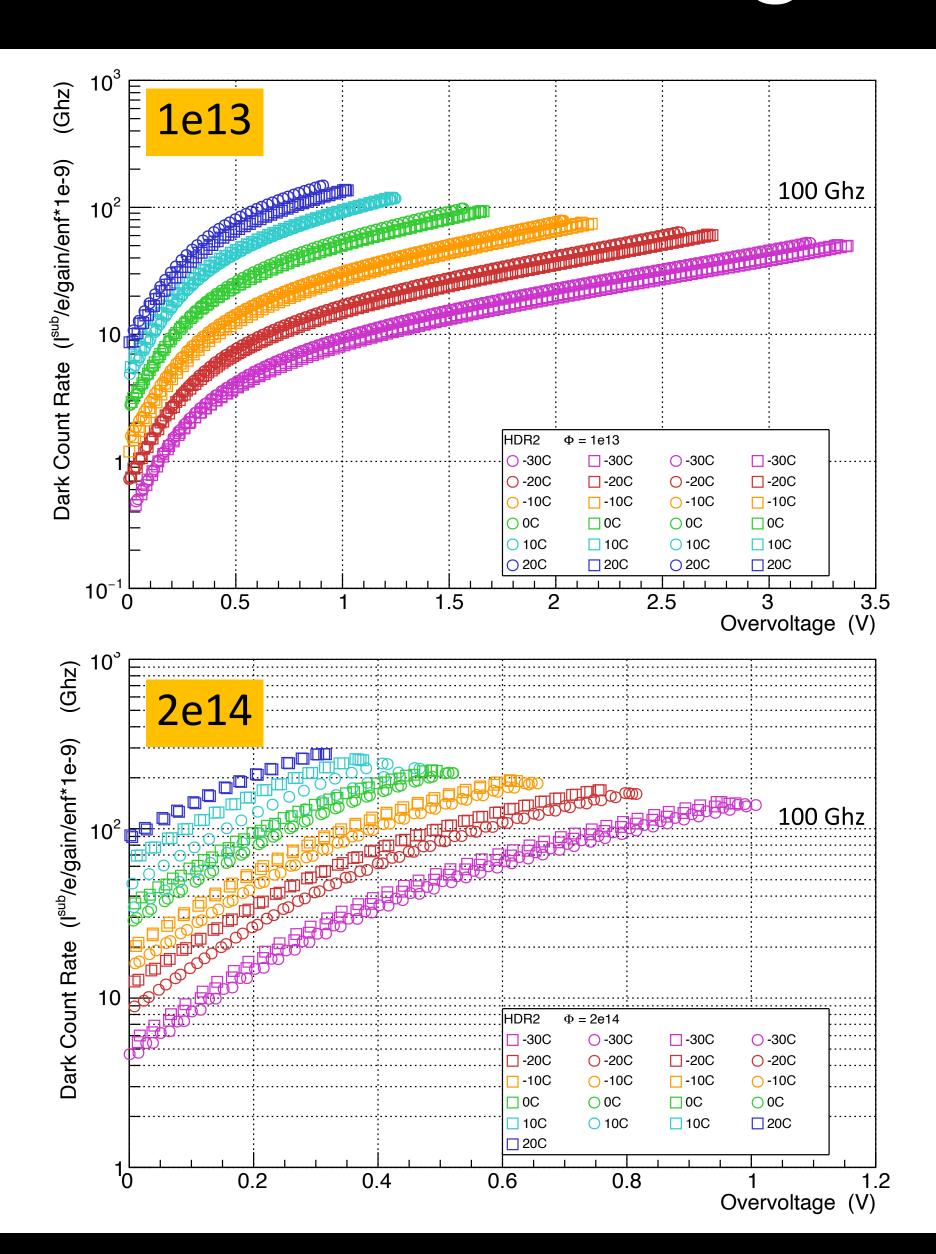
$$CR_{pe}$$
 e gain = I - I_{leak} = y

- I_{leak} is estimated from fit to IV-curve in the range of 20-35 (see figure)
- V_{br} obtained from MethodA (MaxdLnI)

```
x \rightarrow x - V_{br}
y -> y/e/gain(OV)/ENF(OV)
```

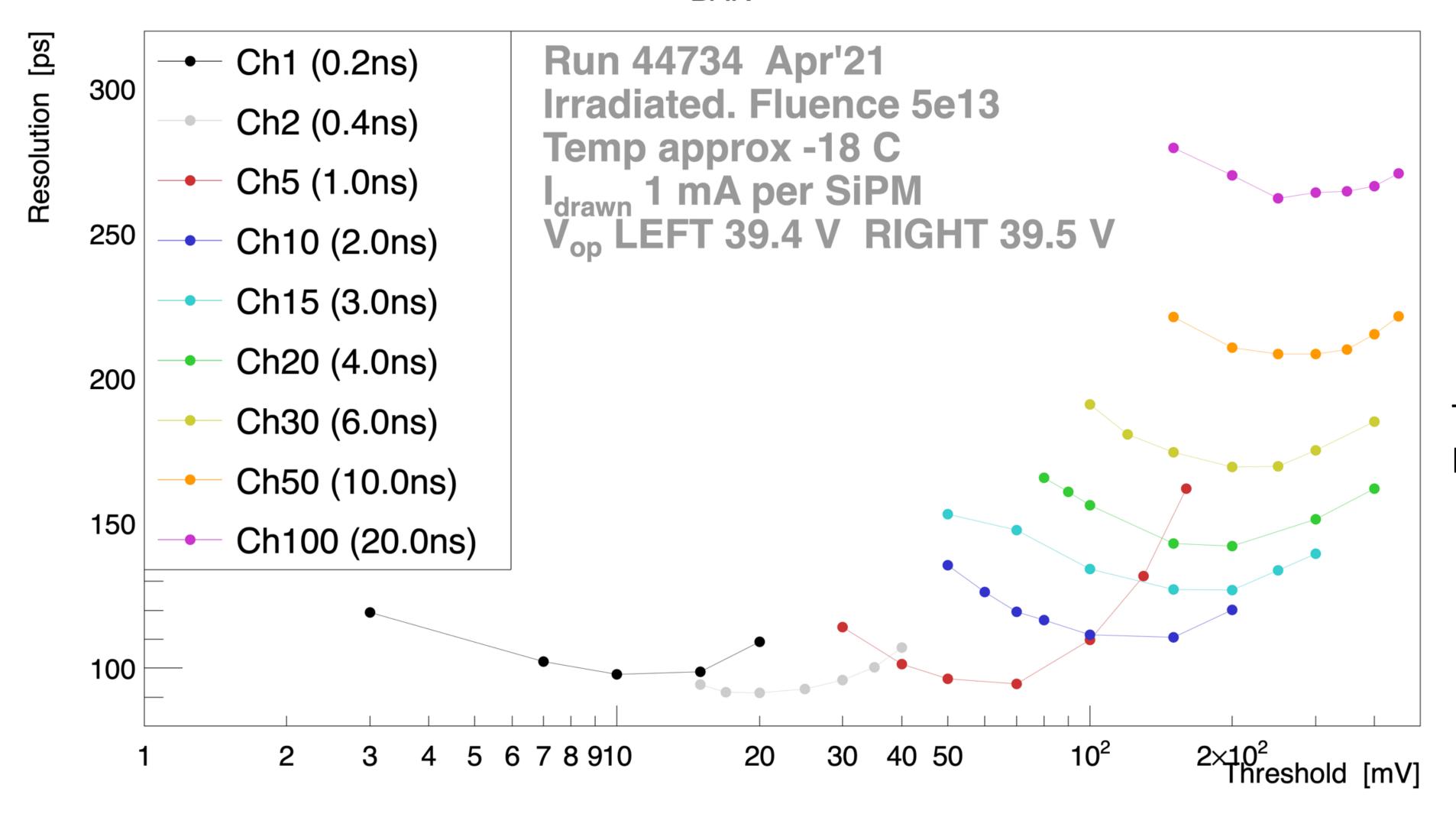
Dark Count Rate (DCR) as function of OverVoltage





Delay Line Shaping Analysis

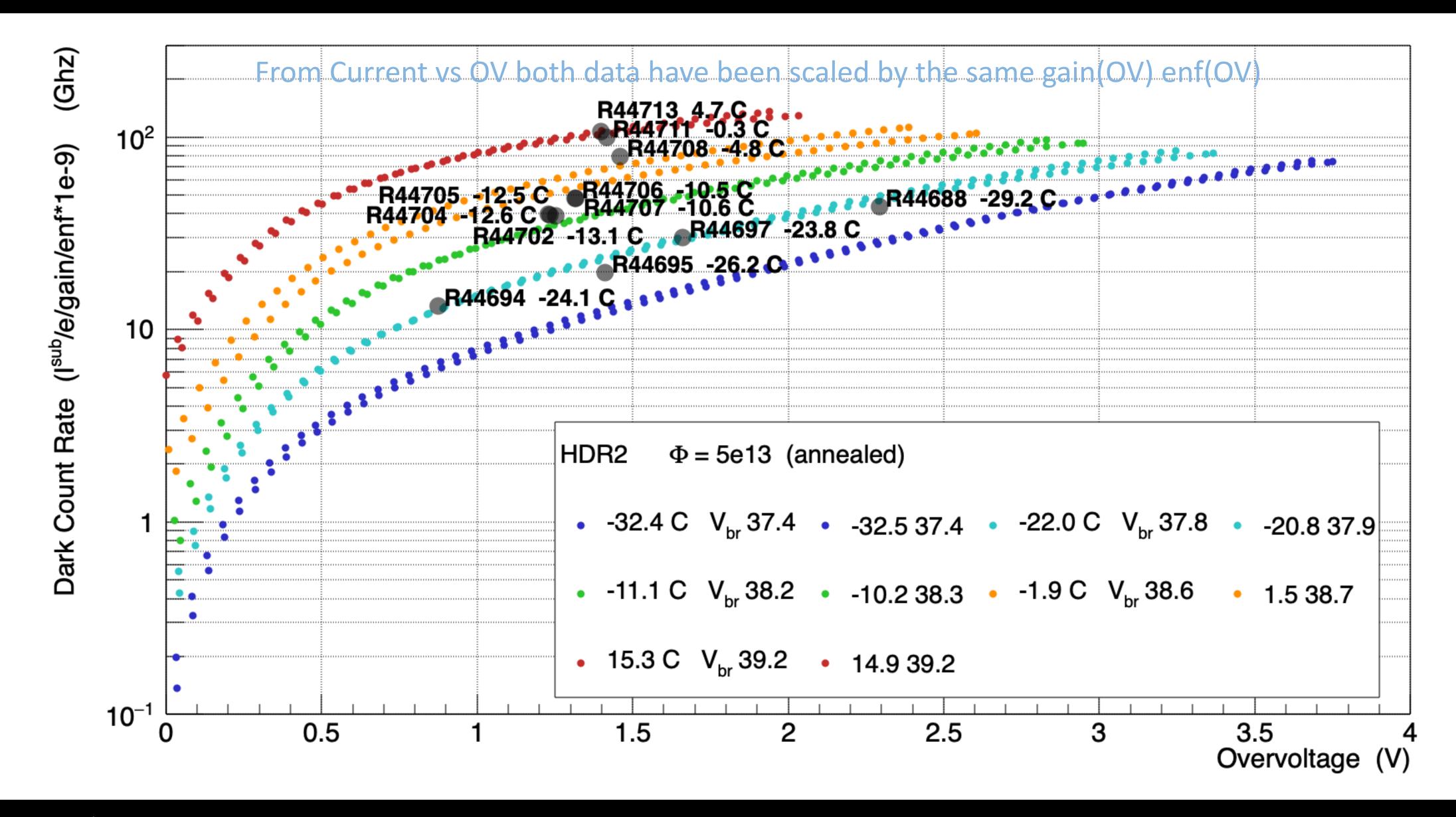
$$\sigma_{BAR} = \sigma^{-}/2$$



Tested different signal delay line chain lengths

- Anything below 1 ns is fine
- There seems to be some optimal close to 0.4 ns for this run

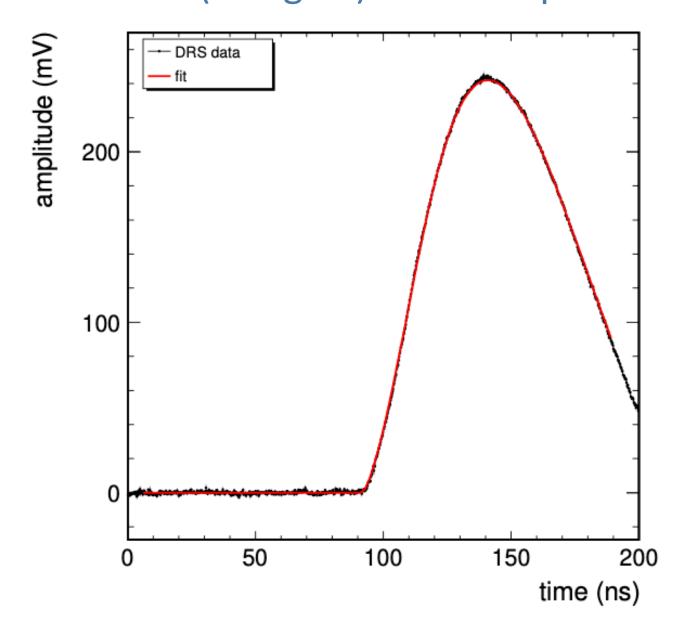
DCR Map for bars @ 52 deg inclination.



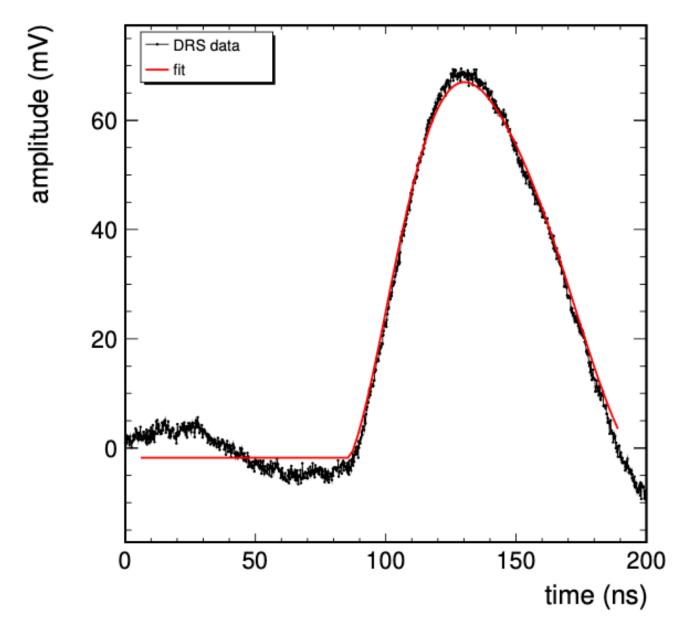
Energy and Time Reconstruction

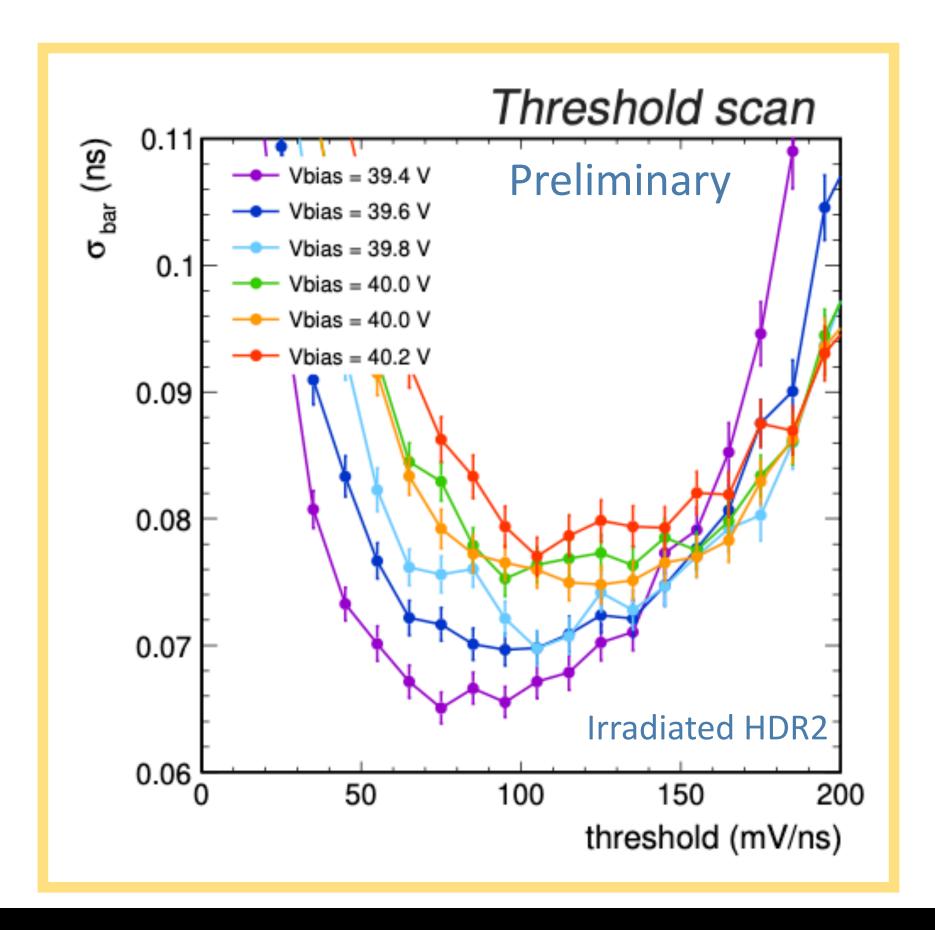
- For the energy channel, a template fit to the pulse was used for each HDR2
- For the timing channel, a single delay line shaping was applied in order to mitigate DCR (+noise)
- Threshold optimization based on OverVoltage

Example of NonIrradiated HDR2 waveform (low gain) fit to template

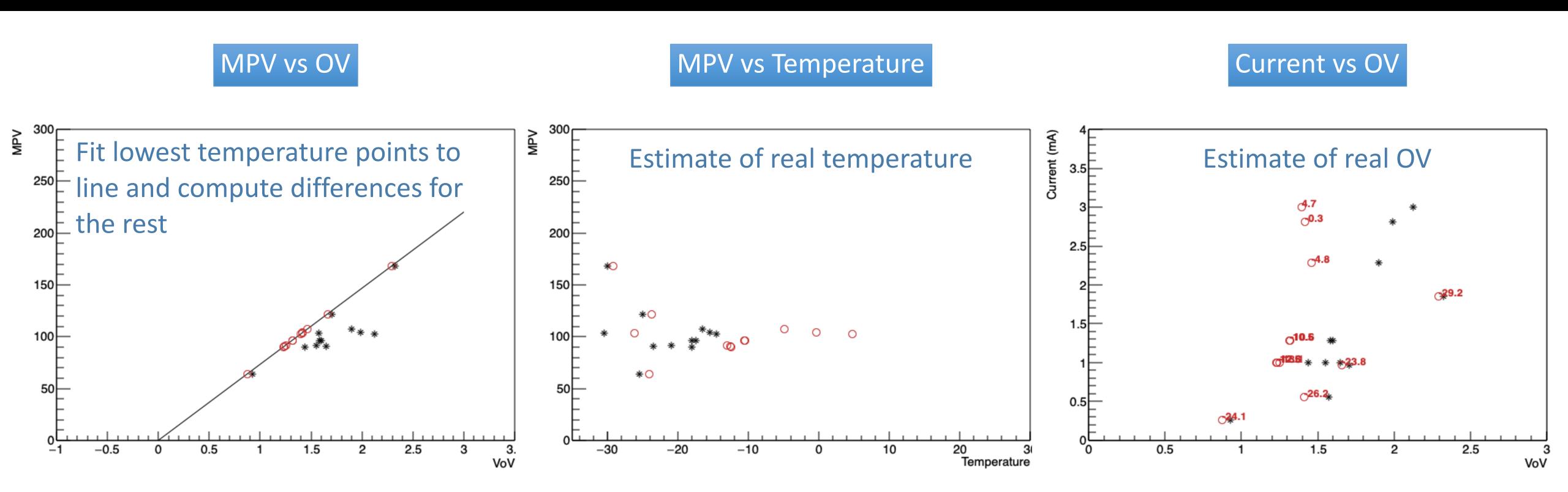


Example of Irradiated HDR2 waveform (low gain) fit to template



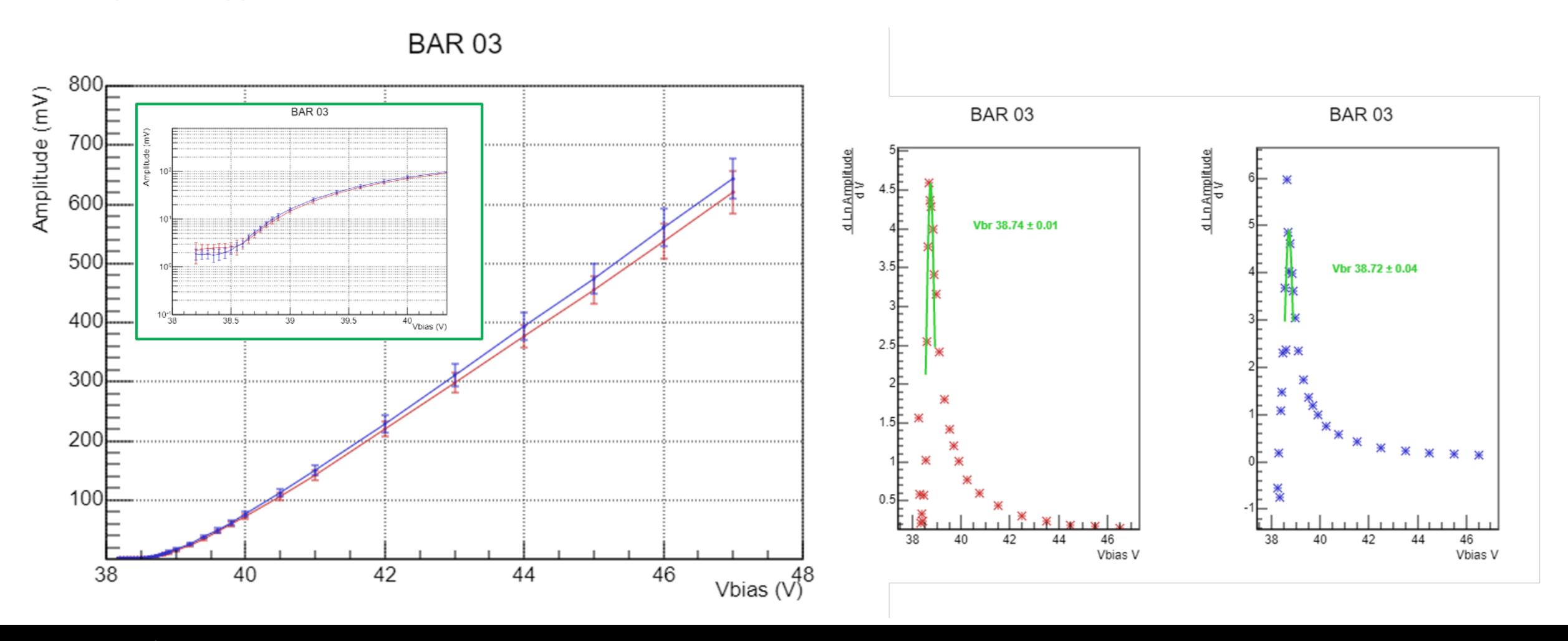


Computing OV correction based on MPV scaling

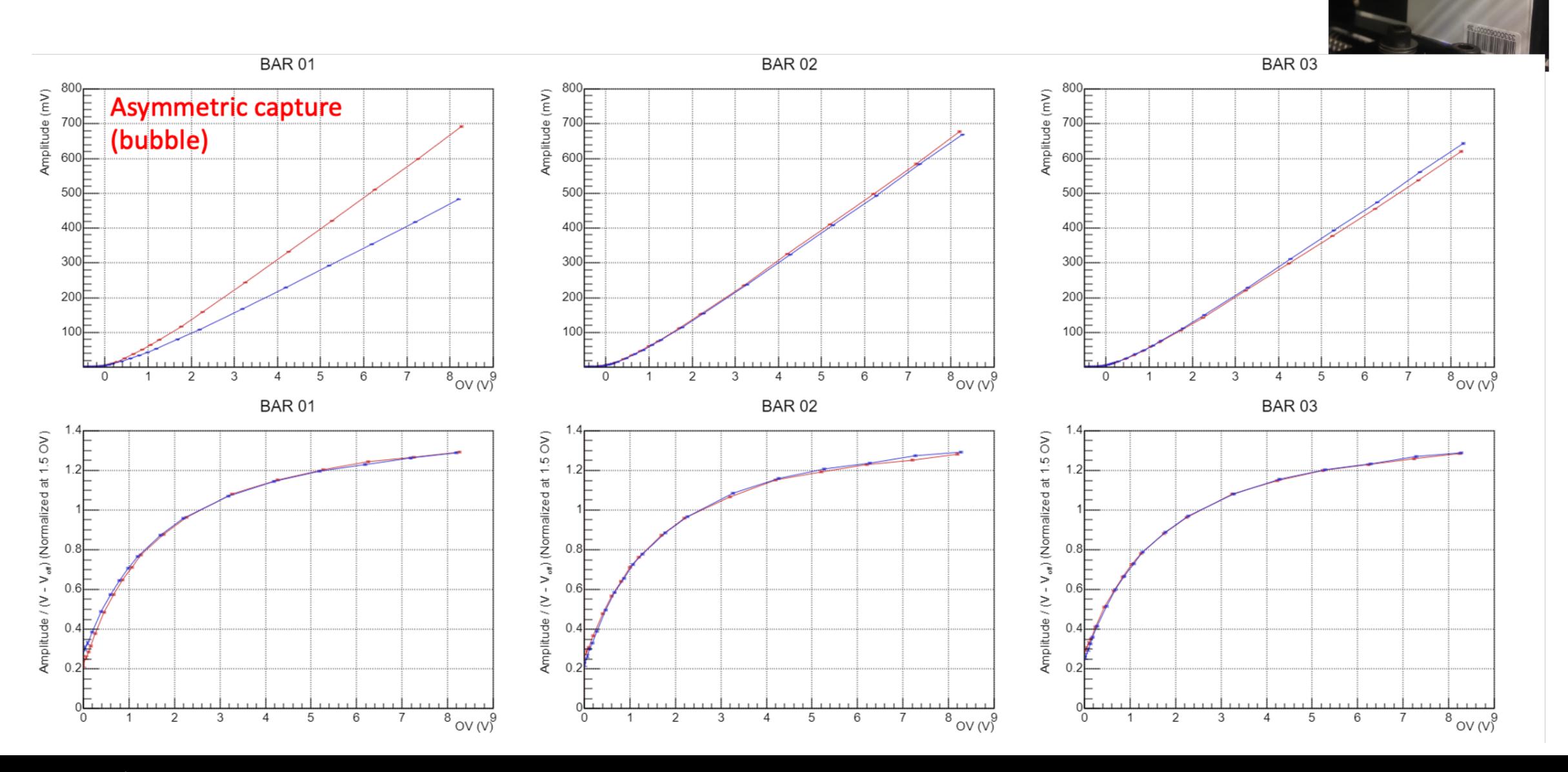


UV Laser on Module 739

UV source centered on bar 03 T approx. +19C Intensity to 8.0 (approx. ~2.9 MeV)



UV Laser on Module 739



Radiation Damage to SiPM Response

• Displacement of silicon atoms in the crystal lattice [G. Landstrom - NIM A 512 (2003) 30]

Crystal defects create additional energy levels in the band gap and facilitate thermal generation of electron-hole pairs which...

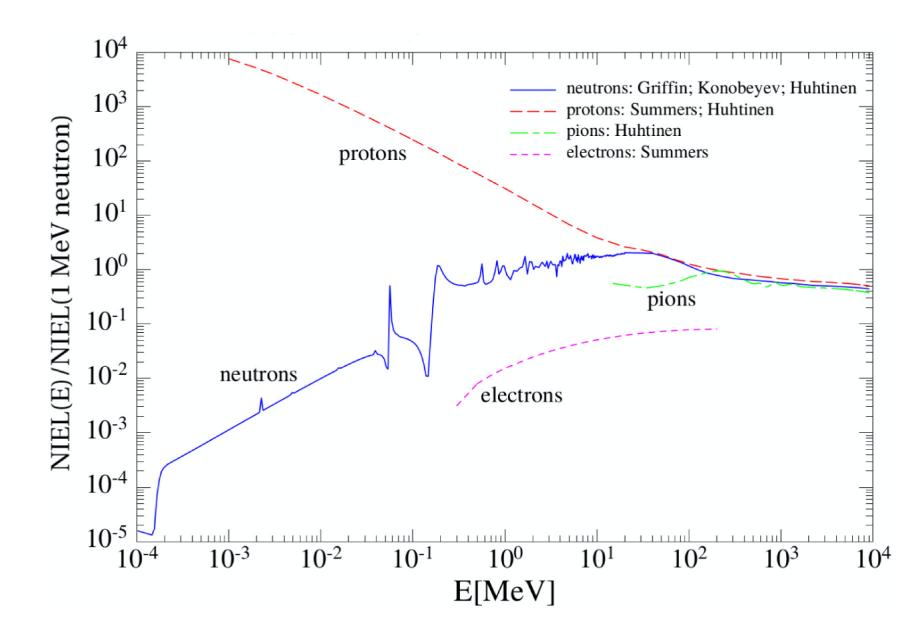
- increase the SiPM dark count rate and dark current
- Change of effective doping density in silicon [A. Heering NIM A 824 (2016) 111]
 - change the SiPM breakdown voltage
- Ionizing damage in the SiO₂ layer which covers the surface of the silicon and insulates it from the bias lines and quench resistors [C. Xu NIM A 762 (2014) p.149]

Surface-generated current which significantly....

increases the SiPM total leakage current below the breakdown voltage

If a fraction of the surface-generated charge carriers reach the amplification region, then also an...

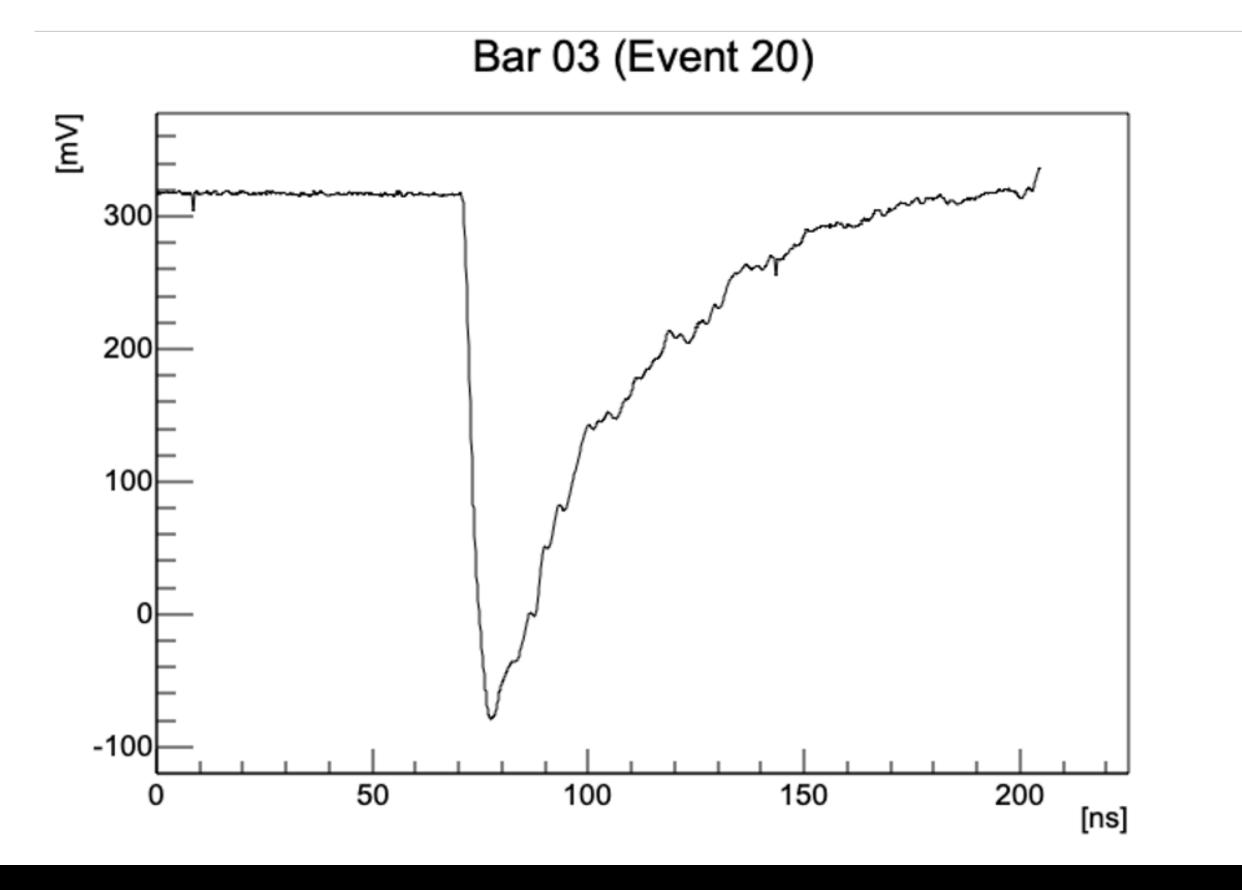
increase of dark count rate and dark current above the breakdown voltage may occur

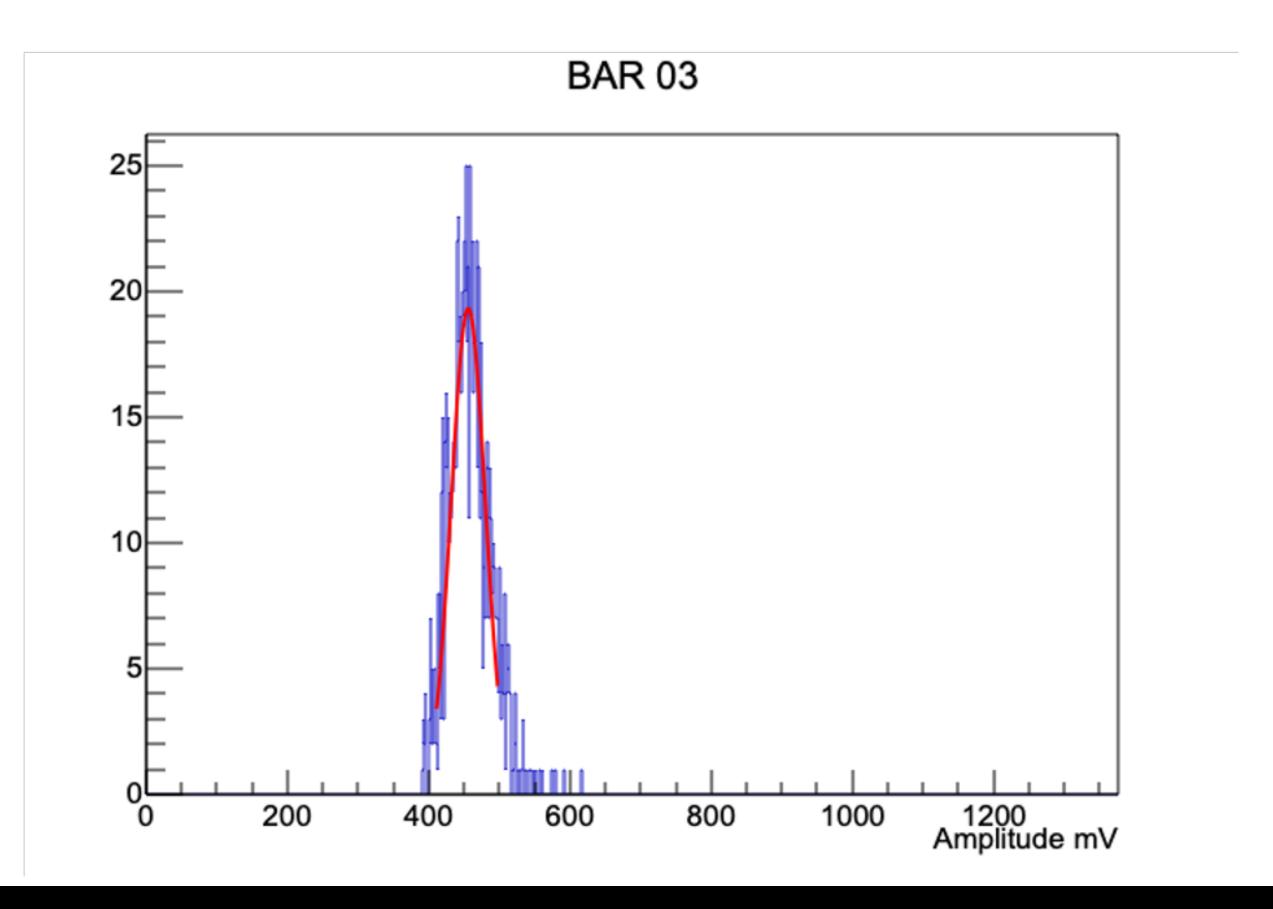


Non-ionizing energy loss (NIEL) in silicon for different particles relative to 1 MeV neutrons. [A. Ulyanov - NIM A 976 (2020) 164203]

UV Laser on Module 739

UV source centered on bar 03 T approx. +19C Intensity to 8.0 (approx. ~2.9 MeV) Bias 45 V

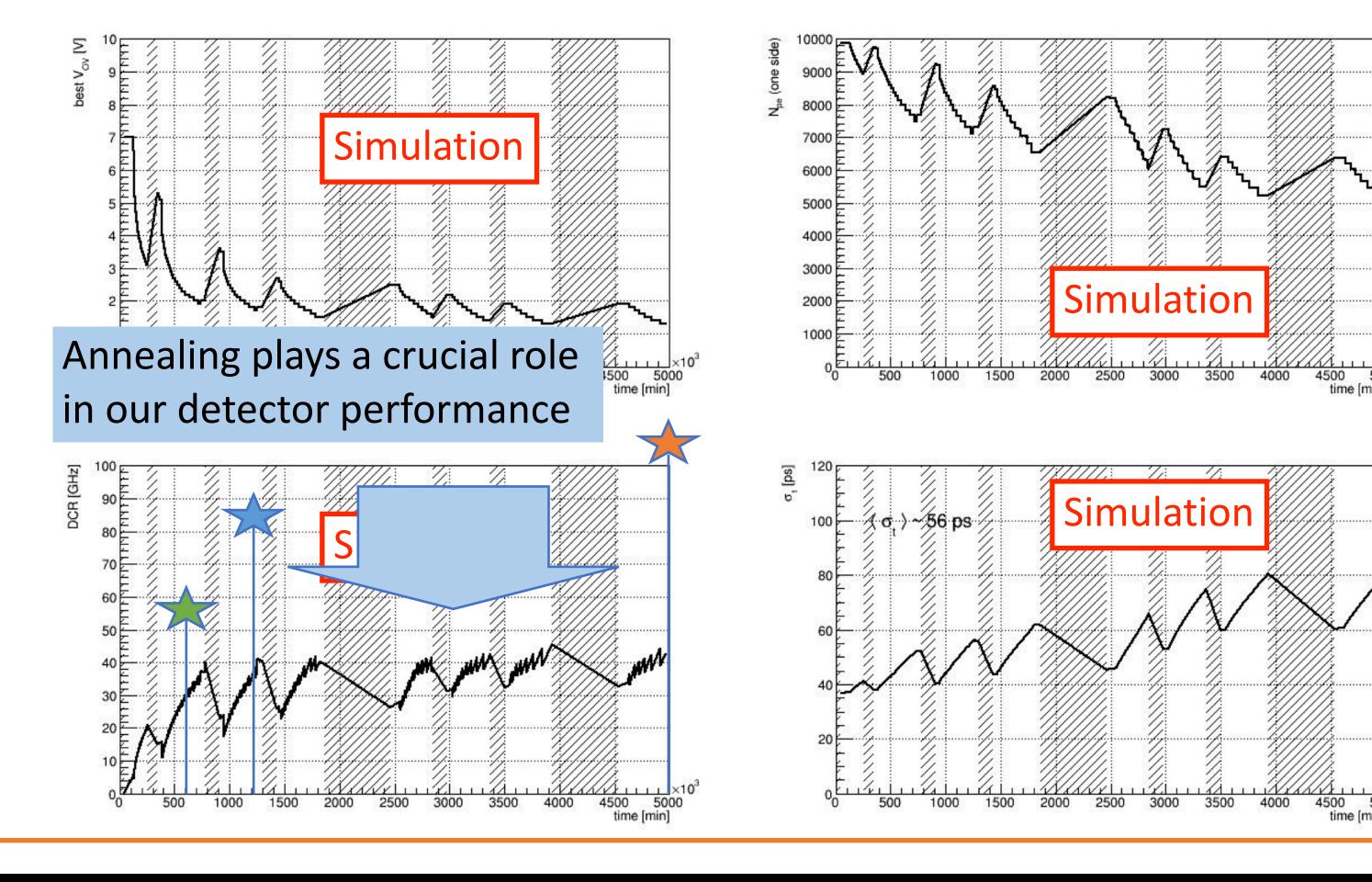




Extrapolation of Performance for a Ten Year Scenario

Results for $T_{op} = -45^{\circ} \text{ C}$, $T_{ann} = 40^{\circ} \text{ C}$

• T_{ann} = 40° C throughout the whole duration of Technical Stops / Long Shutdowns



- Silicon recovers most of its properties by heat treatment: annealing
- Periods of annealing are foreseen for BTL during LHC shutdowns
- To obtain DCR levels at the TB operational temperature, comparable to what we expect in BTL at the end of life, we subjected four SiPMs to a high-temperature annealing procedure